

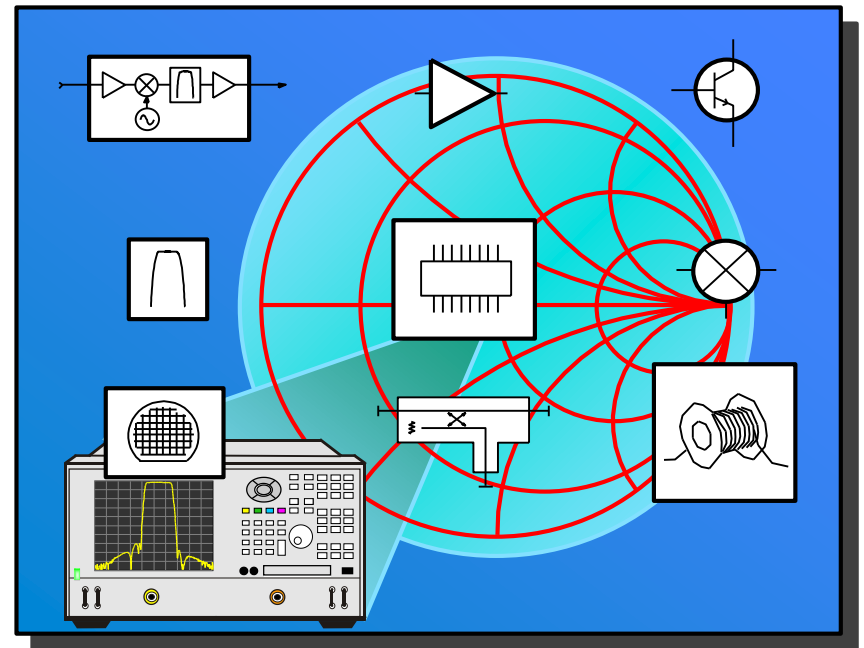


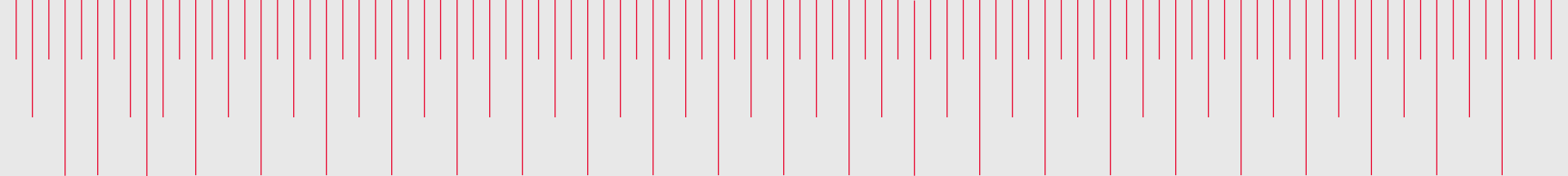
Network Analysis Fundamentals

January 2017

Objectives

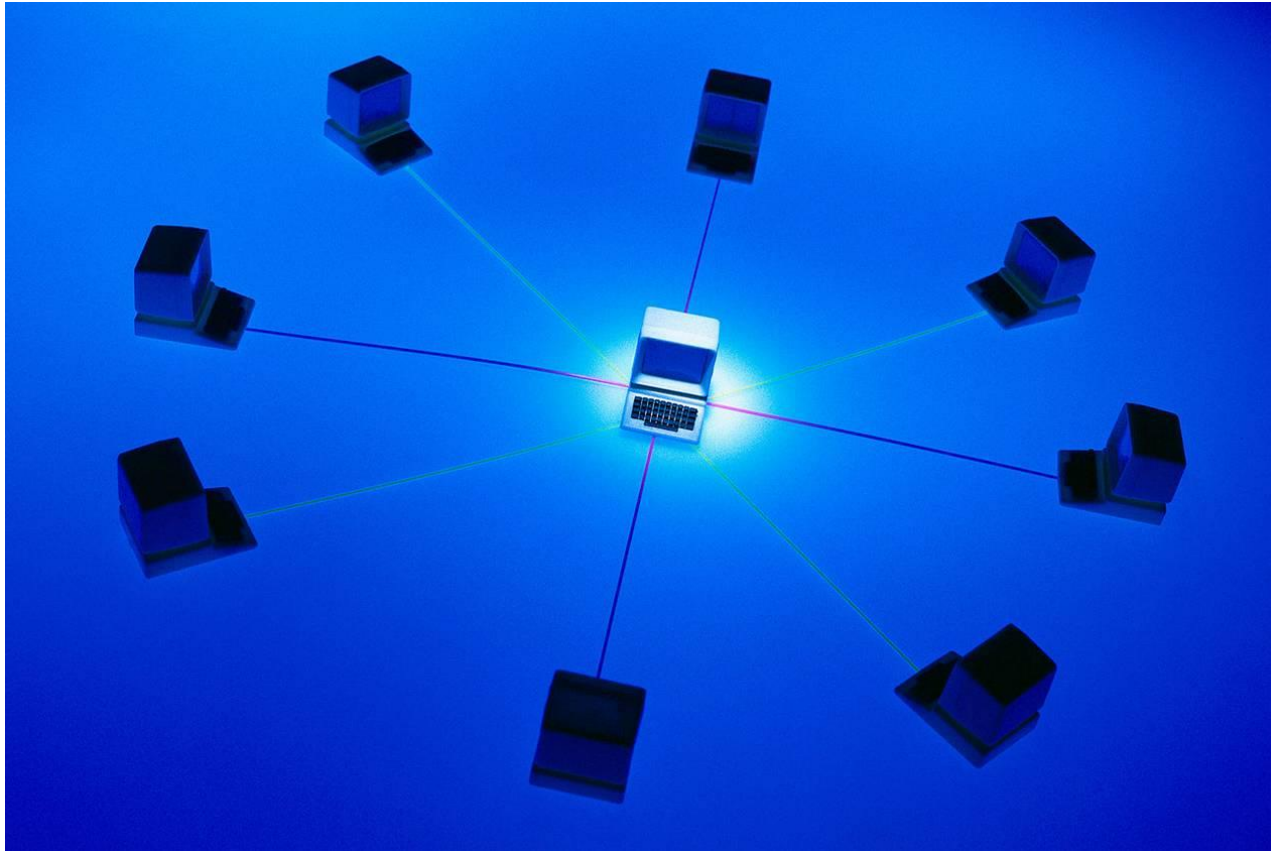
- Review RF basics
- Understand fundamentals on S-parameter measurements
- Examine architectures and calibrations of VNAs





So...what is a Network Analyzer?

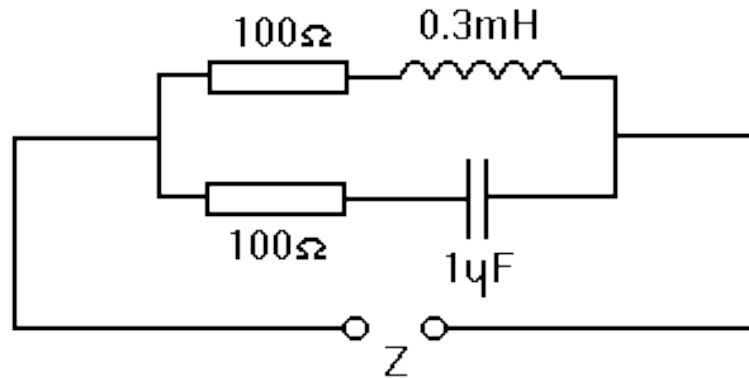
Network Analysis is NOT the analysis of...



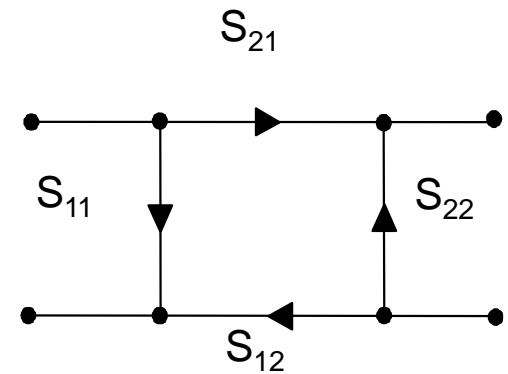
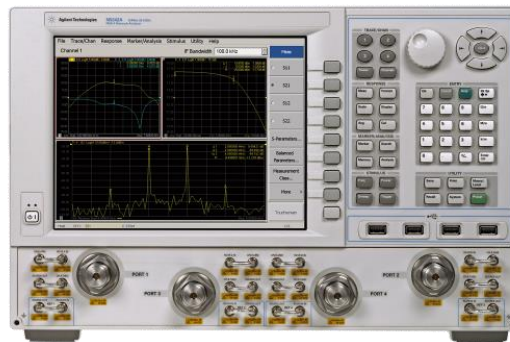
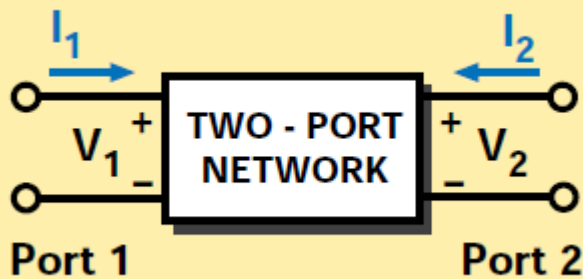
Computers
Network/protocol performance etc...

What is a Network Analyzer?

A *network analyzer* is an instrument that measures the network parameters of electrical networks.

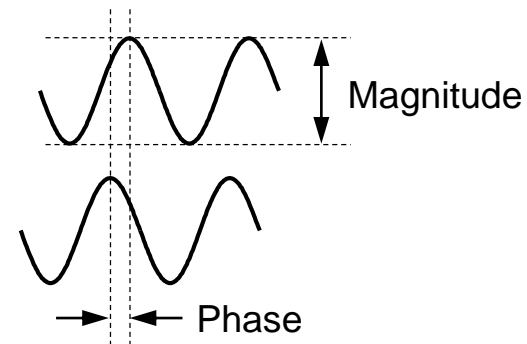
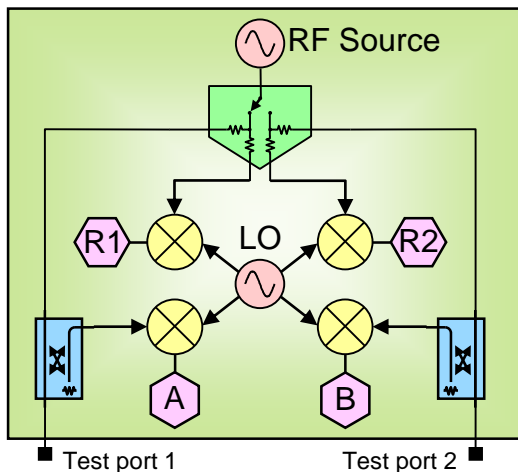
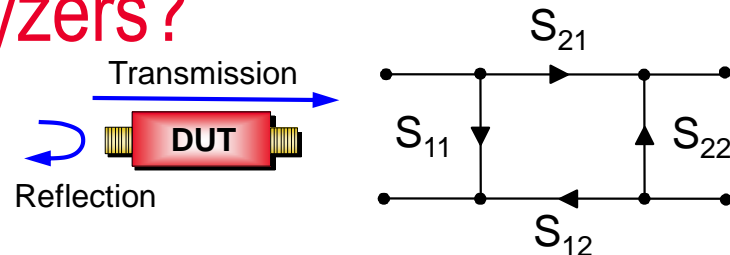


Electrical Network

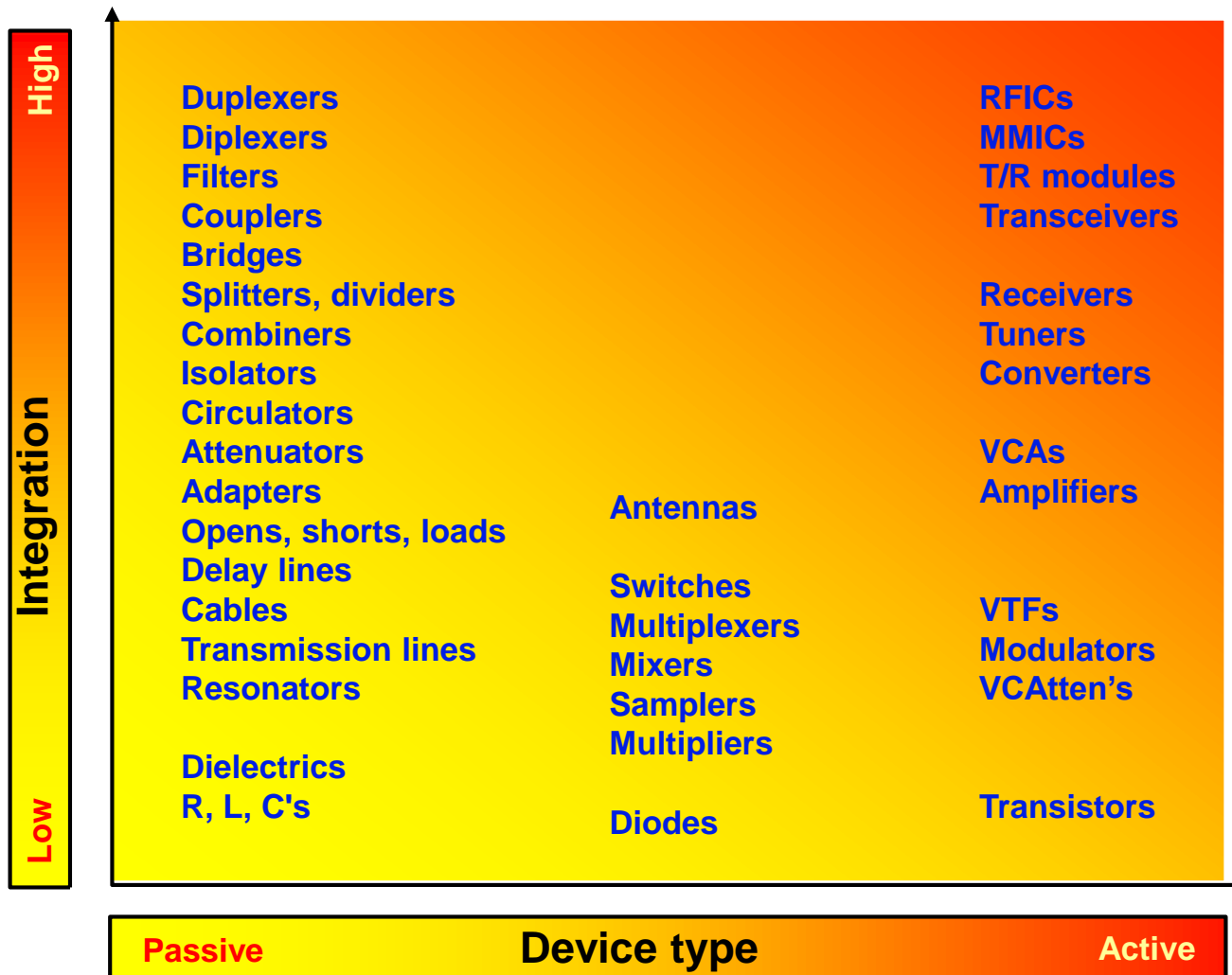


What Are Vector Network Analyzers?

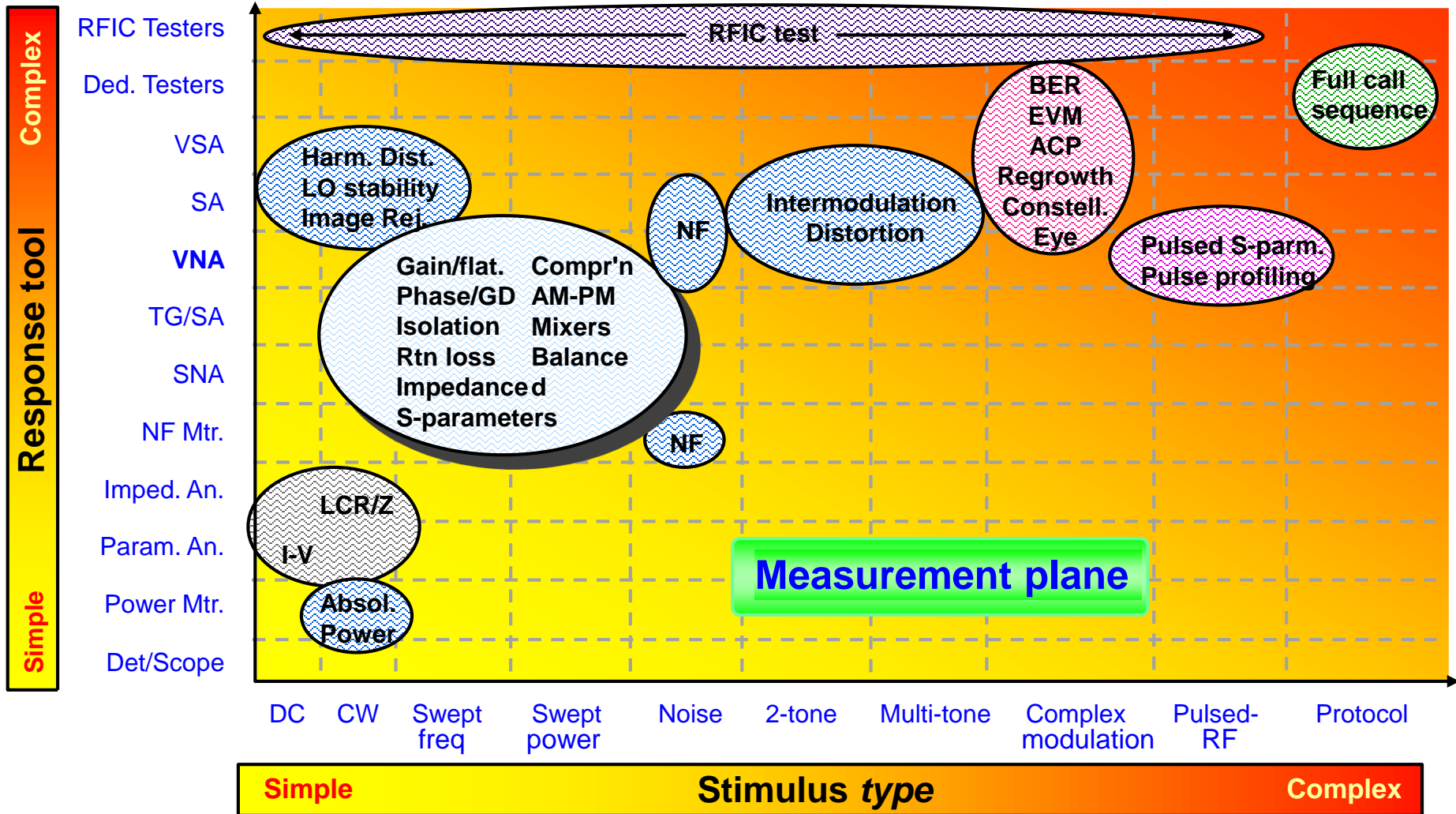
- Are stimulus-response test systems
- Characterize forward and reverse reflection and transmission responses (S-parameters) of RF and microwave components
- Quantify linear magnitude and phase
- Are very fast for swept measurements
- Provide the highest level of measurement accuracy



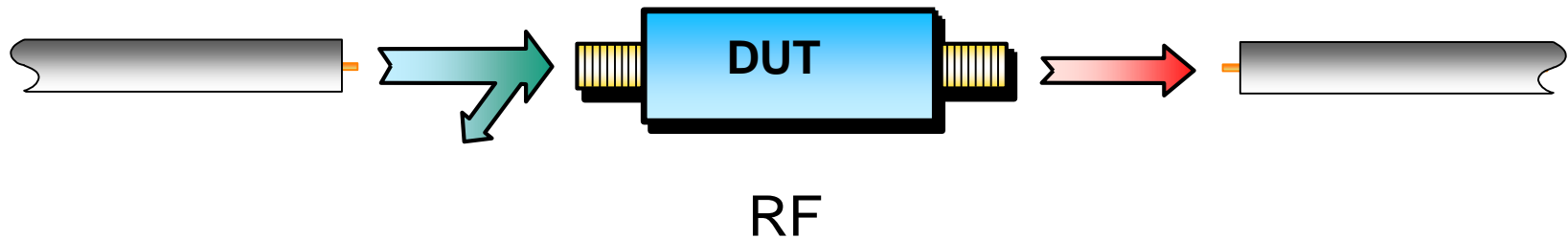
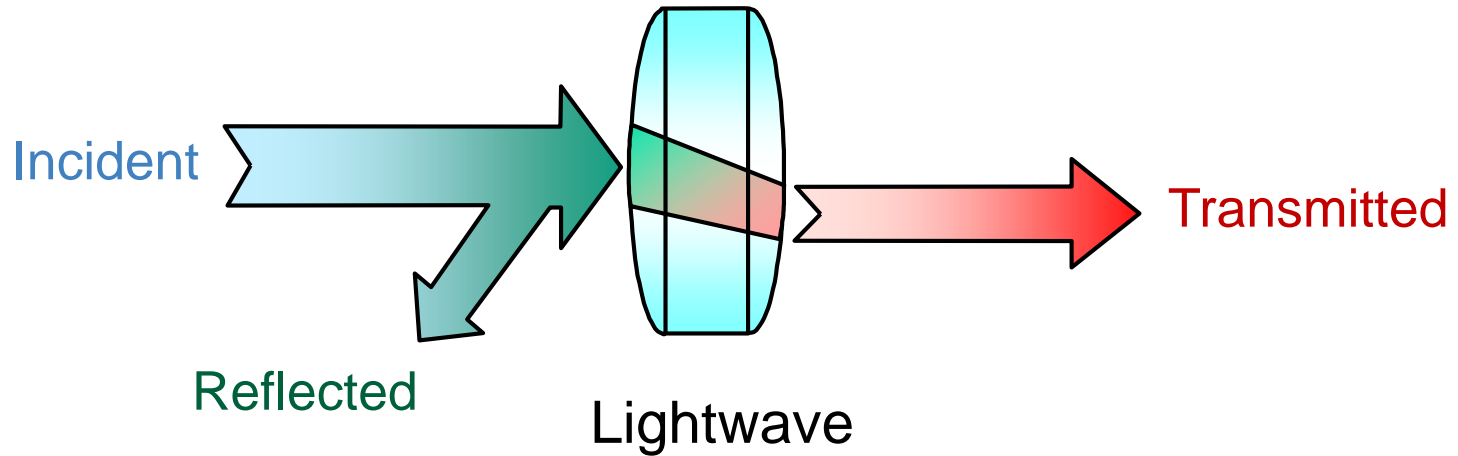
What Types of Devices are Tested?



Device Test Measurement Model

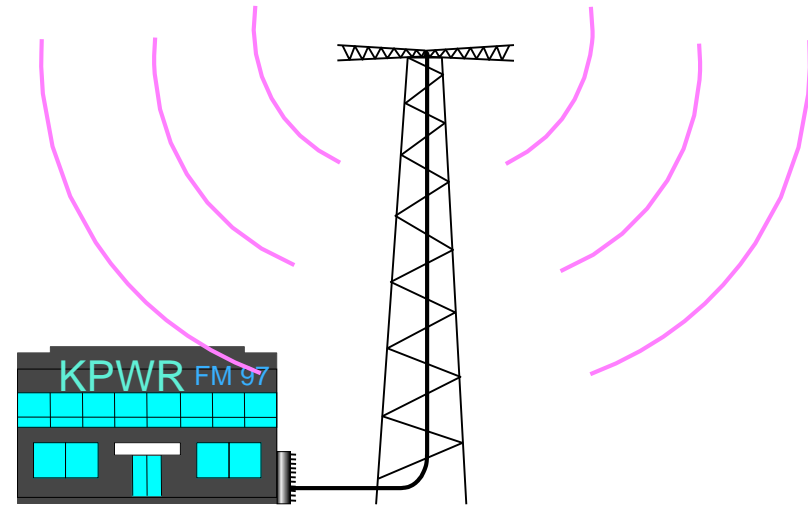


Lightwave Analogy to RF Energy



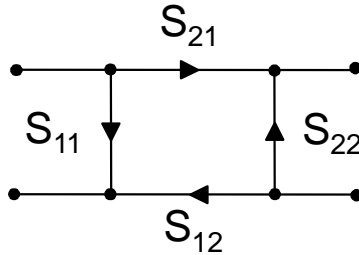
Why Do We Need to Test Components?

- Verify specifications of “building blocks” for more complex RF systems
- Ensure distortionless transmission of communications signals
 - Linear: constant amplitude, linear phase / constant group delay
 - Nonlinear: harmonics, intermodulation, compression, X-parameters
- Ensure good match when absorbing power (e.g., an antenna)

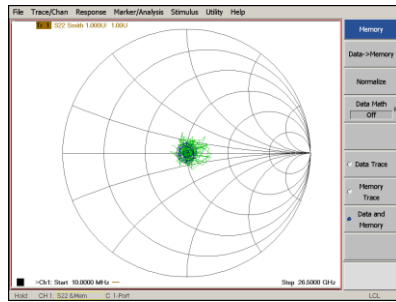


The Need for Both Magnitude and Phase

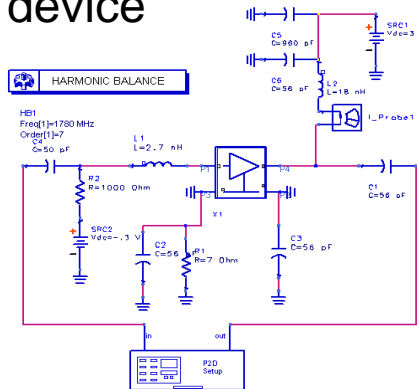
1. Complete characterization of linear networks



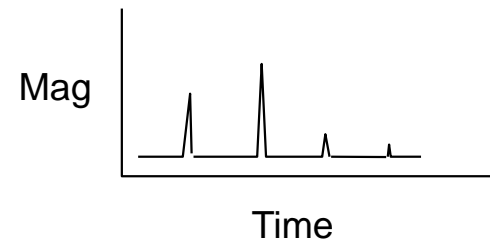
2. Complex impedance needed to design matching circuits



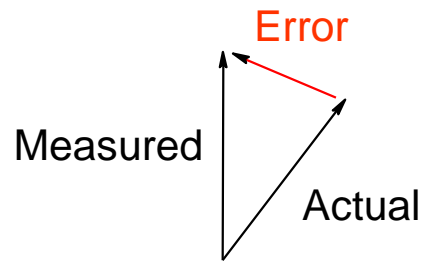
3. Complex values needed for device modeling



4. Time-domain characterization



5. Vector-error correction



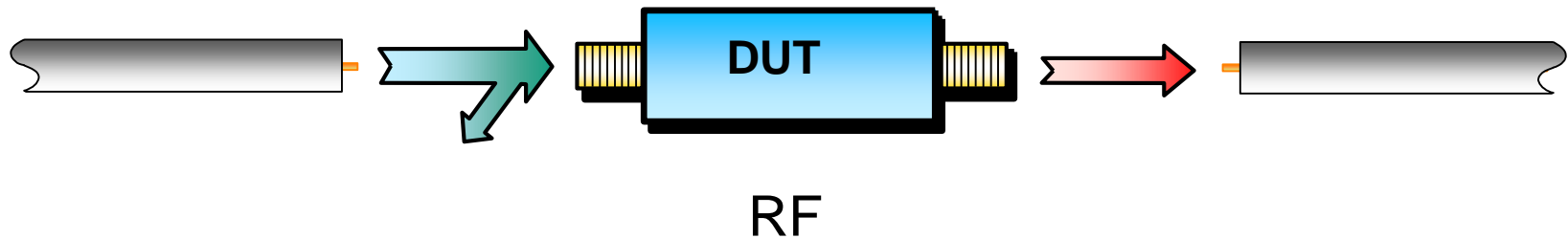
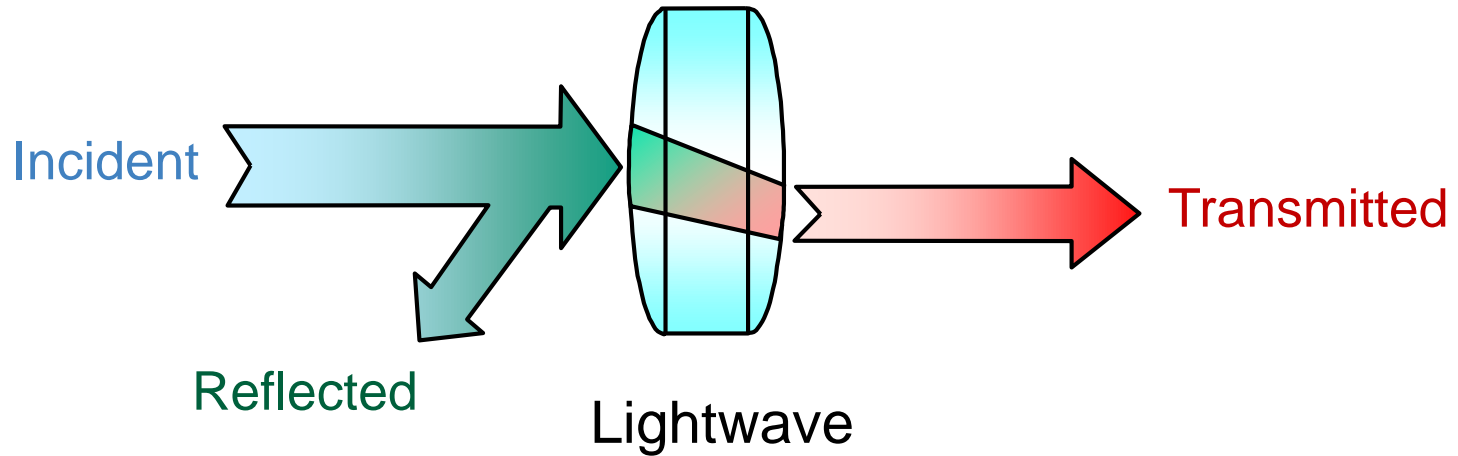
6. X-parameter (nonlinear) characterization

Agenda

- What measurements do we make?
- Network analyzer hardware
- Error models and calibration
- Additional measurements

NA
Fundament
al

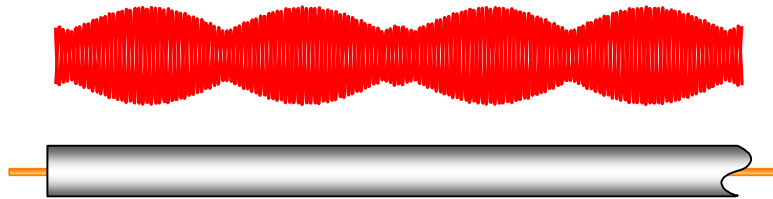
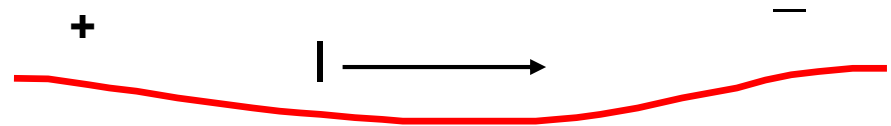
Lightwave Analogy to RF Energy



Transmission Line Basics

Low frequencies

- Wavelengths \gg wire length
- Current (I) travels down wires easily for efficient power transmission
- Measured voltage and current not dependent on position along wire

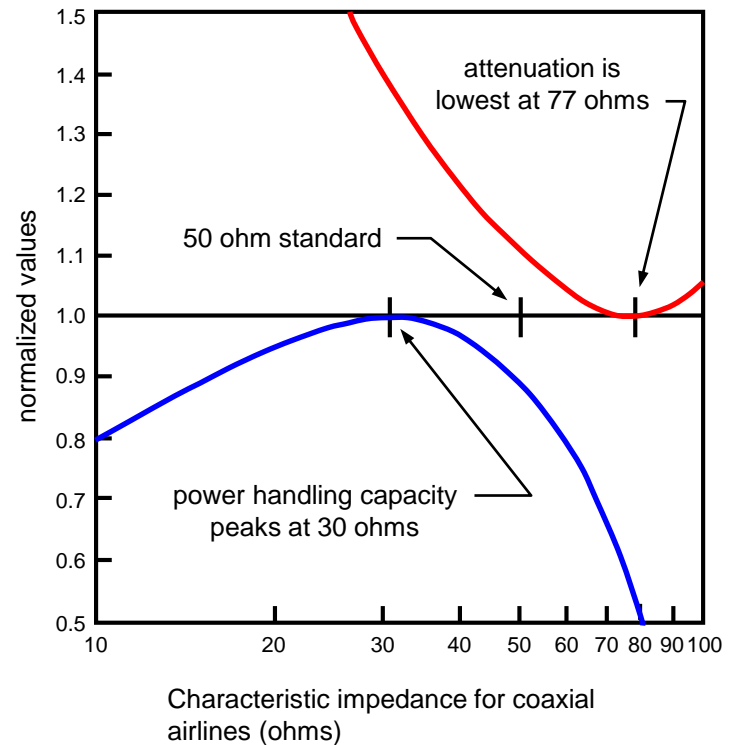
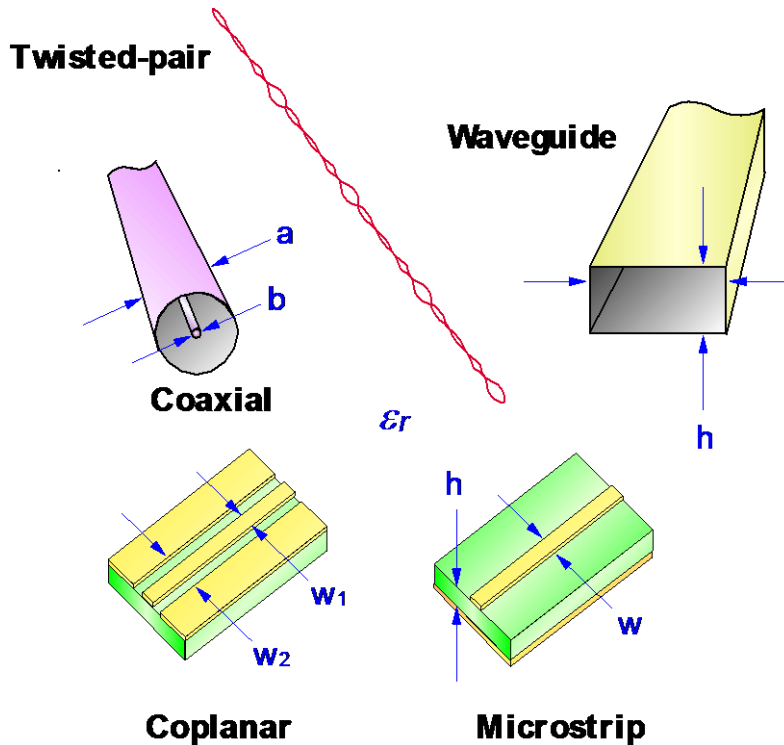


High frequencies

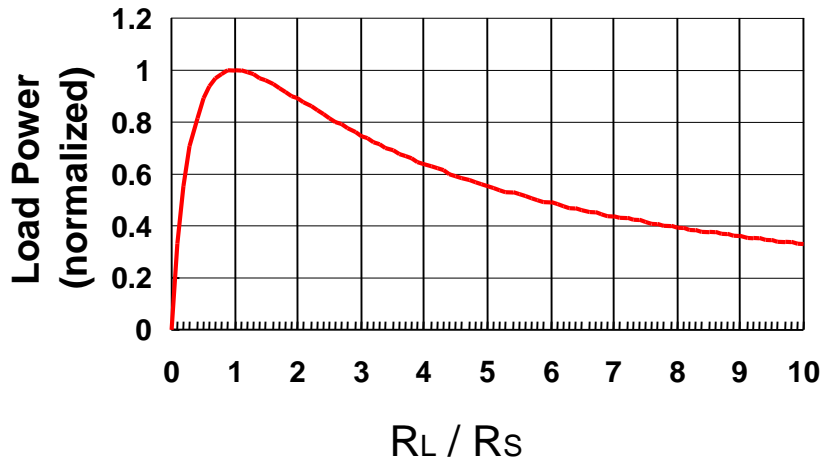
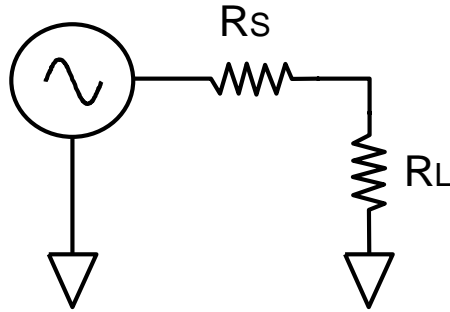
- Wavelength \gg or \ll length of transmission medium
- Need transmission lines for efficient power transmission
- Matching to characteristic impedance (Z_0) is very important for low reflection and maximum power transfer
- Measured envelope voltage dependent on position along line

Transmission line Z_0

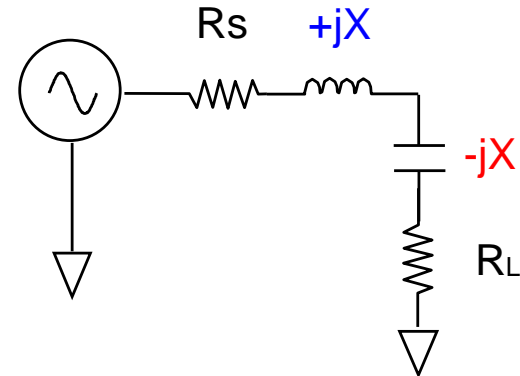
- Z_0 determines relationship between voltage and current waves
- Z_0 is a function of physical dimensions and ϵ_r
- Z_0 is usually a real impedance (e.g. 50 or 75 ohms)



Power Transfer Efficiency

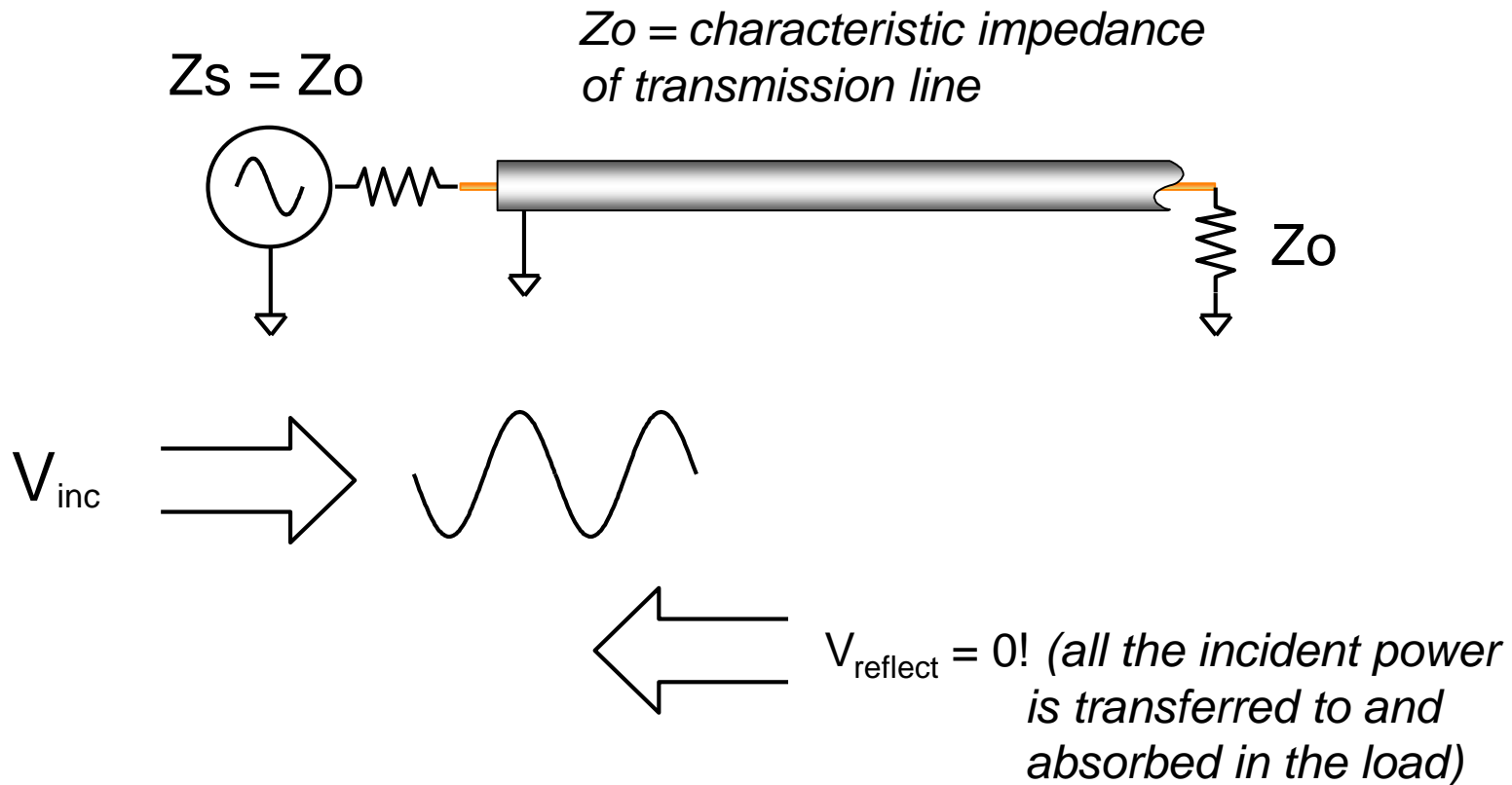


For complex impedances, maximum power transfer occurs when $Z_L = Z_S^*$ (conjugate match)



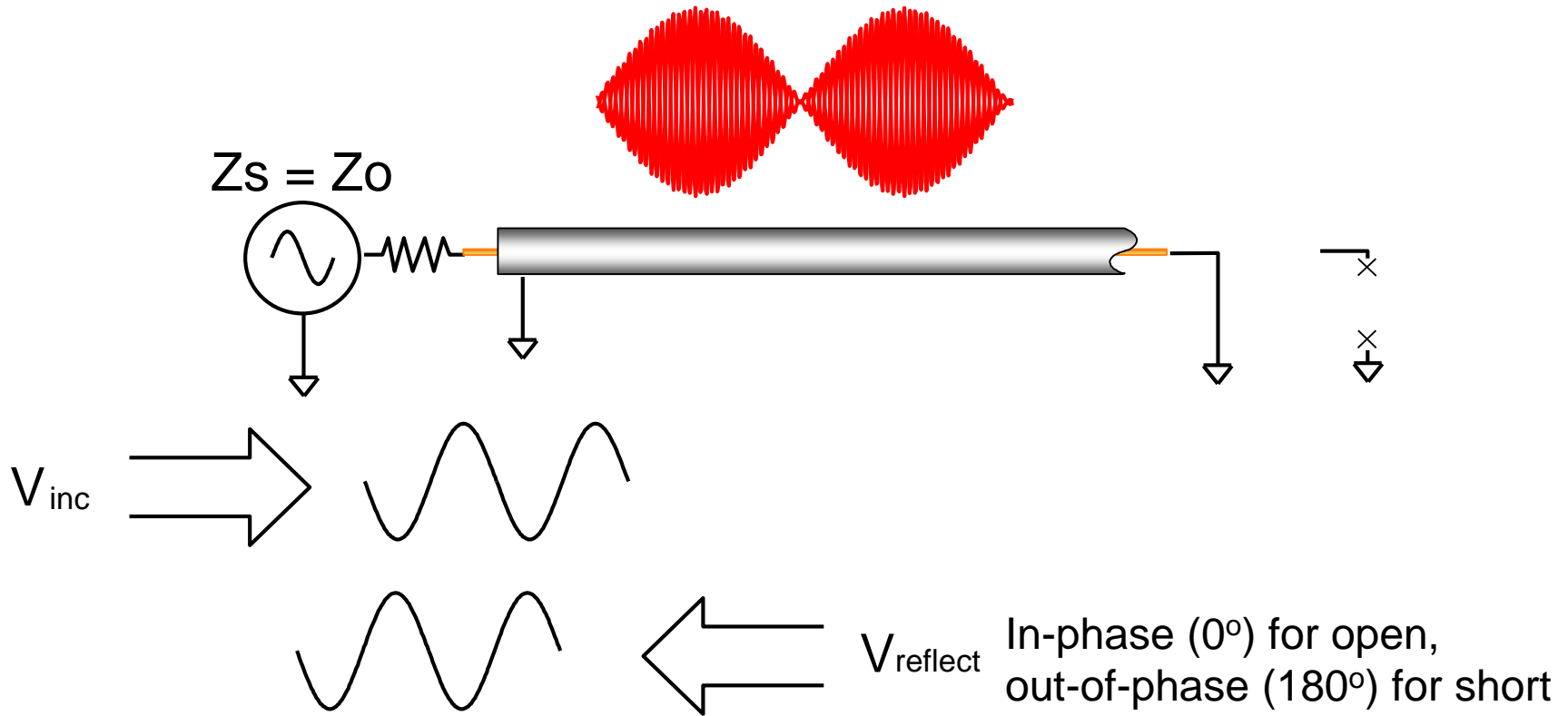
Maximum power is transferred when $R_L = R_S$

Transmission Line Terminated with Z_0



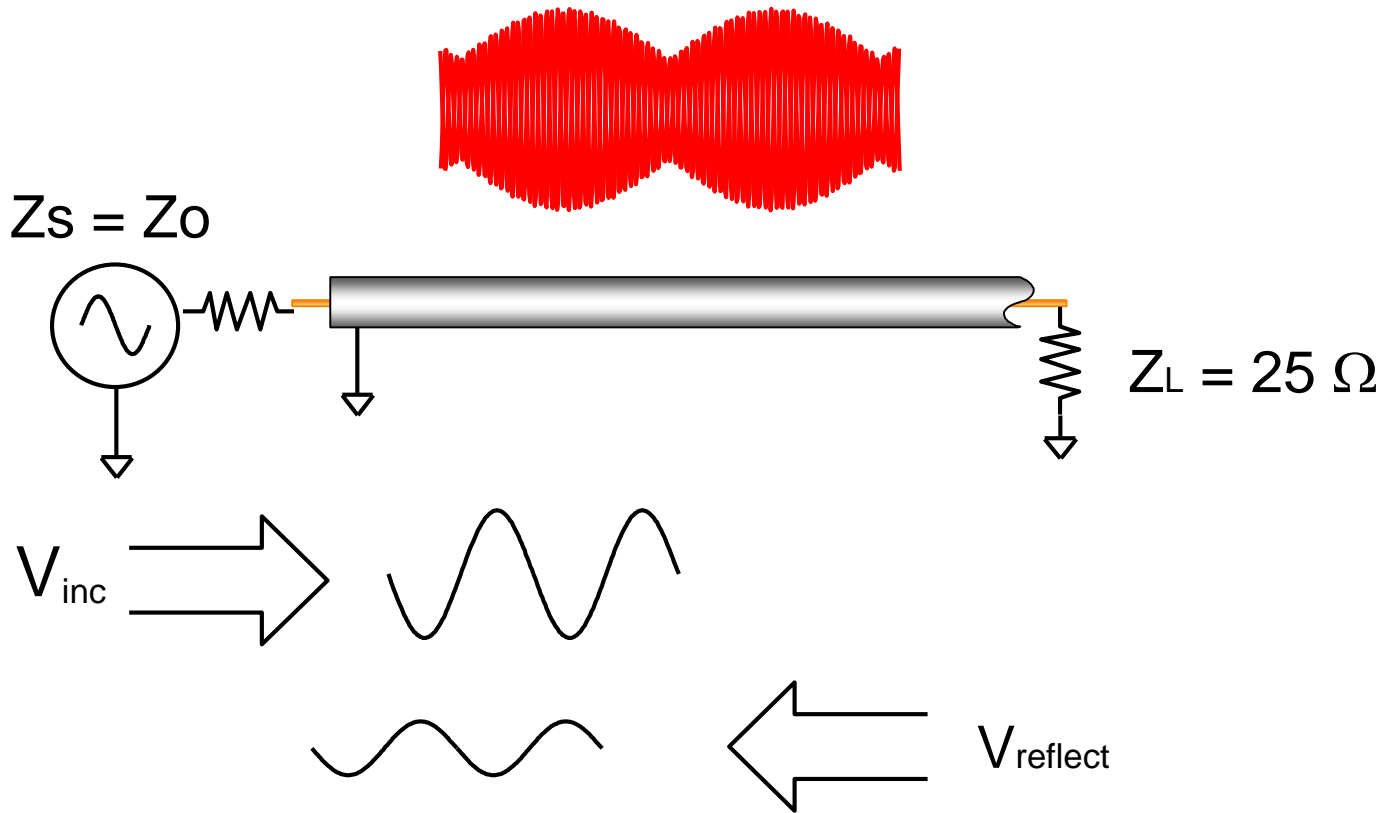
For reflection, a transmission line terminated in Z_0 behaves like an infinitely long transmission line

Transmission Line Terminated with Short, Open



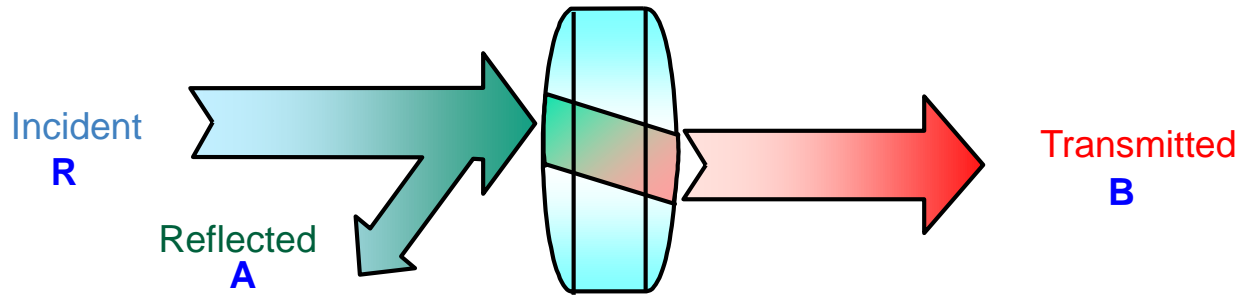
For reflection, a transmission line terminated in a short or open reflects all power back to source

Transmission Line Terminated with 25 Ohms



Standing wave pattern does not go to zero as with short or open

High-Frequency Device Characterization



REFLECTION

$$\frac{\text{Reflected}}{\text{Incident}} = \frac{A}{R}$$

- VSWR
- S-Parameters S_{11}, S_{22}
- Reflection Coefficient G, r
- Impedance, Admittance $R+jX, G+jB$
- Return Loss

TRANSMISSION

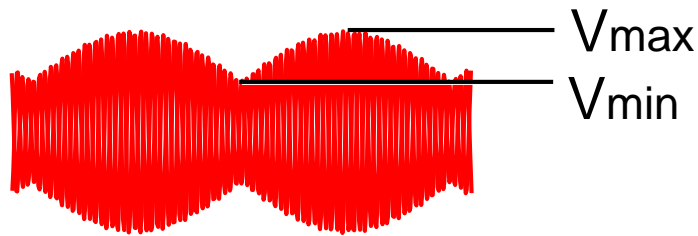
$$\frac{\text{Transmitted}}{\text{Incident}} = \frac{B}{R}$$

- Gain / Loss
- S-Parameters S_{21}, S_{12}
- Transmission Coefficient T, t
- Insertion Phase
- Group Delay

Reflection Parameters

Reflection Coefficient $\Gamma = \frac{V_{\text{reflected}}}{V_{\text{incident}}} = \rho \angle \Phi = \frac{Z_L - Z_0}{Z_L + Z_0}$

Return loss = $-20 \log(\rho)$, $\rho = |\Gamma|$



Voltage Standing Wave Ratio

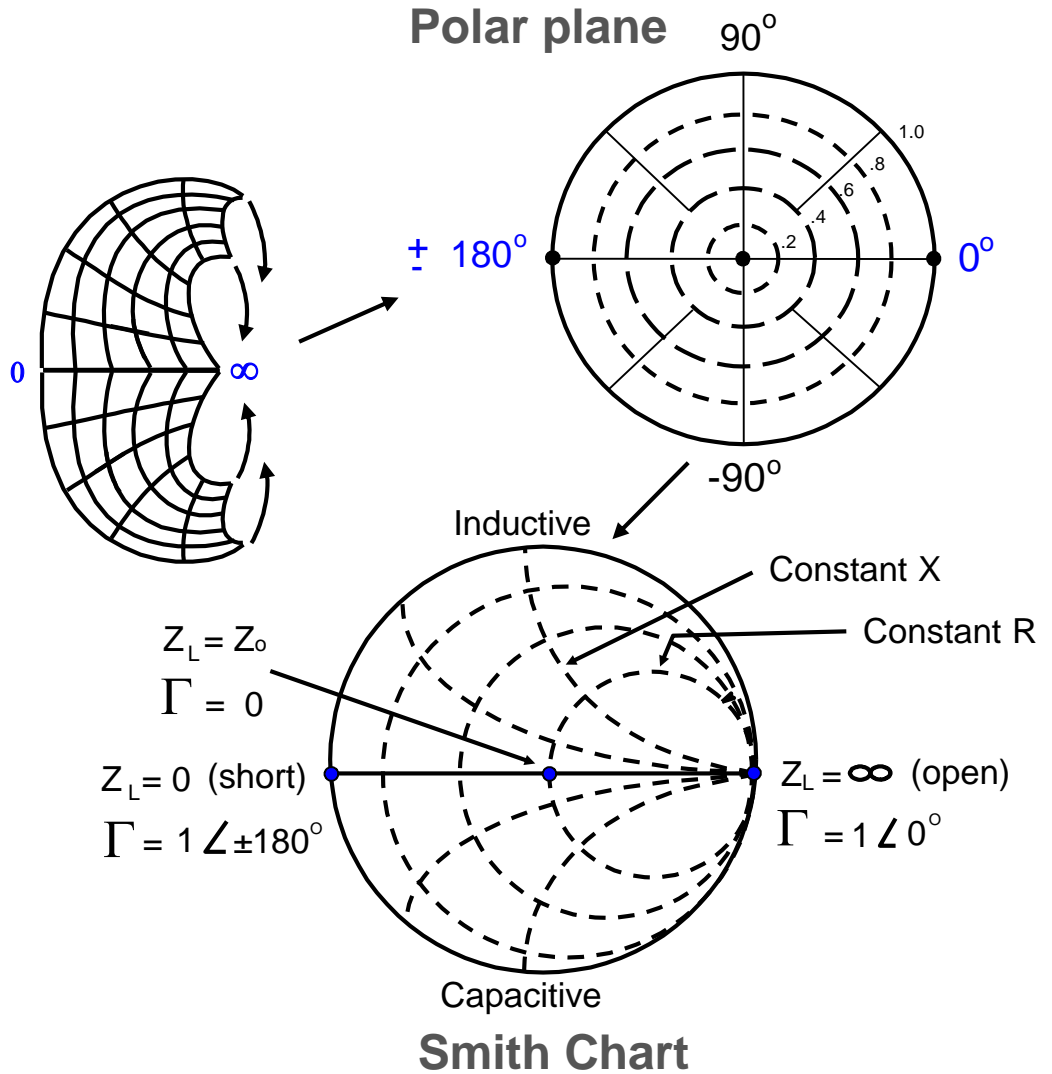
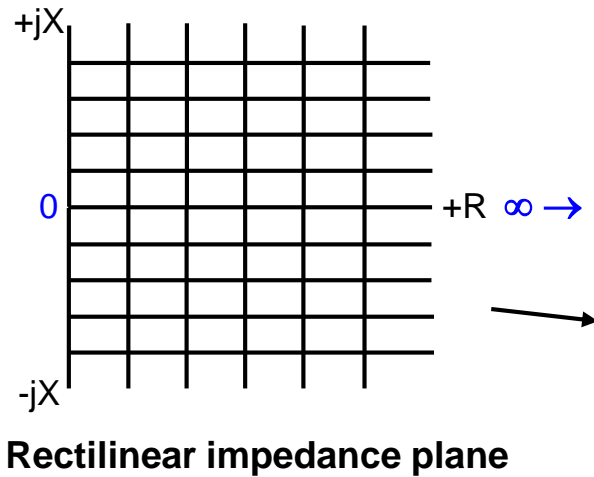
$$\text{VSWR} = \frac{V_{\text{max}}}{V_{\text{min}}} = \frac{1 + \rho}{1 - \rho}$$

No reflection
($Z_L = Z_0$)

Full reflection
($Z_L = \text{open, short}$)

0	ρ	1
∞ dB	RL	0 dB
1	VSWR	∞

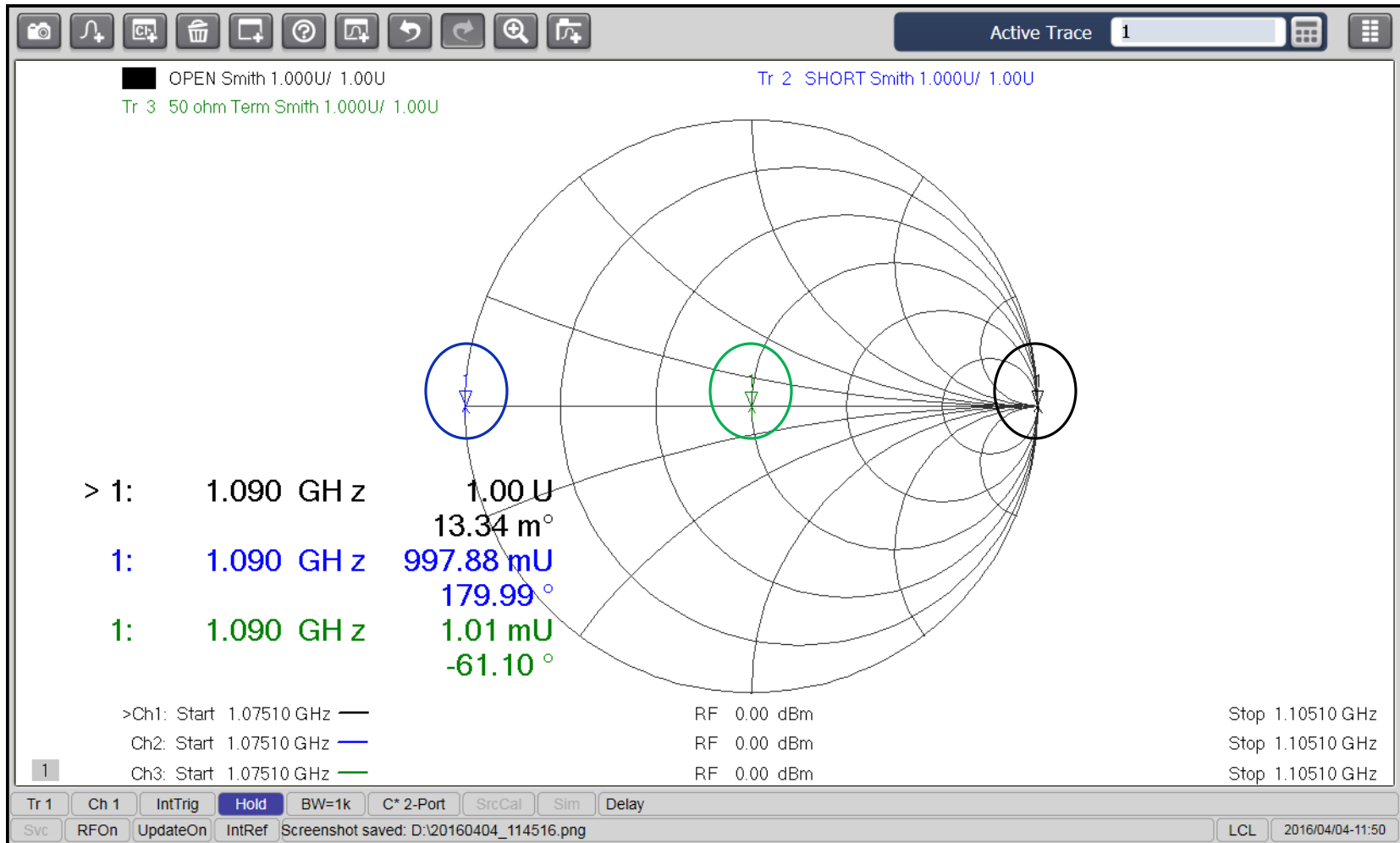
Smith Chart Review



Smith Chart maps rectilinear impedance plane onto polar plane

Demonstration: Smith Chart

Short, and Open, and a Matched Impedance



Transmission Parameters



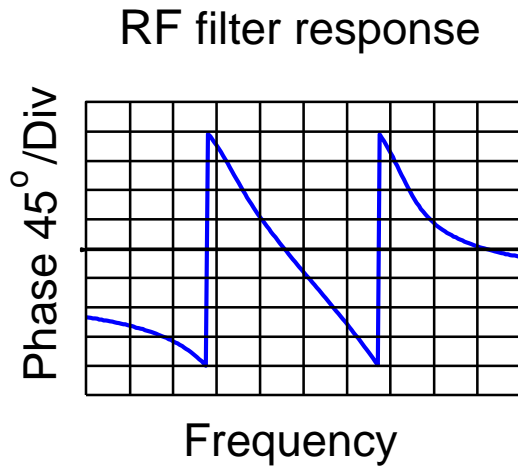
$$\text{Transmission Coefficient} = T = \frac{V_{\text{Transmitted}}}{V_{\text{Incident}}} = \tau \angle \phi$$

$$\text{Insertion Loss (dB)} = -20 \text{ Log} \left| \frac{V_{\text{Trans}}}{V_{\text{Inc}}} \right| = -20 \text{ Log}(\tau)$$

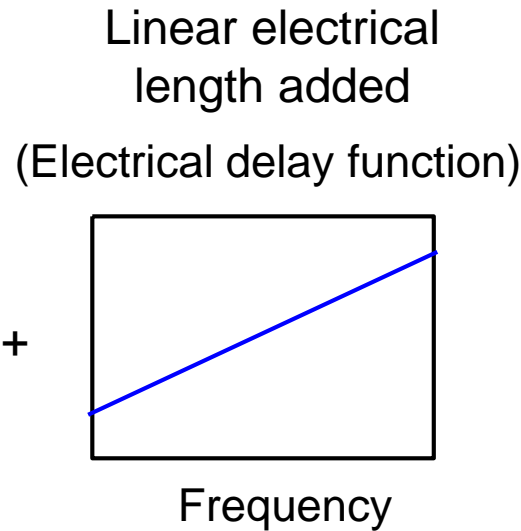
$$\text{Gain (dB)} = 20 \text{ Log} \left| \frac{V_{\text{Trans}}}{V_{\text{Inc}}} \right| = 20 \text{ Log}(\tau)$$

Deviation from Linear Phase

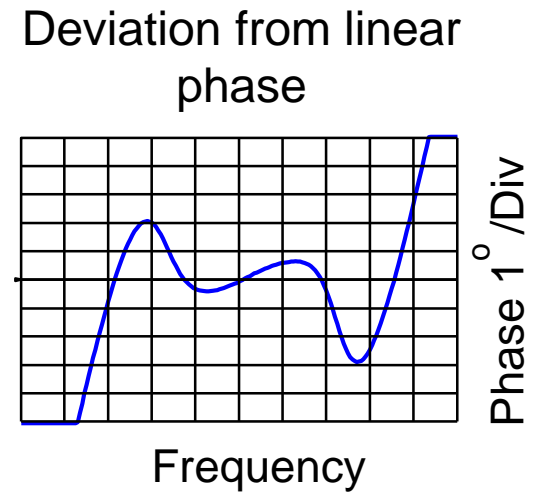
Use electrical delay to remove linear portion of phase response



Low resolution

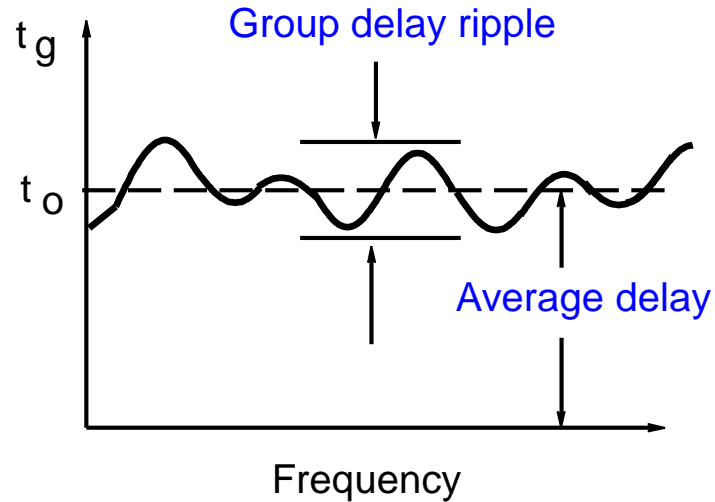
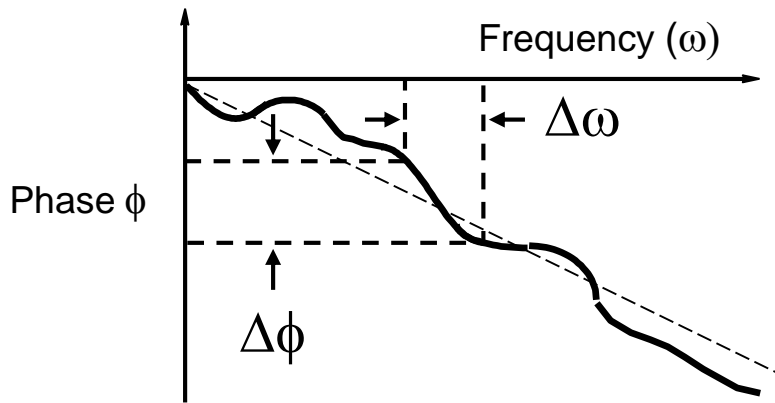


=



High resolution

Group Delay



Group Delay = (t_g)

$$\frac{-d\phi}{d\omega} = \frac{-1}{360^\circ} * \frac{d\phi}{df}$$

ϕ in radians

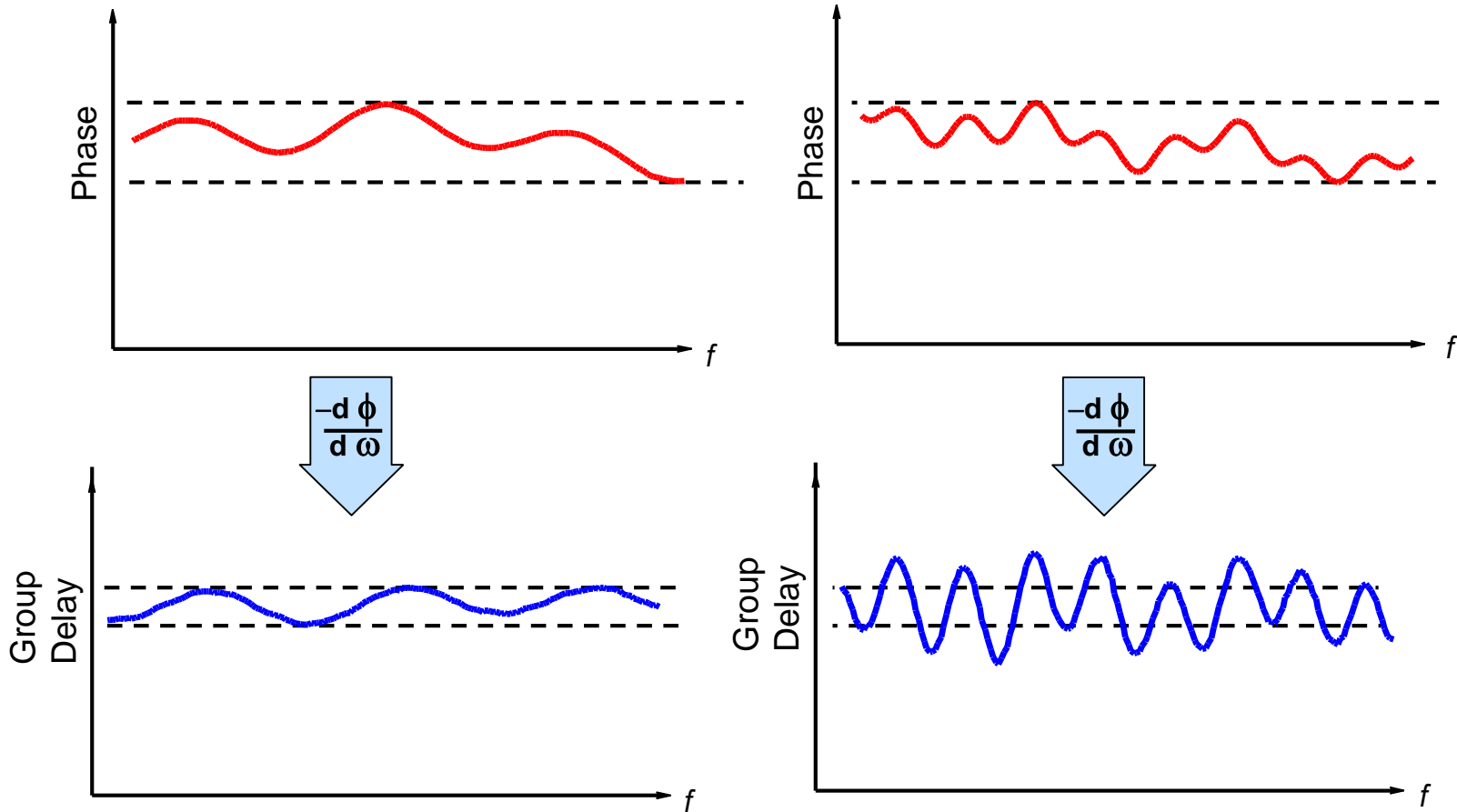
ω in radians/sec

ϕ in degrees

f in Hertz ($\omega = 2\pi f$)

- Group-delay ripple indicates phase distortion
- Average delay indicates electrical length of DUT
- Aperture ($\Delta\omega$) of measurement is very important

Why Measure Group Delay?



Same peak-peak phase ripple can result in different group delay

Characterizing Unknown Devices

Using parameters (H, Y, Z, S) to characterize devices:

- Gives linear behavioral model of our device
- Measure parameters (e.g. voltage and current) versus frequency under various source and load conditions (e.g. short and open circuits)
- Compute device parameters from measured data
- Predict circuit performance under any source and load conditions

H-parameters

$$V_1 = h_{11}I_1 + h_{12}V_2$$

$$I_2 = h_{21}I_1 + h_{22}V_2$$

Y-parameters

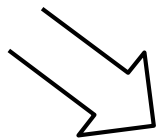
$$I_1 = y_{11}V_1 + y_{12}V_2$$

$$I_2 = y_{21}V_1 + y_{22}V_2$$

Z-parameters

$$V_1 = z_{11}I_1 + z_{12}I_2$$

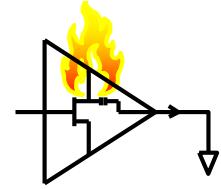
$$V_2 = z_{21}I_1 + z_{22}I_2$$



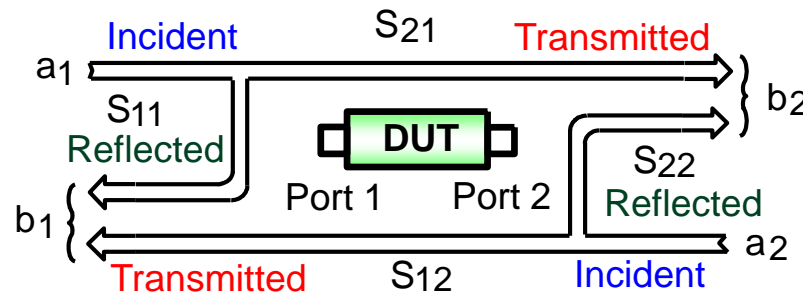
$$h_{11} = \left. \frac{V_1}{I_1} \right|_{V_2=0} \quad (\text{requires } \mathbf{short\ circuit})$$

$$h_{12} = \left. \frac{V_1}{V_2} \right|_{I_1=0} \quad (\text{requires } \mathbf{open\ circuit})$$

Why Use S-Parameters?



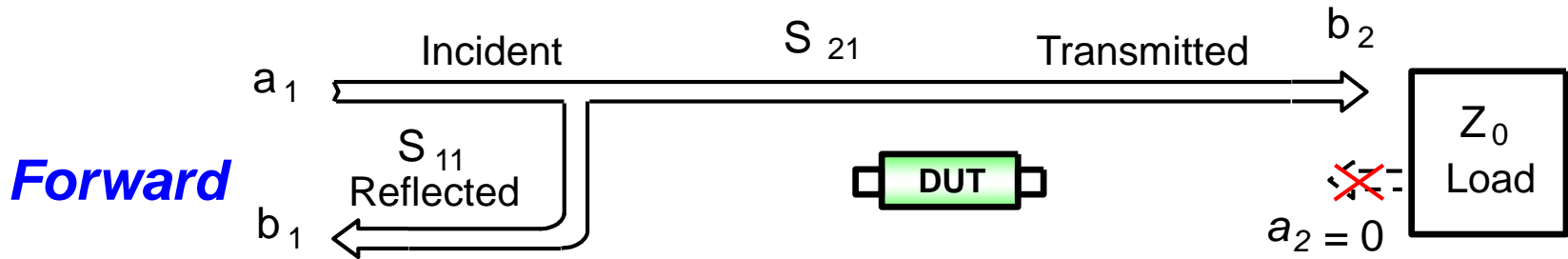
- Relatively easy to **obtain** at high frequencies
 - Measure voltage traveling waves with a vector network analyzer
 - Don't need shorts/opens (can cause active devices to oscillate or self-destruct)
- Relate to **familiar** measurements (gain, loss, reflection coefficient ...)
- Can **cascade** S-parameters of multiple devices to predict system performance
- Can **compute** H-, Y-, or Z-parameters from S-parameters if desired
- Can easily import and use S-parameter files in **electronic-simulation** tools



$$b_1 = S_{11}a_1 + S_{12}a_2$$

$$b_2 = S_{21}a_1 + S_{22}a_2$$

Measuring S-Parameters

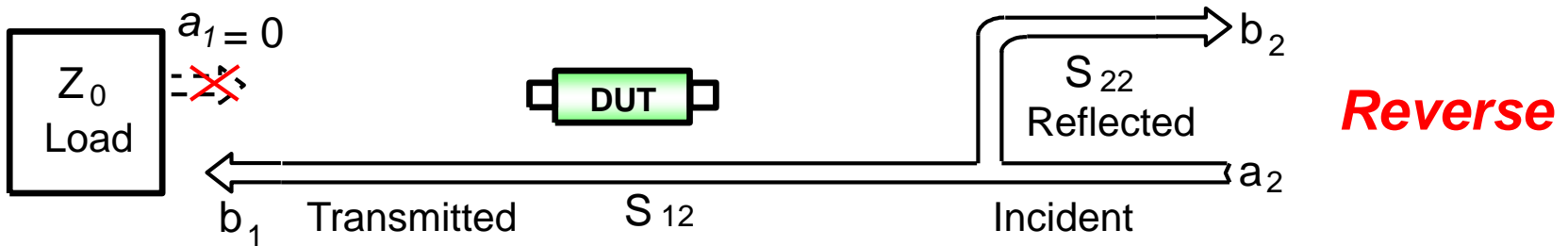


$$S_{11} = \frac{\text{Reflected}}{\text{Incident}} = \frac{b_1}{a_1} \Big|_{a_2 = 0}$$

$$S_{21} = \frac{\text{Transmitted}}{\text{Incident}} = \frac{b_2}{a_1} \Big|_{a_2 = 0}$$

$$S_{22} = \frac{\text{Reflected}}{\text{Incident}} = \frac{b_2}{a_2} \Big|_{a_1 = 0}$$

$$S_{12} = \frac{\text{Transmitted}}{\text{Incident}} = \frac{b_1}{a_2} \Big|_{a_1 = 0}$$



Equating S-Parameters With Common Measurement Terms


S_{11} = forward reflection coefficient (***input match***)

S_{22} = reverse reflection coefficient (***output match***)

S_{21} = forward transmission coefficient (***gain or loss***)

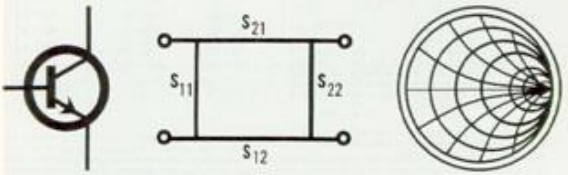

S_{12} = reverse transmission coefficient (***isolation***)

S-parameters is not very new...

HEWLETT  PACKARD

Transistor Parameter Measurements

application note 77-1



1001 Page Mail Road, Palo Alto, California, U.S.A., Geste: "HEWLETT" Tel: (415) 353-2000
Europe: 64 Route Des Acaziers, Geneva, Switzerland, Geste: "HEWLETT" Tel: (022) 61.81.10

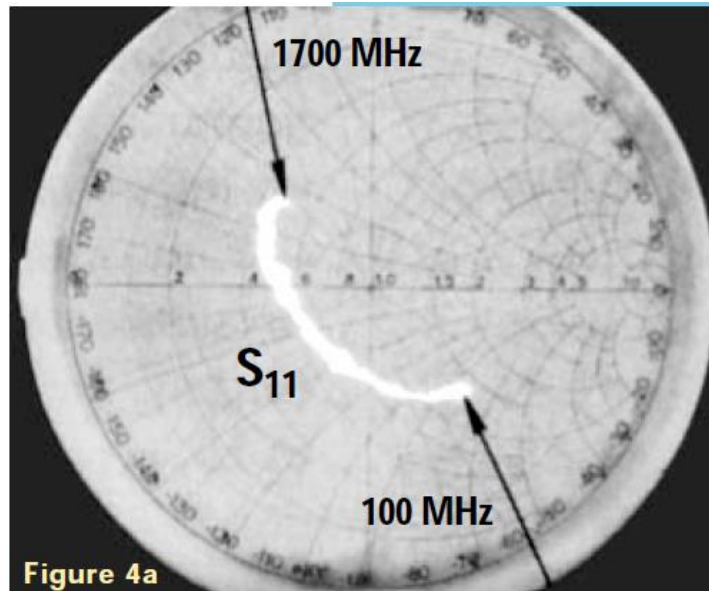


Figure 4a

s_{11} of a 2N3478 transistor measured with the classic HP 8410A network analyzer. Outermost circle on Smith Chart overlay corresponds to $|s_{11}| = 1$. The movement of s_{11} with frequency is approximately along circles of constant resistance, indicative of series capacitance and inductance.



Figure 1. 8410 network analyzer

The Network Analyzer make the S-parameter design simple, affordable and accurate!!



Agenda

- What measurements do we make?
- Network analyzer hardware
- Error models and calibration
- Additional measurements

Keysight Technologies Over 45 Years of Network Analyzer Innovations

1967
8410A



Figure 1. 8410 network analyzer

1975
8542A Automation V



Figure 2. 8542 automatic network analyzer system

1984
8510A set the industry
standard



Figure 3. 8510 network analyzer

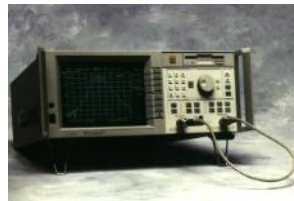
1986
8753 Series New economy
entry into RF market



1988
8720 Series New
economy entry into the
Microwave



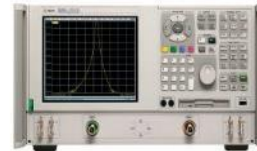
1991
8711 Series Low
Frequency



1996
8510XF Single sweep
up 110GHz



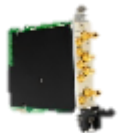
2000
PNA: New standard
of performance



2001
ENA



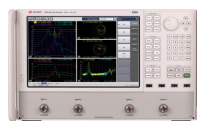
2014
PXI VNA



2007
PNA-X



2008
FieldFox



2015
E5080A

Broadband Passive Components for Microwave Network Analysis

HEWLETT-PACKARD JOURNAL

It takes more than an advanced network analyzer to make accurate, broadband device-parameter measurements. You can't do it without precision, broadband hardware—things like directional couplers, line stretchers, switches, and transmission lines. It also helps to have everything in one instrument.

By Stephen F. Adam, George R. Kirkpatrick, and Richard A. Lyon

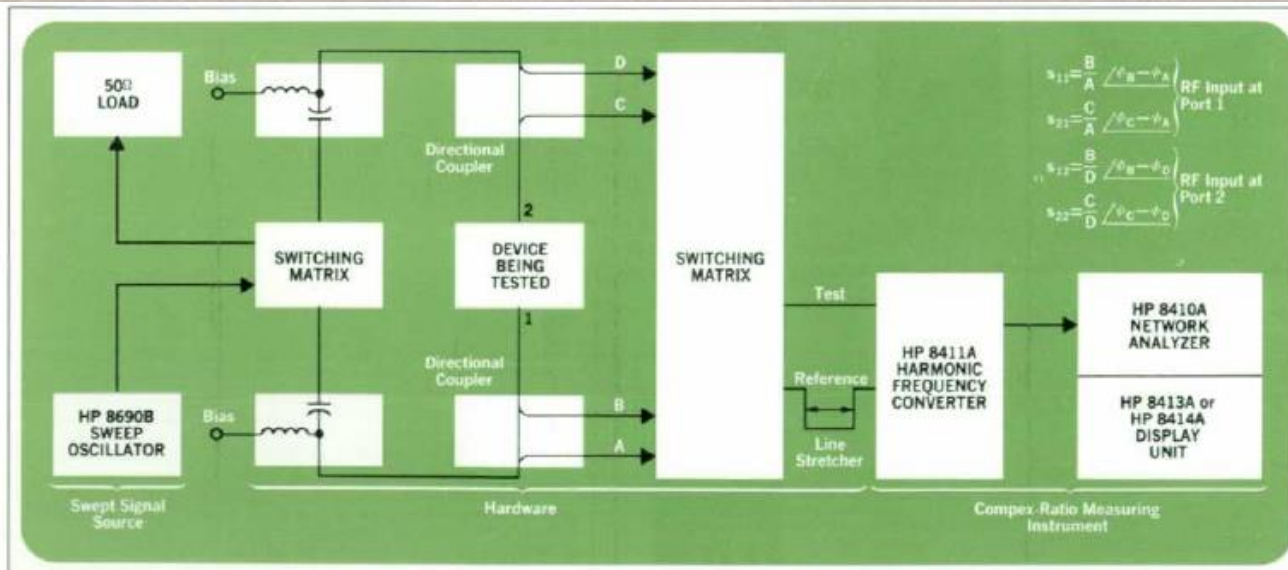
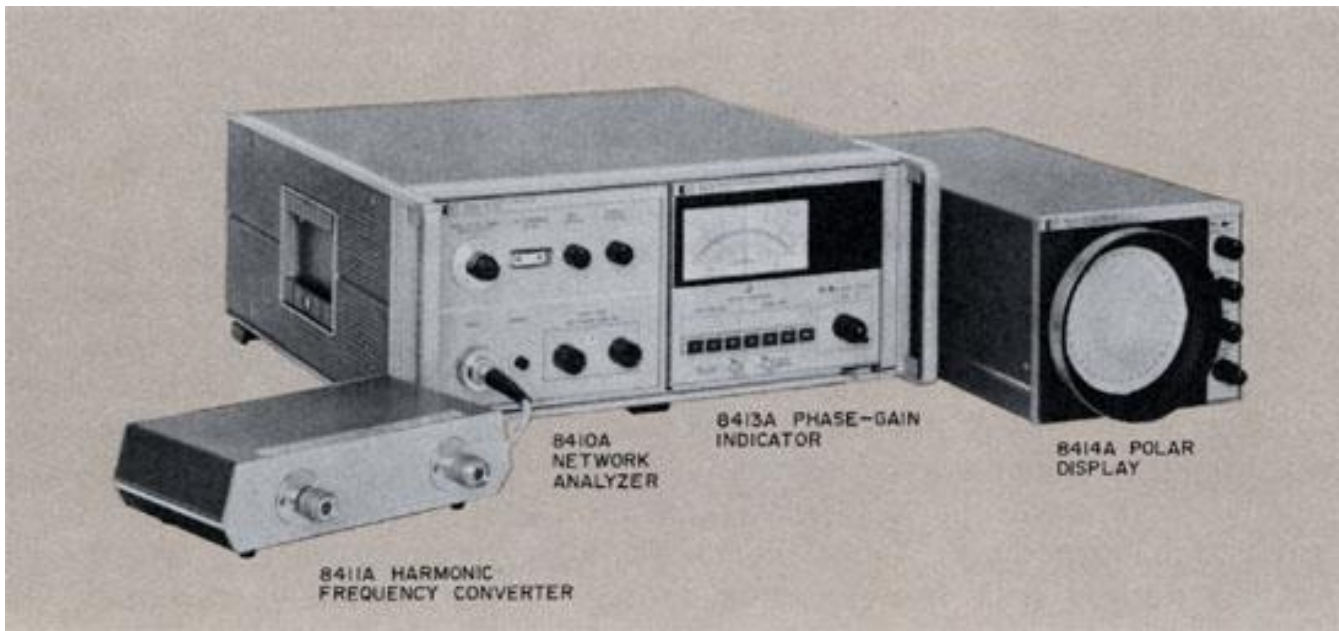


THERE WAS A TIME, not very long ago, when microwave transmission and reflection measurements were nearly always magnitude-only measurements. People were interested in phase, of course, and it would have been most desirable to have a system that could measure magnitude and phase looking into or through any two-port device. But a system that could do this, and do it over very broad frequency ranges, conveniently and accurately, would have been extremely expensive and complex.

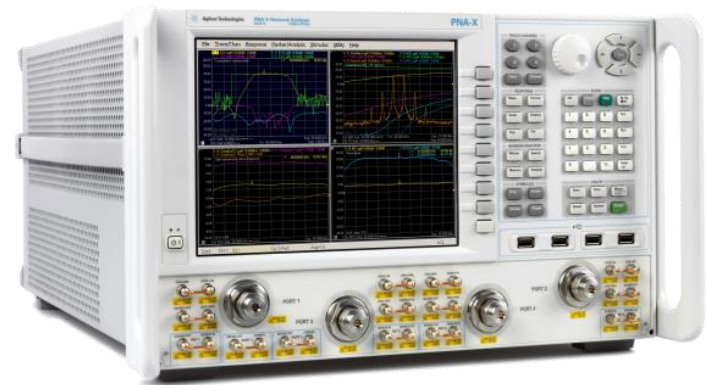
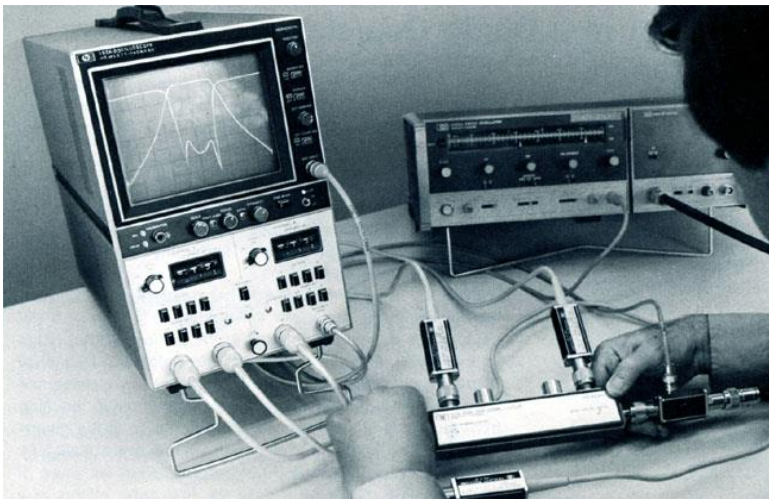
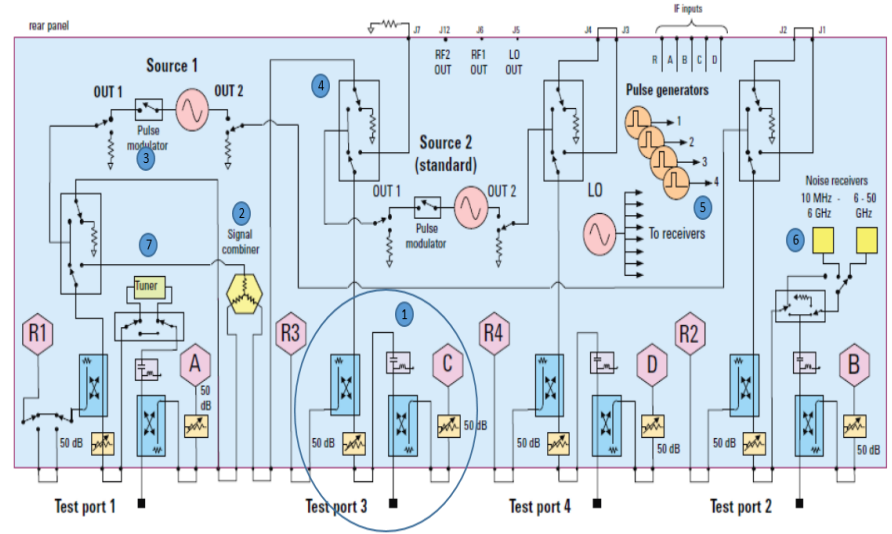
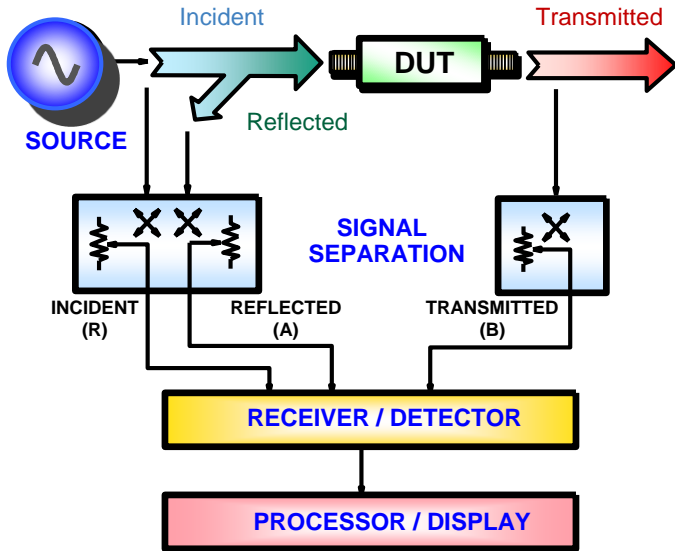
At Hewlett-Packard, the key to broadband microwave measurements proved to be a dc-to-12.4-GHz sampling device, developed in 1966.^[1] Using the device as a harmonic mixer, a network analyzer system, Model 8410A, was developed and introduced in 1967.^[2] The network

analyzer is basically an instrument which measures and displays the complex ratio of two signals. Specifically, it measures the complex reflection and transmission coefficients, or s-parameters, of active and passive devices.^[3] These parameters characterize the device completely.

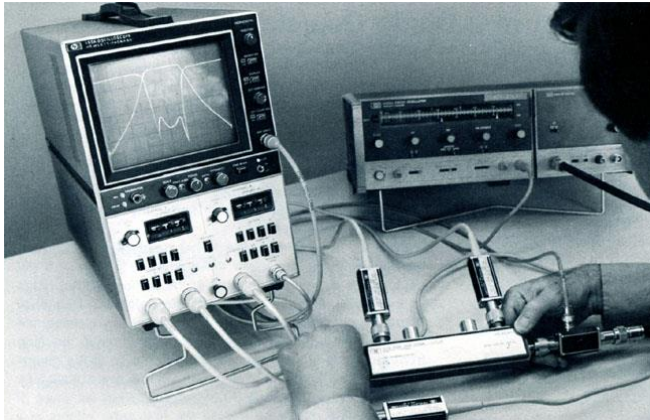
Besides the network analyzer, two other elements are needed to measure network parameters. One is a swept signal source, and the other is a collection of passive components for interfacing the signal source and the network analyzer with the device being tested. Fig. 1 illustrates the three elements and their relationships. The passive components take the signal from the sweep generator, isolate part of it for use as a reference signal, and direct the rest to one of the ports of the device being



Network Analyzer Block Diagram: Yesterday and Today

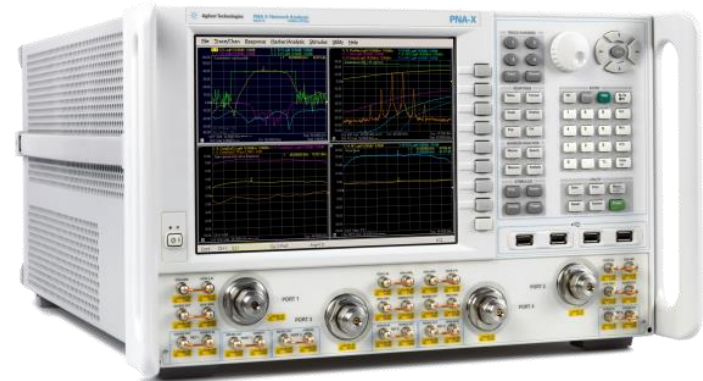
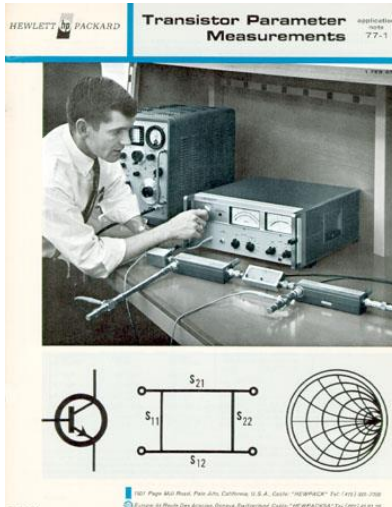


Network Analyzer Block Diagram: Yesterday and Today



Measurements:

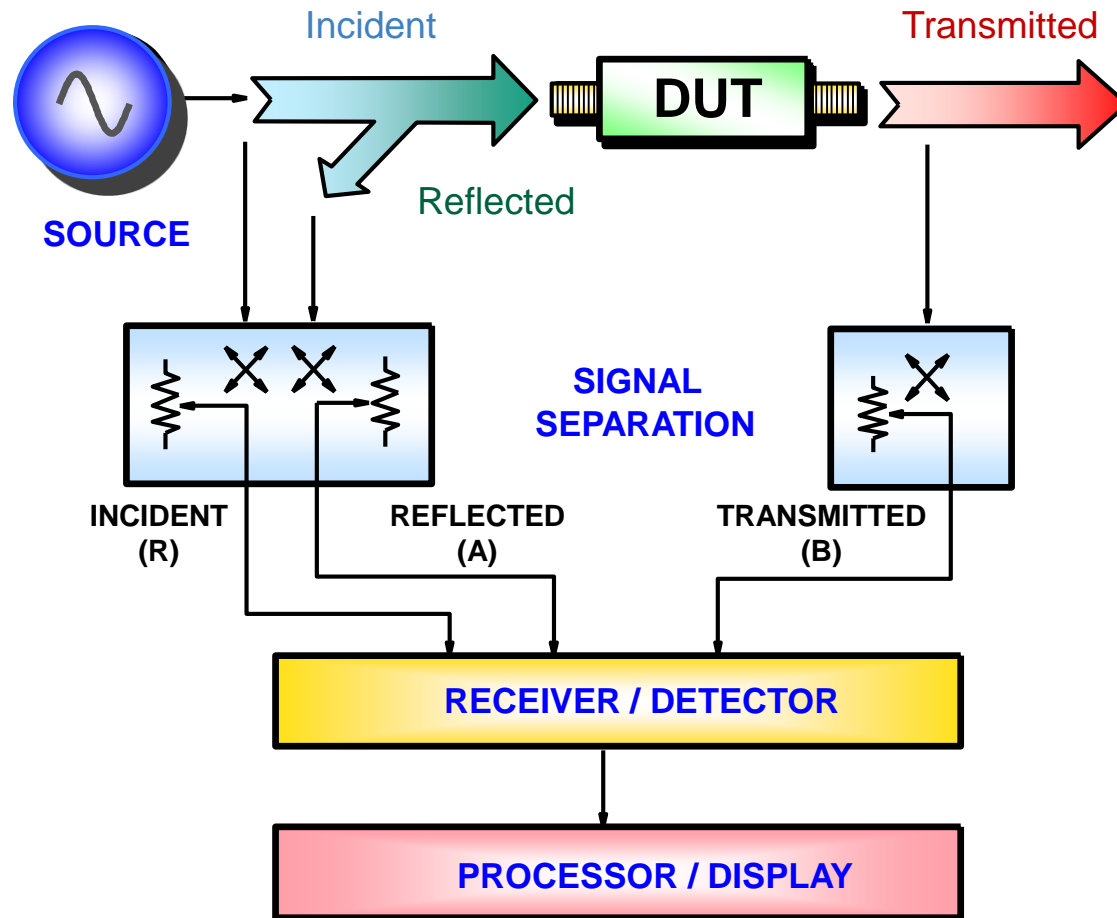
- ✓ CW S-parameters



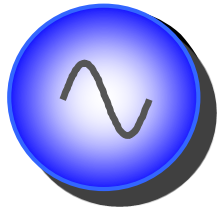
Measurements:

- ✓ CW S-parameters
- ✓ Pulsed S-parameters
- ✓ Gain compression
- ✓ AM-to-PM conversion
- ✓ Harmonics
- ✓ Intermodulation distortion
- ✓ Noise Figure
- ✓ Hot-S-parameters
- ✓ Phase versus drive
- ✓ True-mode differential stimulus
- ✓ Spectrum Analysis

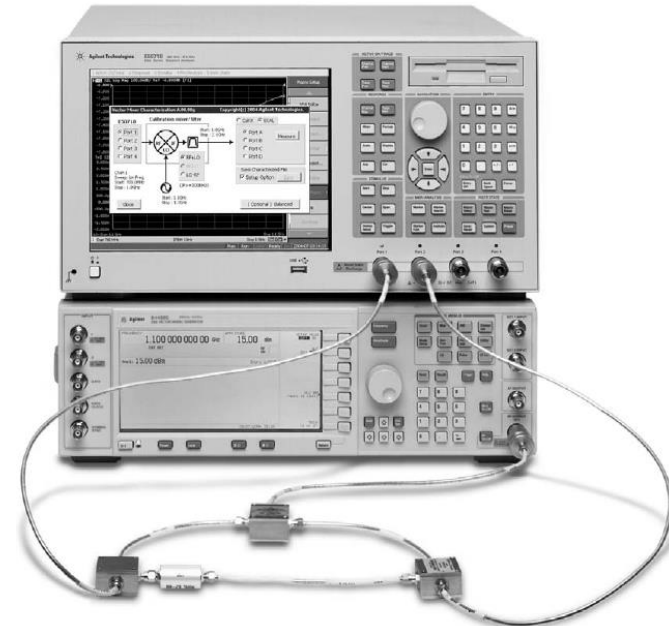
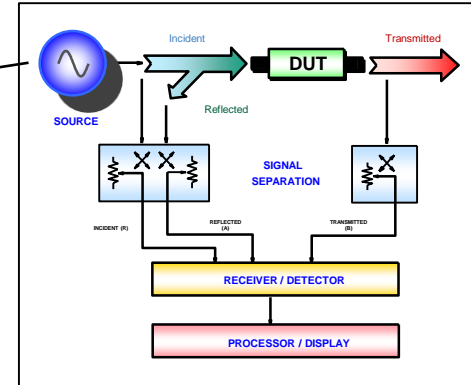
Generalized Network Analyzer Block Diagram (Forward Measurements Shown)



Source

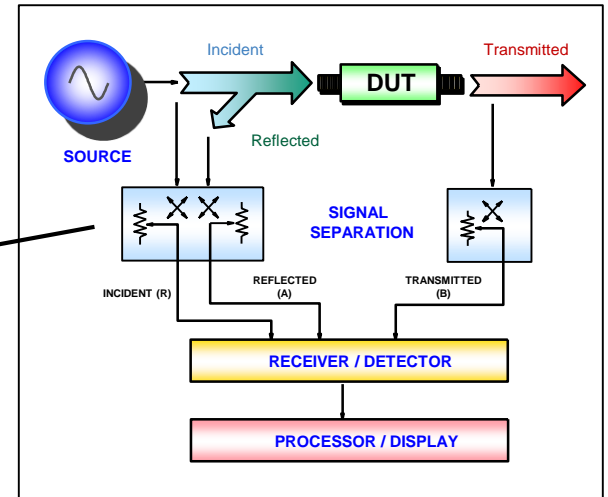


- Supplies stimulus for system
- Can sweep frequency or power
- Traditionally NAs had one signal source
- Modern NAs have the option for a second internal source and/or the ability to control external source
 - Can control an external source as a local oscillator (LO) signal for mixers and converters
 - Useful for mixer measurements like conversion loss, group delay

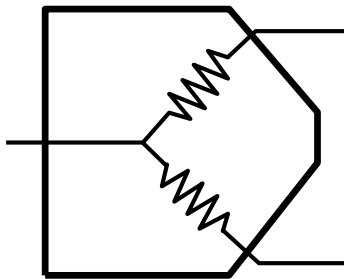


Signal Separation

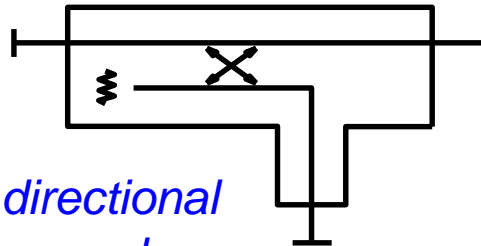
- Measure incident signal for reference
- Separate incident and reflected signals



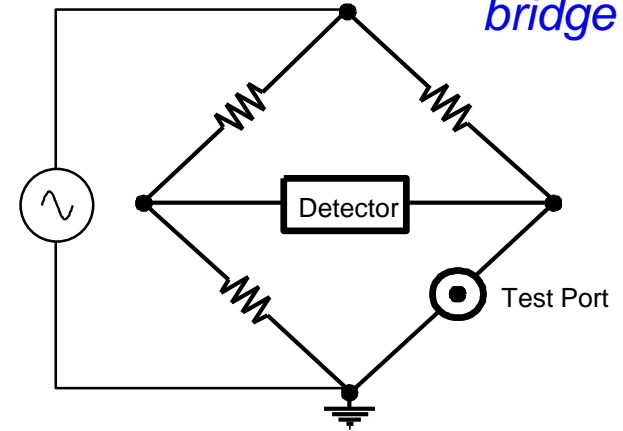
splitter



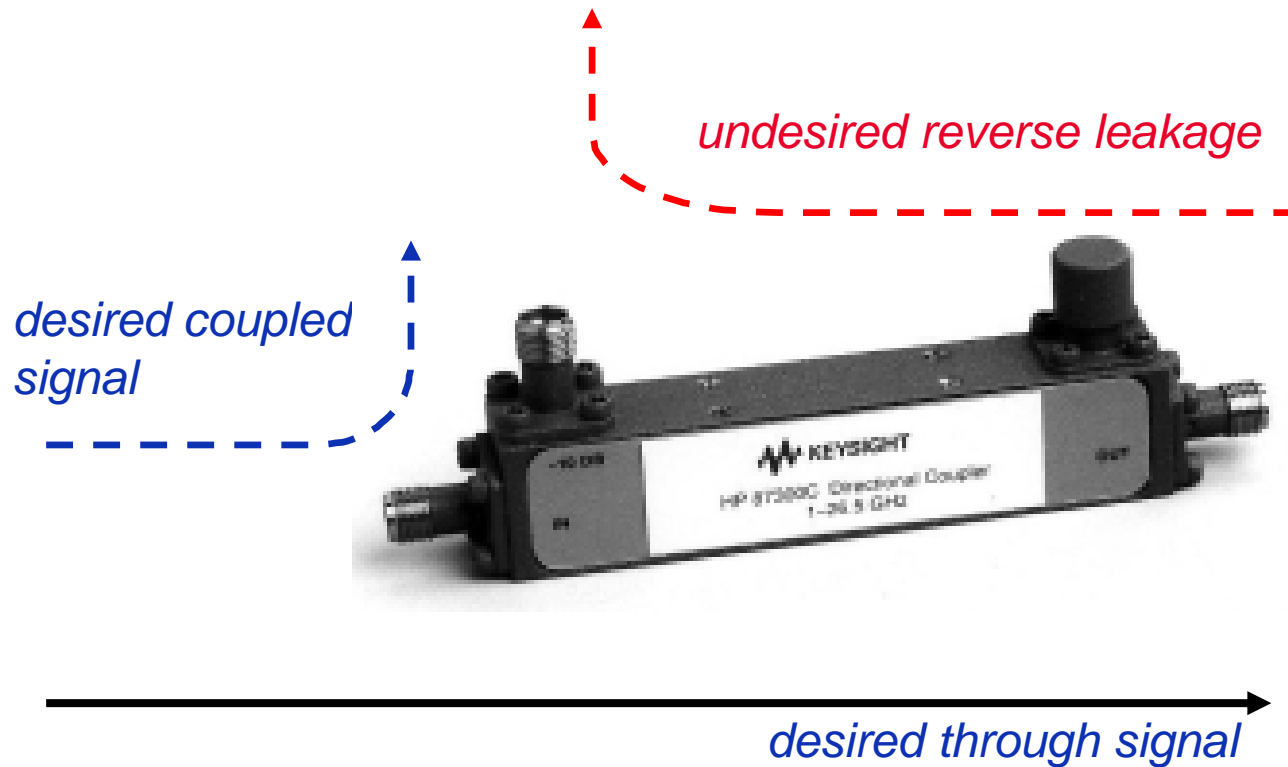
directional coupler



bridge

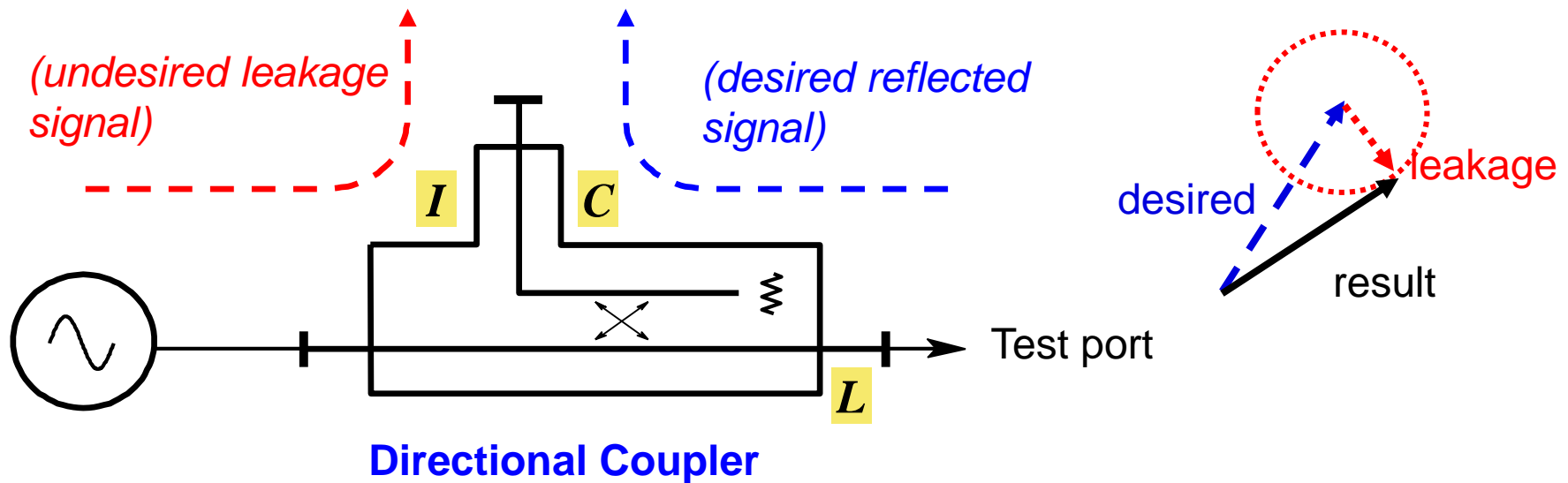


Directional Coupler



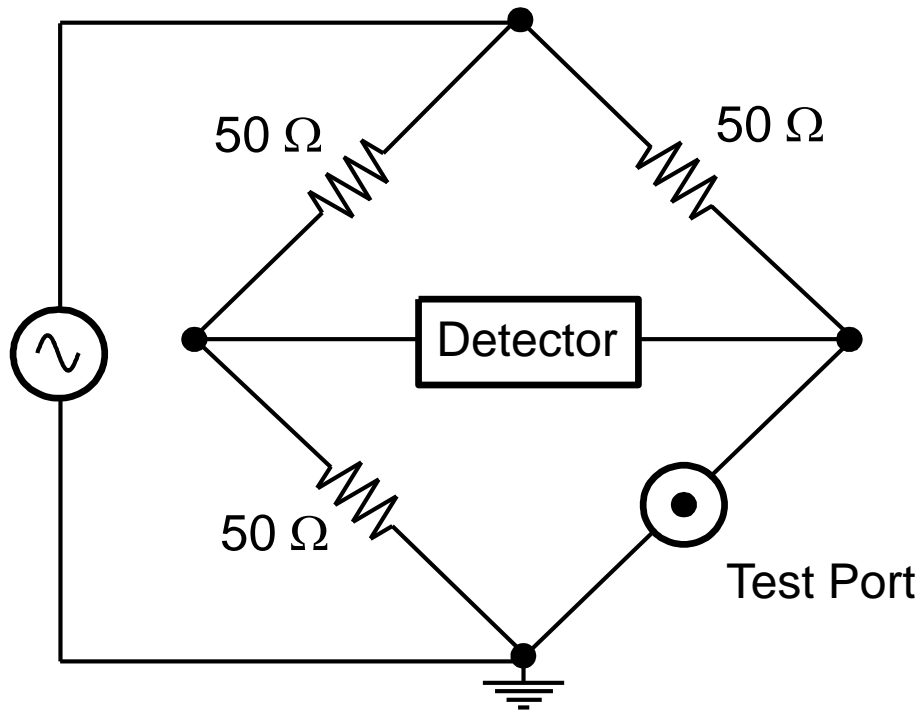
Directivity

Directivity is a measure of how well a directional coupler or bridge can separate signals moving in opposite directions



$$\text{Directivity} = \text{Isolation (I)} - \text{Fwd Coupling (C)} - \text{Main Arm Loss (L)}$$

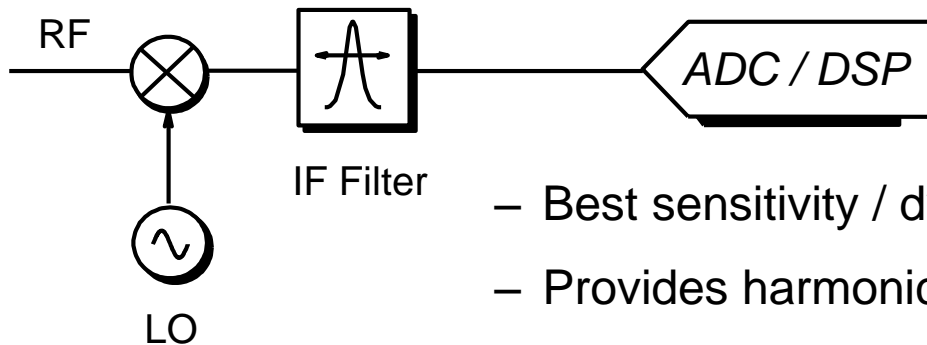
Directional Bridge



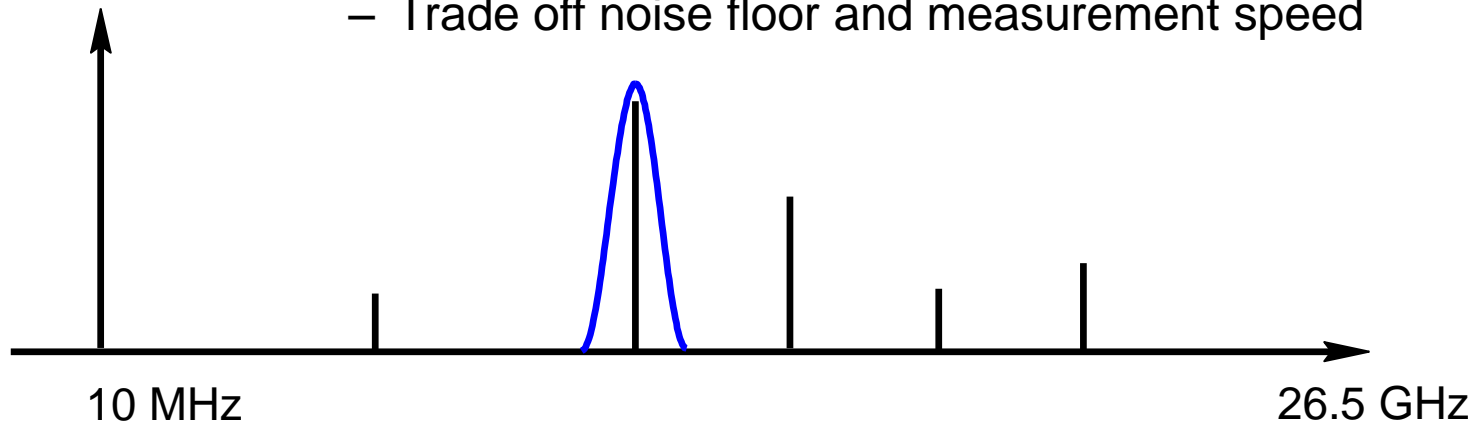
- 50-ohm load at test port balances the bridge -- detector reads zero
- Non-50-ohm load imbalances bridge
- Measuring magnitude and phase of imbalance gives complex impedance
- "Directivity" is difference between maximum and minimum balance
- Advantage: less loss at low frequencies
- Disadvantages: more loss in main arm at high frequencies and less power-handling capability

Detector:

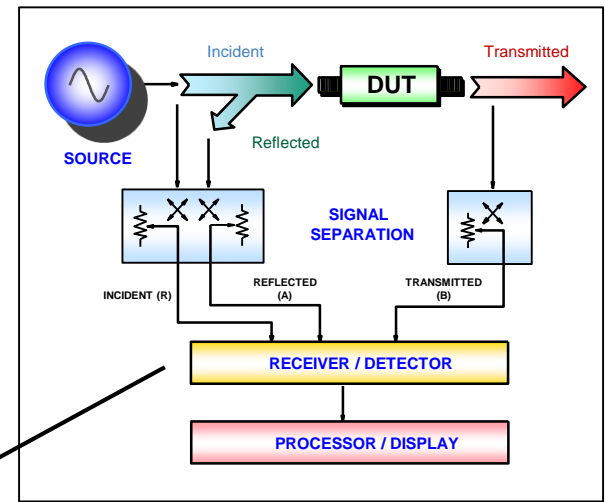
Narrowband Detection - Tuned Receiver



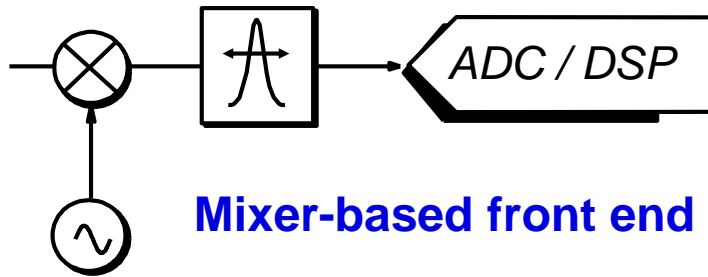
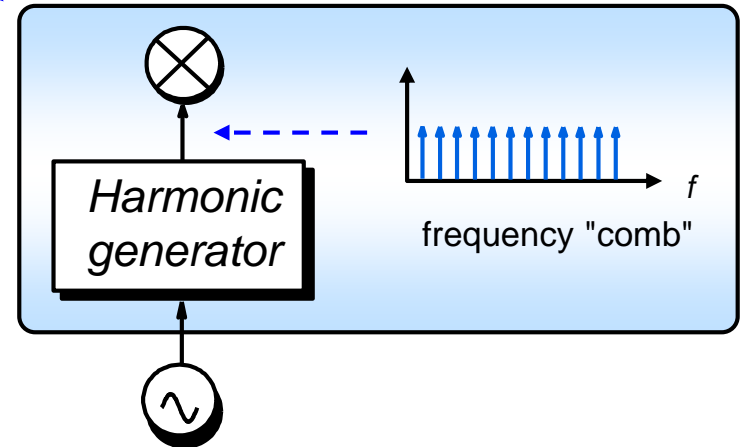
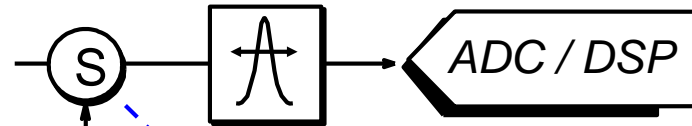
- Best sensitivity / dynamic range
- Provides harmonic / spurious signal rejection
- Improve dynamic range by increasing power, decreasing IF bandwidth, or averaging
- Trade off noise floor and measurement speed



Tuned Receiver Front Ends: Mixers Versus Samplers



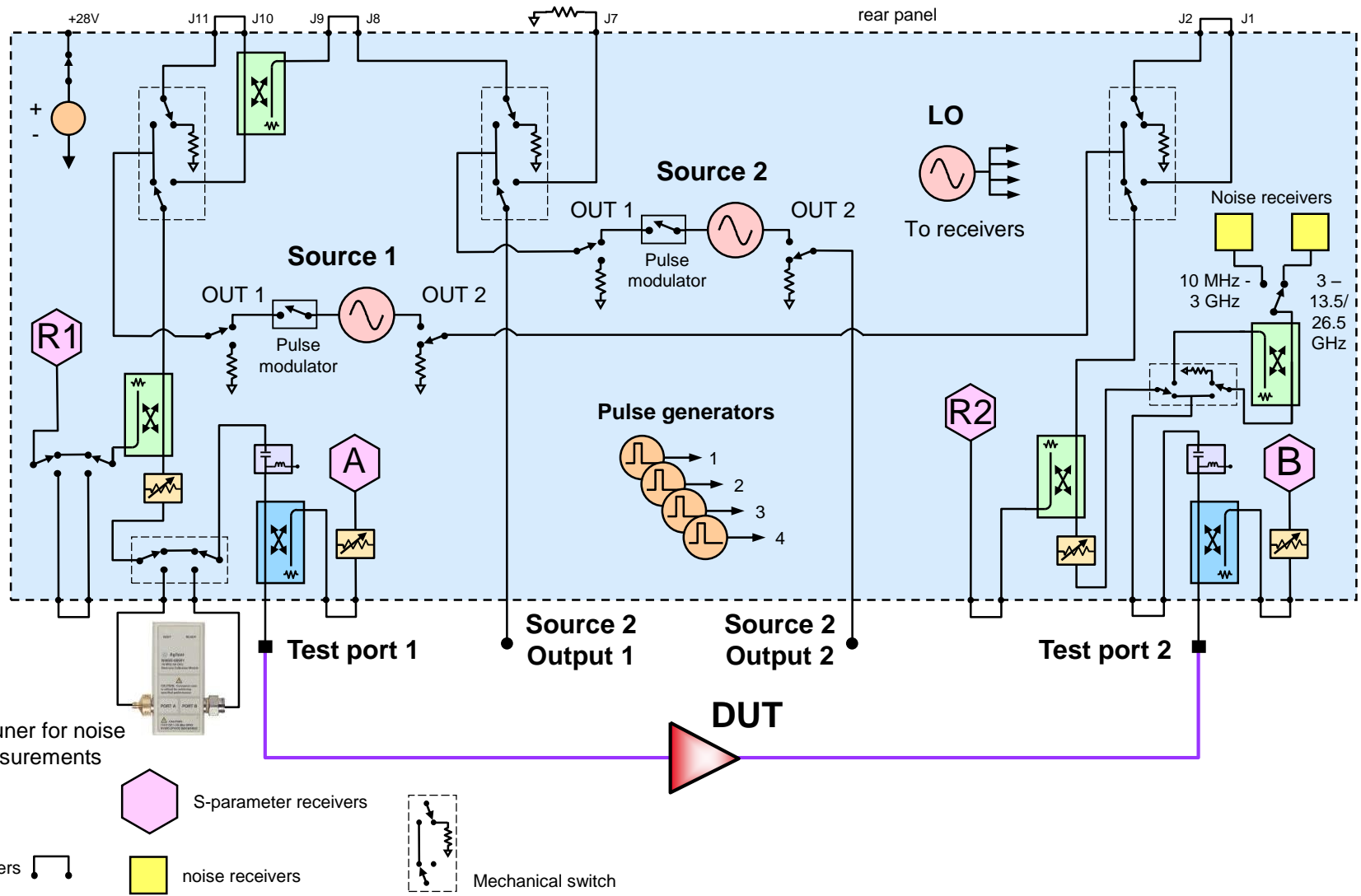
Sampler-based front end



Mixer-based front end

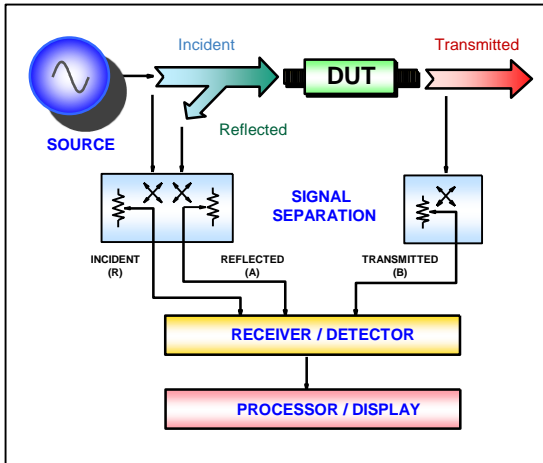
It is cheaper and easier to make broadband front ends using samplers instead of mixers, but dynamic range is considerably less

Modern VNA Block Diagram (2-Port PNA-X)

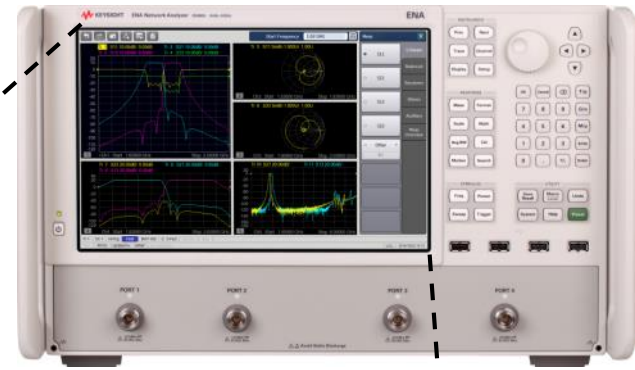


Impedance tuner for noise figure measurements

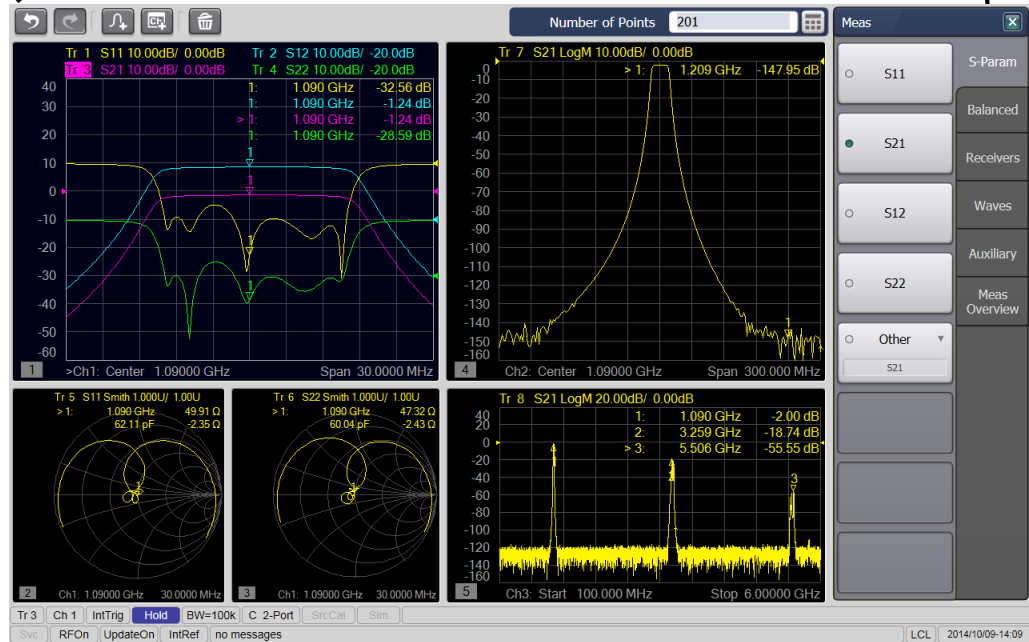
Processor / Display



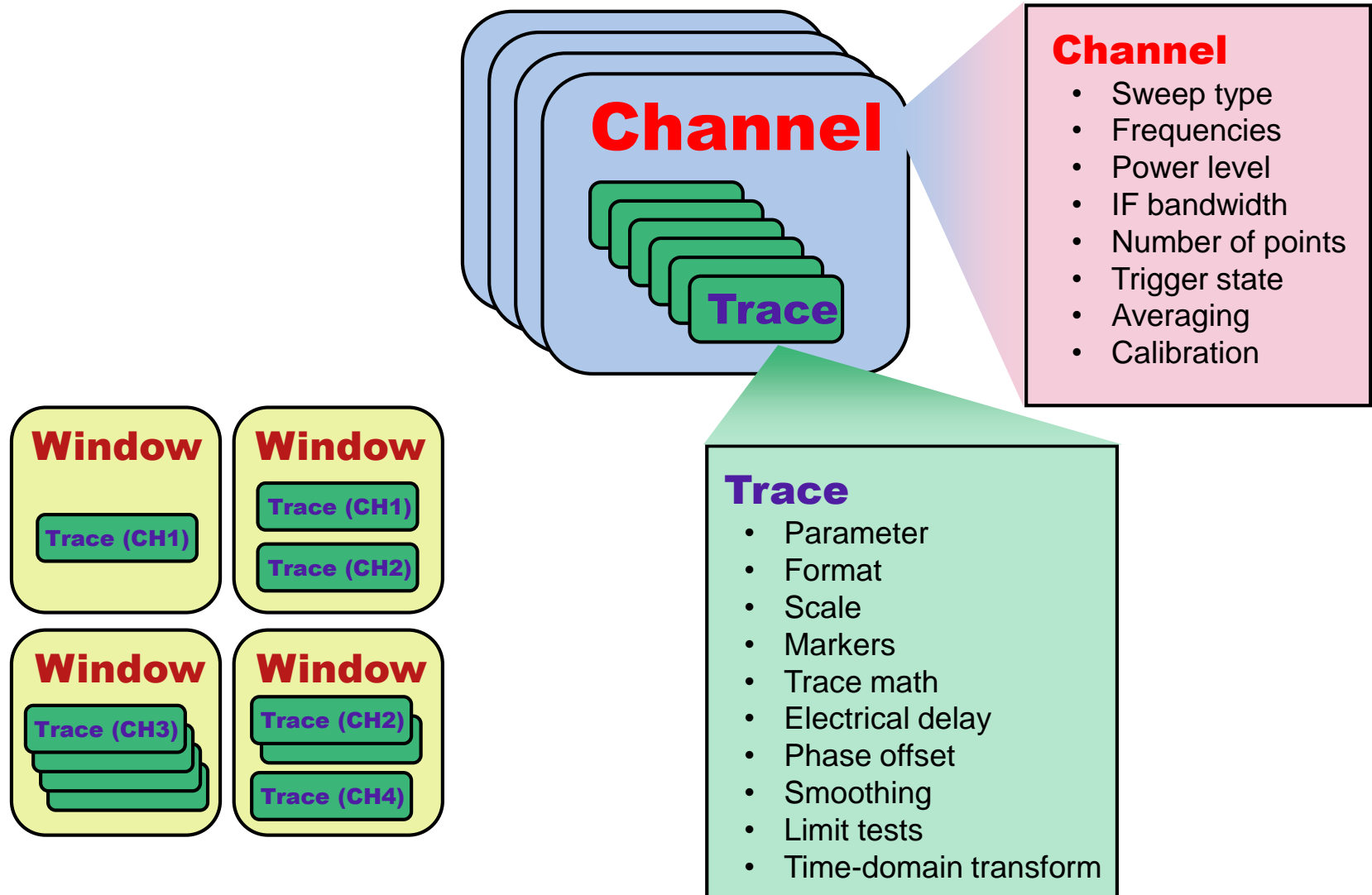
- Markers
- Limit lines
- Pass/fail indicators
- Linear/log formats
- Grid/polar/Smith charts
- Time-domain transform
- Trace math



E5080A ENA



Achieving Measurement Flexibility (PNA and E5080A)



Three Channel Example (PNA and E5080A)

Channel 1
frequency sweep (narrow)

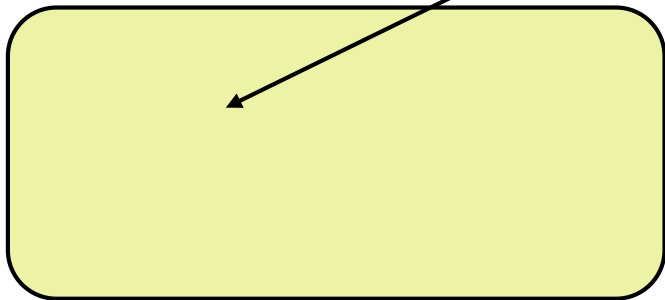
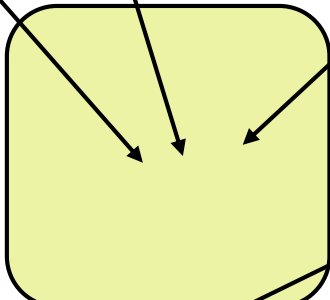
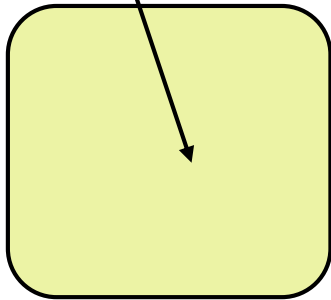
S21 S11 S21

Channel 2
frequency sweep (broad)

S21

Channel 3
power sweep

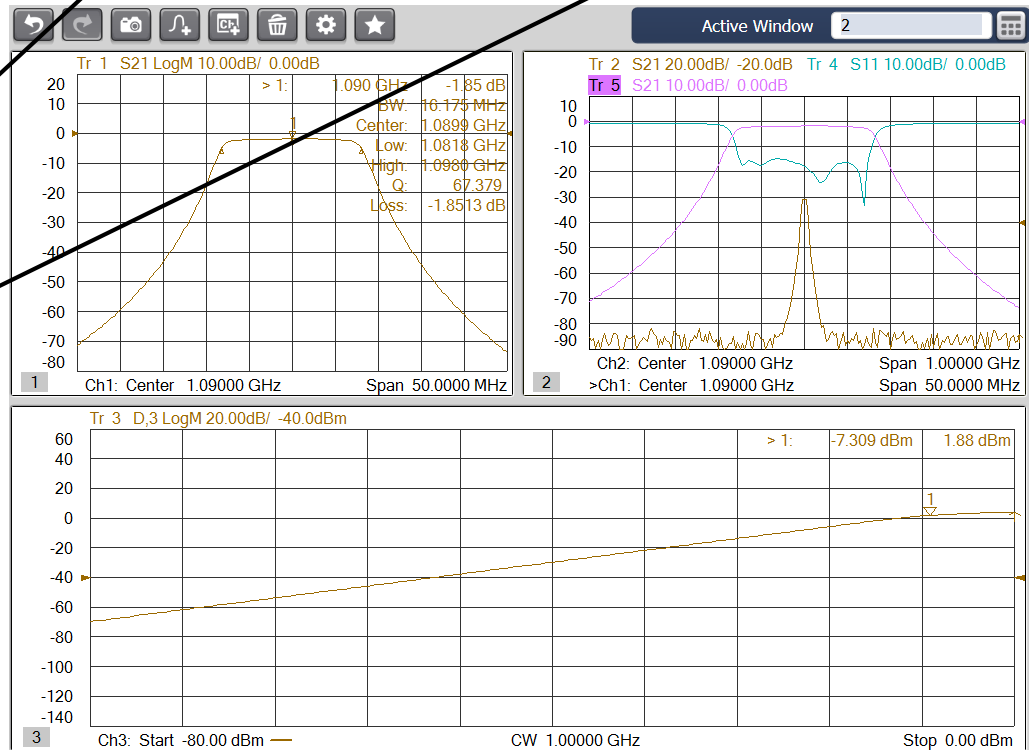
S21



Window

Window

Window



Agenda

- What measurements do we make?
- Network analyzer hardware
- **Error models and calibration**
- Additional measurements

The Need For Calibration

– Why do we have to calibrate?

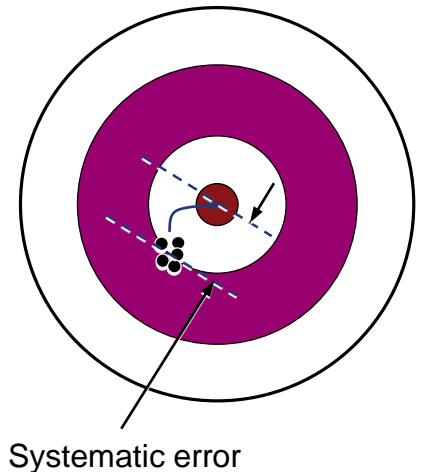
- It is impossible to make perfect hardware
- It would be extremely difficult and expensive to make hardware good enough to entirely eliminate the need for error correction

– How do we get accuracy?

- With vector-error-corrected calibration
- Not the same as the yearly instrument calibration

– What does calibration do for us?

- Removes the largest contributor to measurement uncertainty: systematic errors
- Provides best picture of true performance of DUT



Measurement Error Modeling



– *Systematic errors*

- Due to imperfections in the analyzer and test setup
- Assumed to be time invariant (predictable)
- Generally, are largest sources of error



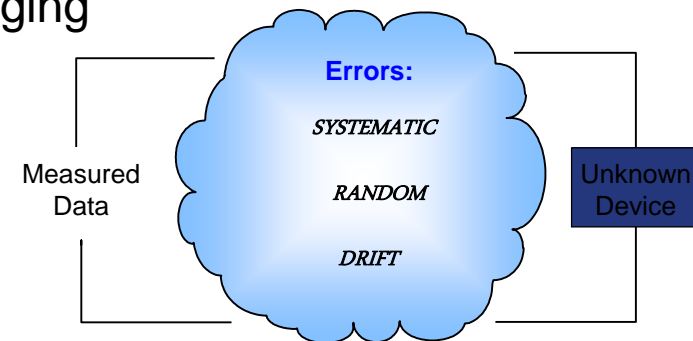
– *Random errors*

- Vary with time in random fashion (unpredictable)
- Main contributors: instrument noise, switch and connector repeatability

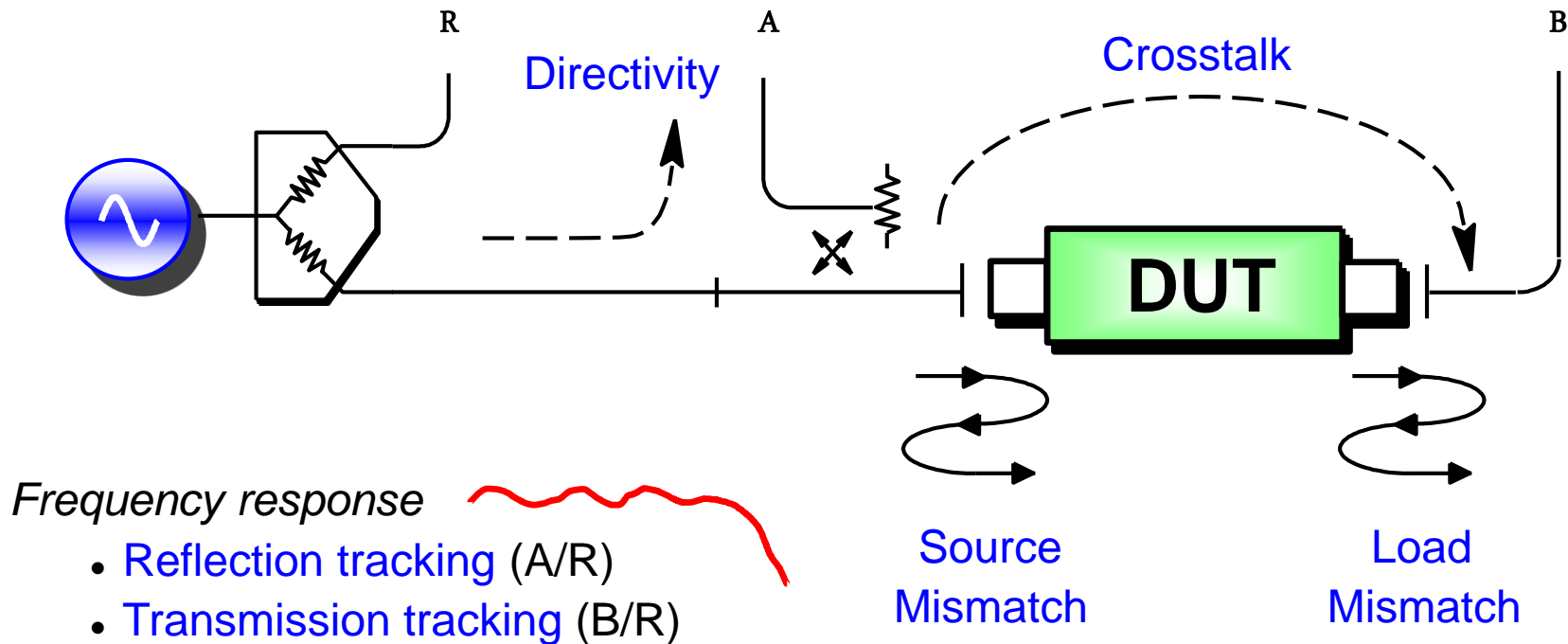


– *Drift errors*

- Due to system performance changing **after** a calibration has been done
- Primarily caused by **temperature variation**



Systematic Measurement Errors



Six forward and six reverse error terms yields 12 error terms for two-port devices

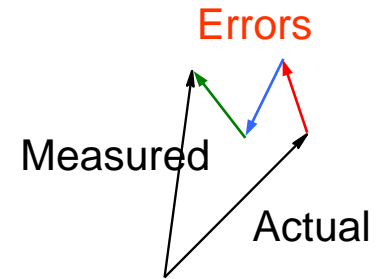
What is Vector-Error Correction?

– Vector-error correction...

- Is a process for characterizing systematic error terms
- Measures known electrical standards
- Removes effects of error terms from subsequent measurements

– Electrical standards...

- Can be mechanical or electronic
- Are often an open, short, load, and thru, but can be arbitrary impedances as well

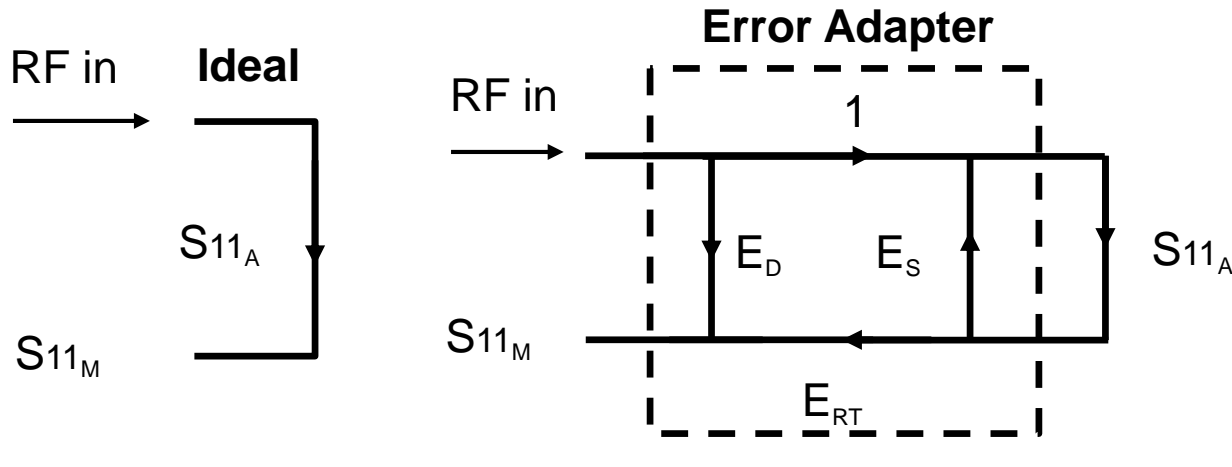


Using Known Standards to Correct for Systematic Errors

- **1-port calibration** (*reflection measurements*)
 - Only three systematic error terms measured
 - Directivity, source match, and reflection tracking
- **Full two-port calibration** (*reflection and transmission measurements*)
 - Twelve systematic error terms measured
 - Usually requires 12 measurements on four known standards (SOLT)
- **Standards defined in cal kit definition file**
 - Network analyzer contains standard cal kit definitions
 - **CAL KIT DEFINITION MUST MATCH ACTUAL CAL KIT USED!**
 - User-built standards must be characterized and entered into user cal-kit



Reflection: One-Port Model



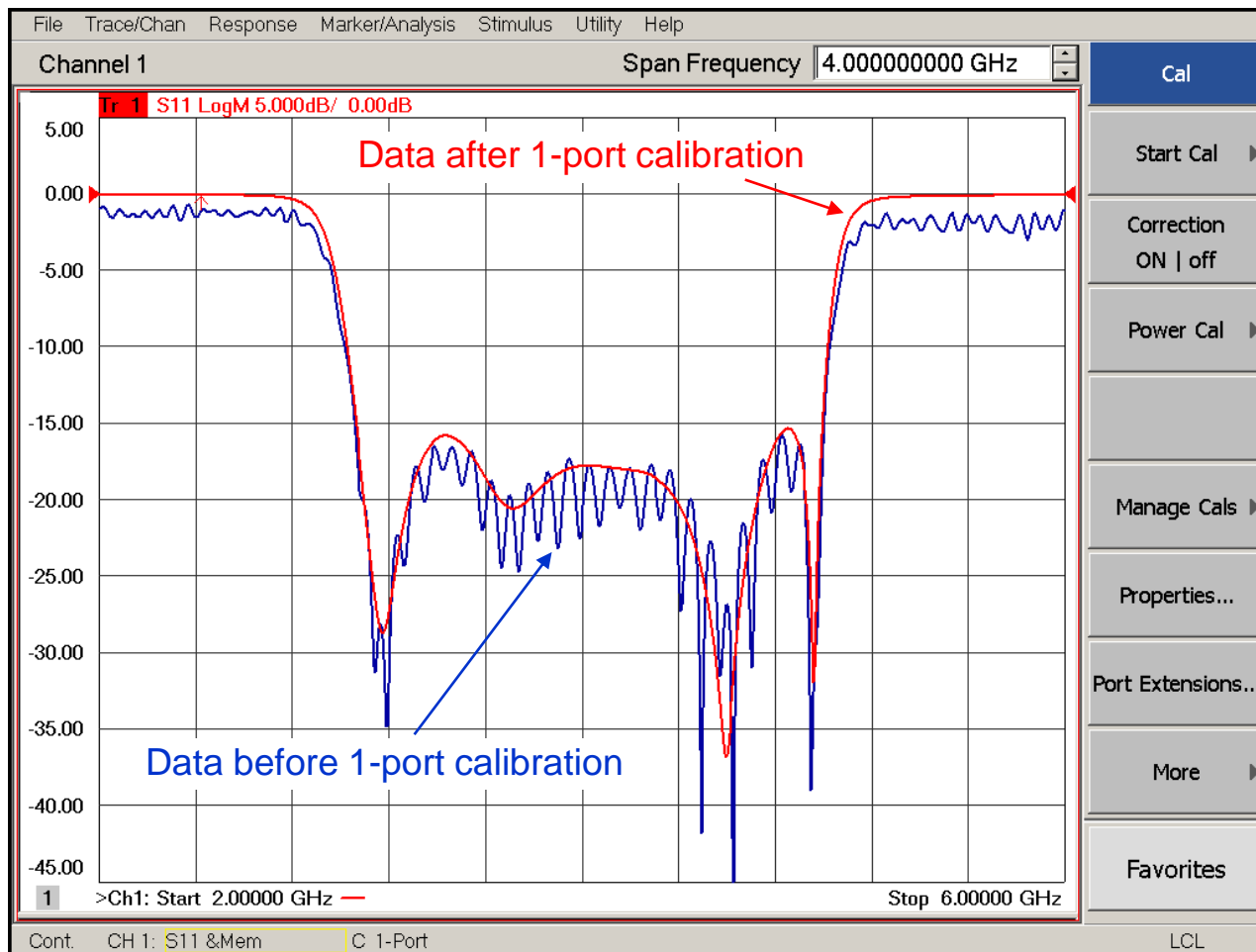
E_D = Directivity
 E_{RT} = Reflection tracking
 E_S = Source Match
 S_{11M} = Measured
 S_{11A} = Actual

To solve for error terms, we measure 3 standards to generate 3 equations and 3 unknowns

$$S_{11M} = E_D + E_{RT} \left[\frac{S_{11A}}{1 - E_S S_{11A}} \right]$$

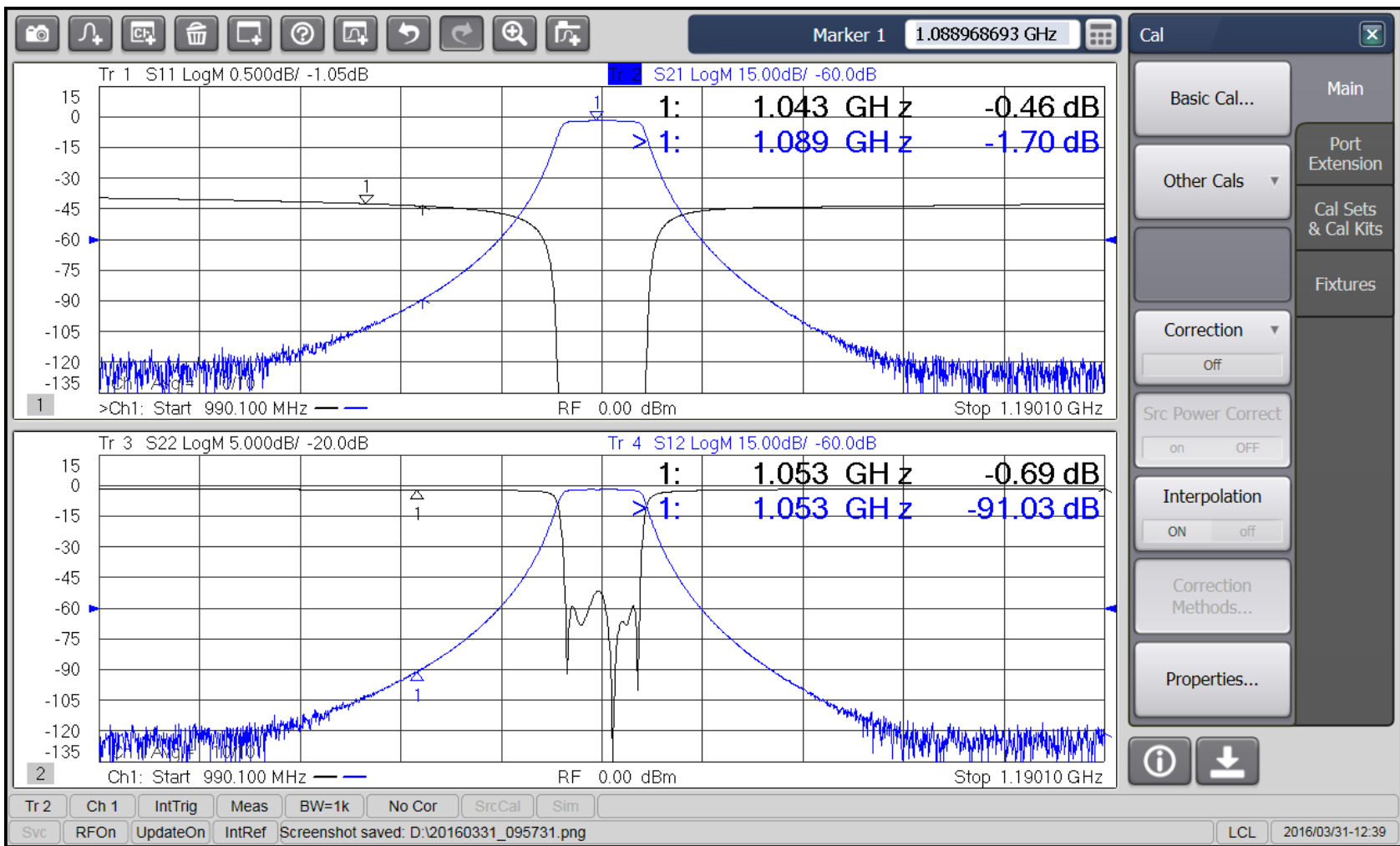
- Assumes good termination at port two if testing two-port devices
- If using port two of NA *and* DUT reverse isolation is low (e.g., filter passband):
 - Assumption of good termination is not valid
 - Two-port error correction yields better results

Before and After A One-Port Calibration



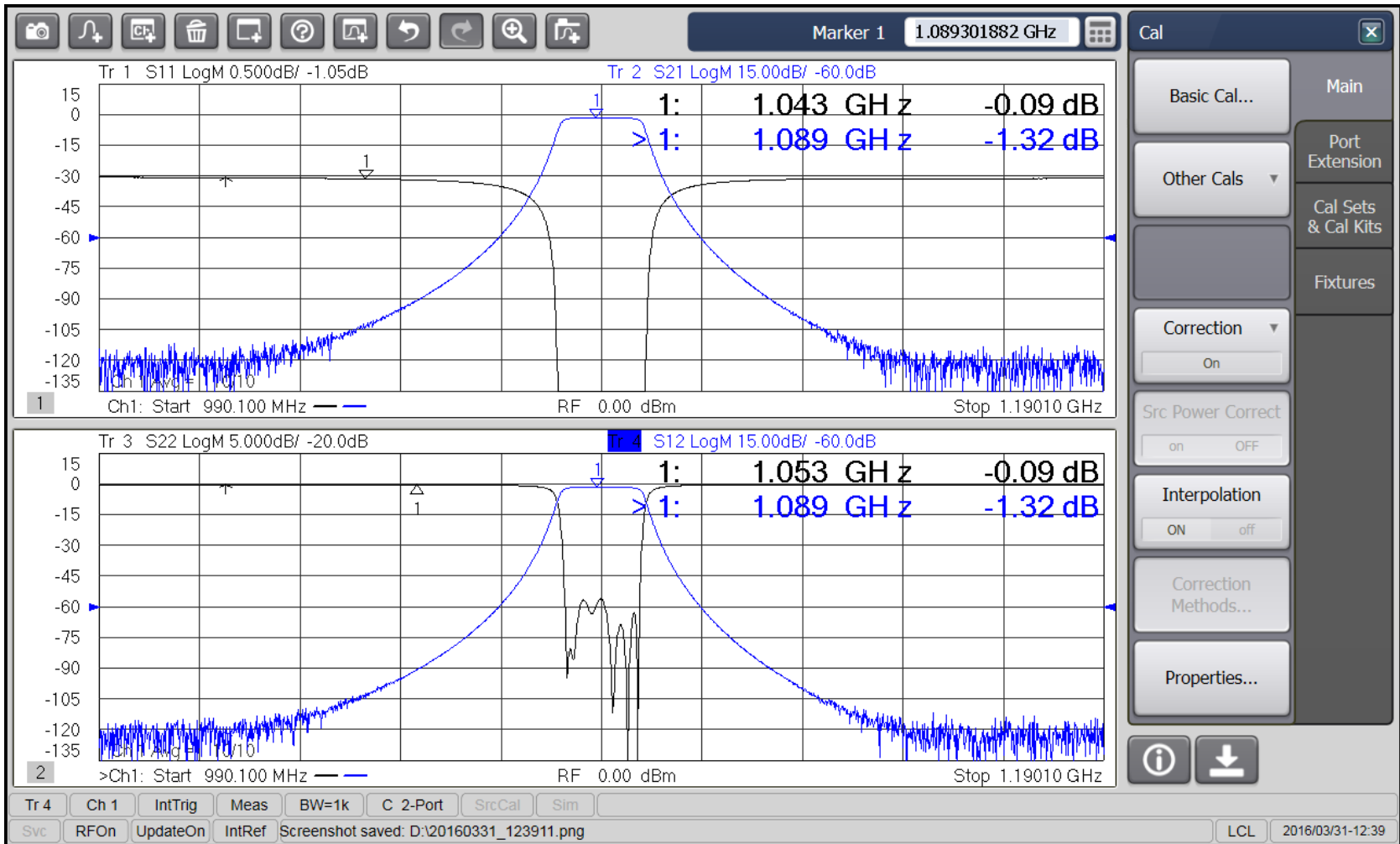
Demonstration

4 S-Parameters with Correction Off



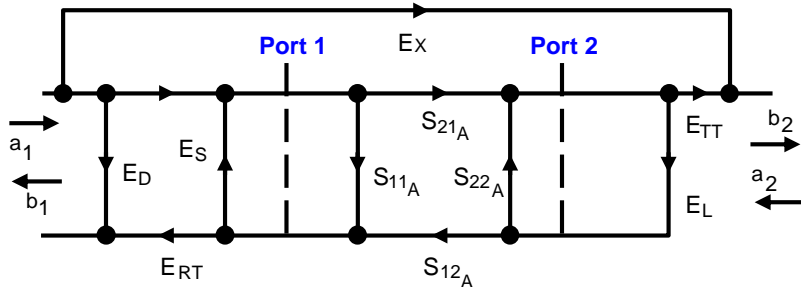
Demonstration

4 S-Parameters with Correction On



Two-Port Error Correction

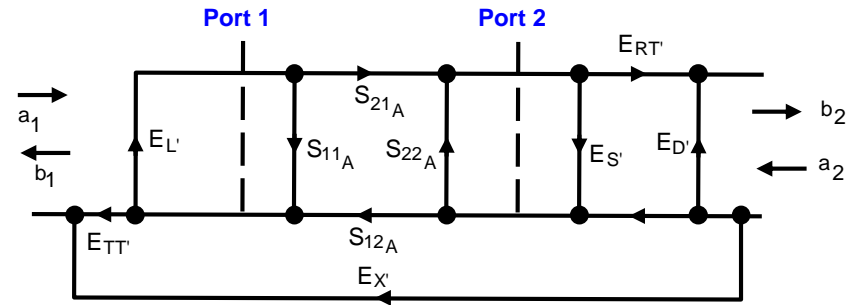
Forward model



- | | |
|-------------------------------------|---------------------------------------|
| E_D = fwd directivity | E_L = fwd load match |
| E_S = fwd source match | E_{TT} = fwd transmission tracking |
| E_{RT} = fwd reflection tracking | E_X = fwd isolation |
| $E_{D'}$ = rev directivity | $E_{L'}$ = rev load match |
| $E_{S'}$ = rev source match | $E_{TT'}$ = rev transmission tracking |
| $E_{RT'}$ = rev reflection tracking | $E_{X'}$ = rev isolation |

- Each actual S-parameter is a function of all four measured S-parameters
- Analyzer must make forward *and* reverse sweep to update any one S-parameter
- Luckily, you don't need to know these equations to **use** a network analyzers!!!

Reverse model



$$S_{11a} = \frac{\left(\frac{S_{11m} - E_D}{E_{RT}}\right)\left(1 + \frac{S_{22m} - E_{D'}}{E_{RT'}} E_{S'}\right) - E_L \left(\frac{S_{21m} - E_X}{E_{TT}}\right) \left(\frac{S_{12m} - E_{X'}}{E_{TT'}}\right)}{\left(1 + \frac{S_{11m} - E_{D'}}{E_{RT}} E_S\right)\left(1 + \frac{S_{22m} - E_{D'}}{E_{RT'}} E_{S'}\right) - E_{L'} E_L \left(\frac{S_{21m} - E_X}{E_{TT}}\right) \left(\frac{S_{12m} - E_{X'}}{E_{TT'}}\right)}$$

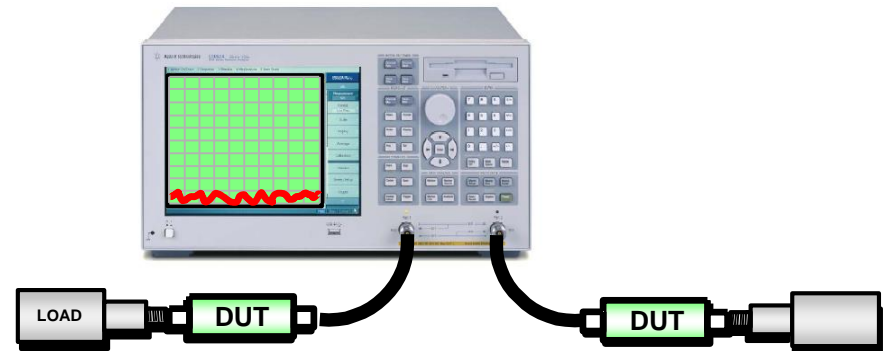
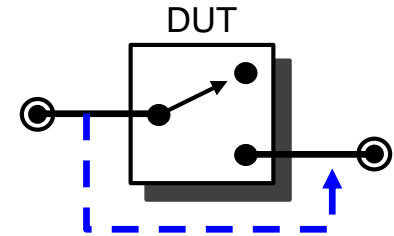
$$S_{21a} = \frac{\left(\frac{S_{21m} - E_X}{E_{TT}}\right)\left(1 + \frac{S_{22m} - E_{D'}}{E_{RT'}} (E_{S'} - E_L)\right)}{\left(1 + \frac{S_{11m} - E_D}{E_{RT}} E_S\right)\left(1 + \frac{S_{22m} - E_{D'}}{E_{RT'}} E_{S'}\right) - E_{L'} E_L \left(\frac{S_{21m} - E_X}{E_{TT}}\right) \left(\frac{S_{12m} - E_{X'}}{E_{TT'}}\right)}$$

$$S_{12a} = \frac{\left(\frac{S_{12m} - E_{X'}}{E_{TT'}}\right)\left(1 + \frac{S_{11m} - E_D}{E_{RT}} (E_S - E_{L'})\right)}{\left(1 + \frac{S_{11m} - E_D}{E_{RT}} E_S\right)\left(1 + \frac{S_{22m} - E_{D'}}{E_{RT'}} E_{S'}\right) - E_{L'} E_L \left(\frac{S_{21m} - E_X}{E_{TT}}\right) \left(\frac{S_{12m} - E_{X'}}{E_{TT'}}\right)}$$

$$S_{22a} = \frac{\left(\frac{S_{22m} - E_{D'}}{E_{RT'}}\right)\left(1 + \frac{S_{11m} - E_D}{E_{RT}} E_S\right) - E_{L'} \left(\frac{S_{21m} - E_X}{E_{TT}}\right) \left(\frac{S_{12m} - E_{X'}}{E_{TT'}}\right)}{\left(1 + \frac{S_{11m} - E_D}{E_{RT}} E_S\right)\left(1 + \frac{S_{22m} - E_{D'}}{E_{RT'}} E_{S'}\right) - E_{L'} E_L \left(\frac{S_{21m} - E_X}{E_{TT}}\right) \left(\frac{S_{12m} - E_{X'}}{E_{TT'}}\right)}$$

Crosstalk: Signal Leakage Between Test Ports During Transmission

- Can be a problem with:
 - High-isolation devices (e.g., switch in open position)
 - High-dynamic range devices (some filter stopbands)
- Isolation calibration
 - Adds noise to error model (measuring near noise floor of system)
 - Only perform if really needed (use averaging if necessary)
 - If crosstalk is **independent** of DUT match, use two terminations
 - If **dependent** on DUT match, use two DUTs with termination on output



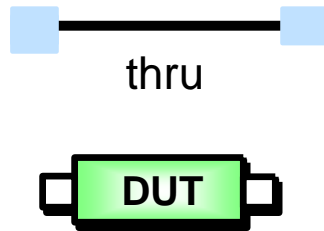
Errors and Calibration Standards

UNCORRECTED FULL 2-PORT



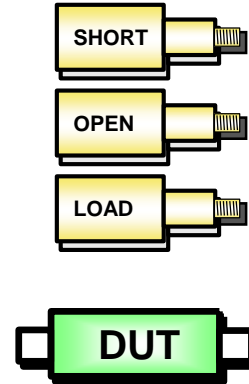
- Convenient
- Generally not accurate
- No errors removed

RESPONSE

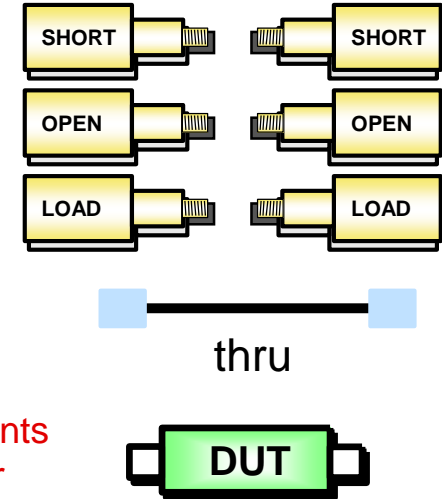


- Easy to perform
- Use when highest accuracy is not required
- Removes frequency response error

1-PORT



- For reflection measurements
- Need good termination for high accuracy with two-port devices
- Removes these errors:
 - Directivity
 - Source match
 - Reflection tracking



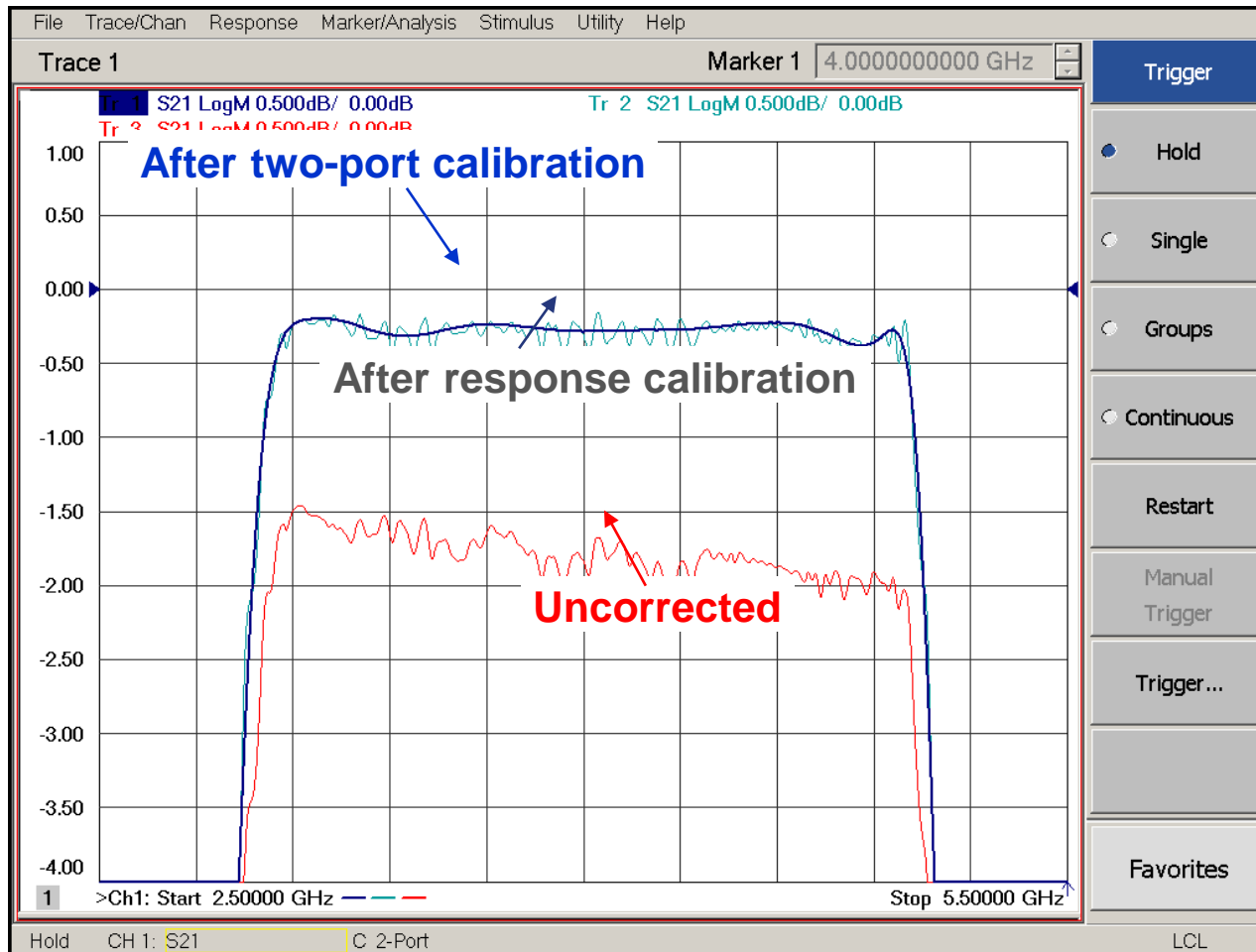
- Highest accuracy
- Removes these errors:
 - Directivity
 - Source, load match
 - Reflection tracking
 - Transmission tracking
 - Crosstalk

ENHANCED-RESPONSE

- Combines response and 1-port
- Corrects source match for transmission measurements

Response versus Two-Port Calibration

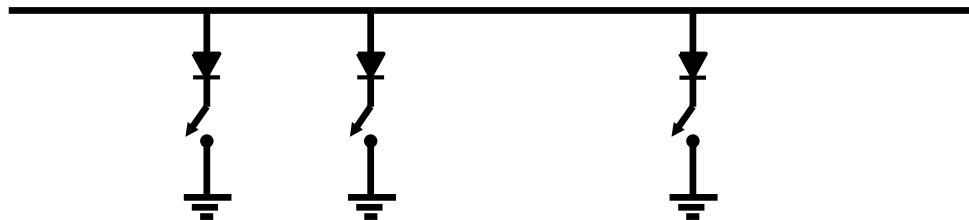
Measuring filter insertion loss



ECal: Electronic Calibration

- Variety of two- and four-port modules cover 300 kHz to 67 GHz
- Nine connector types available, 50 and 75 ohms
- Single-connection calibration
 - dramatically reduces calibration time
 - makes calibrations easy to perform
 - minimizes wear on cables and standards
 - eliminates operator errors
- Highly repeatable temperature-compensated characterized terminations provide excellent accuracy

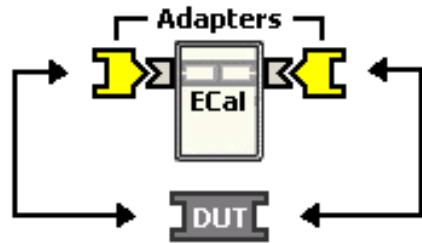
USB controlled



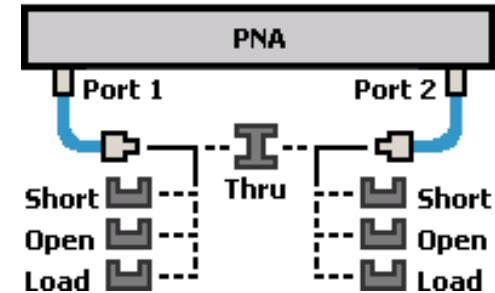
Microwave modules use a transmission line shunted by PIN-diode switches in various combinations

ECal User Characterizations

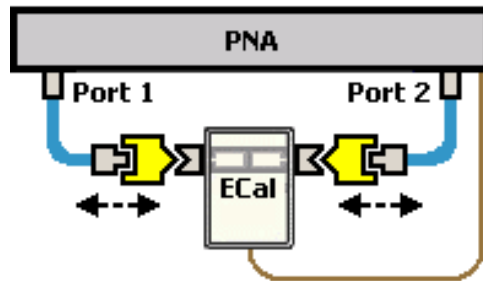
1. Select adapters for the module to match the connector configuration of the DUT.



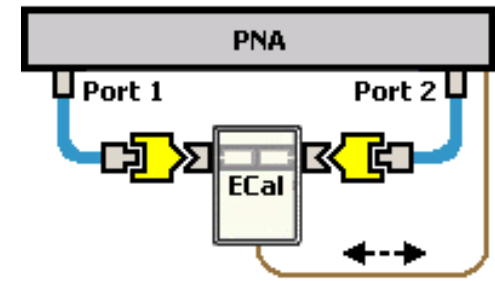
2. Perform a calibration using appropriate mechanical standards.



3. Measure the ECal module, including adapters, as though it were a DUT



4. VNA stores resulting characterization data inside the module.



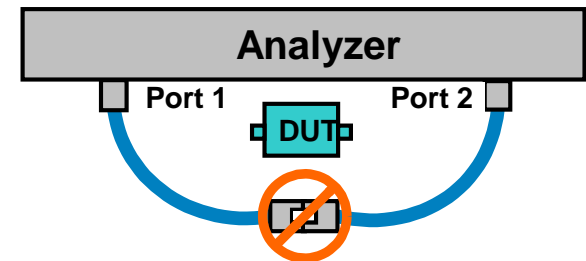
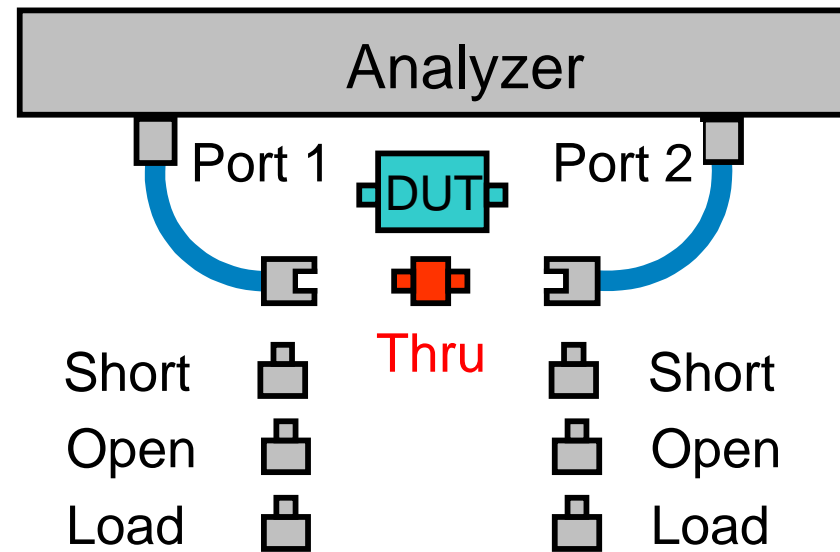
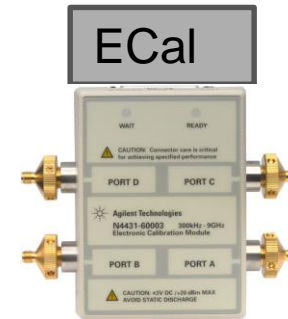
Unknown Thru Calibration Requirements

- 1) The systematic errors, directivity, source match and reflection tracking, of each test port can be completely characterized.
- 2) The “unknown thru” must be reciprocal, $S_{ij} = S_{ji}$.
- 3) The phase response of the “unknown thru” must be known to within a quarter of a wavelength.
- 4) VNA signal path switch errors can be quantified.

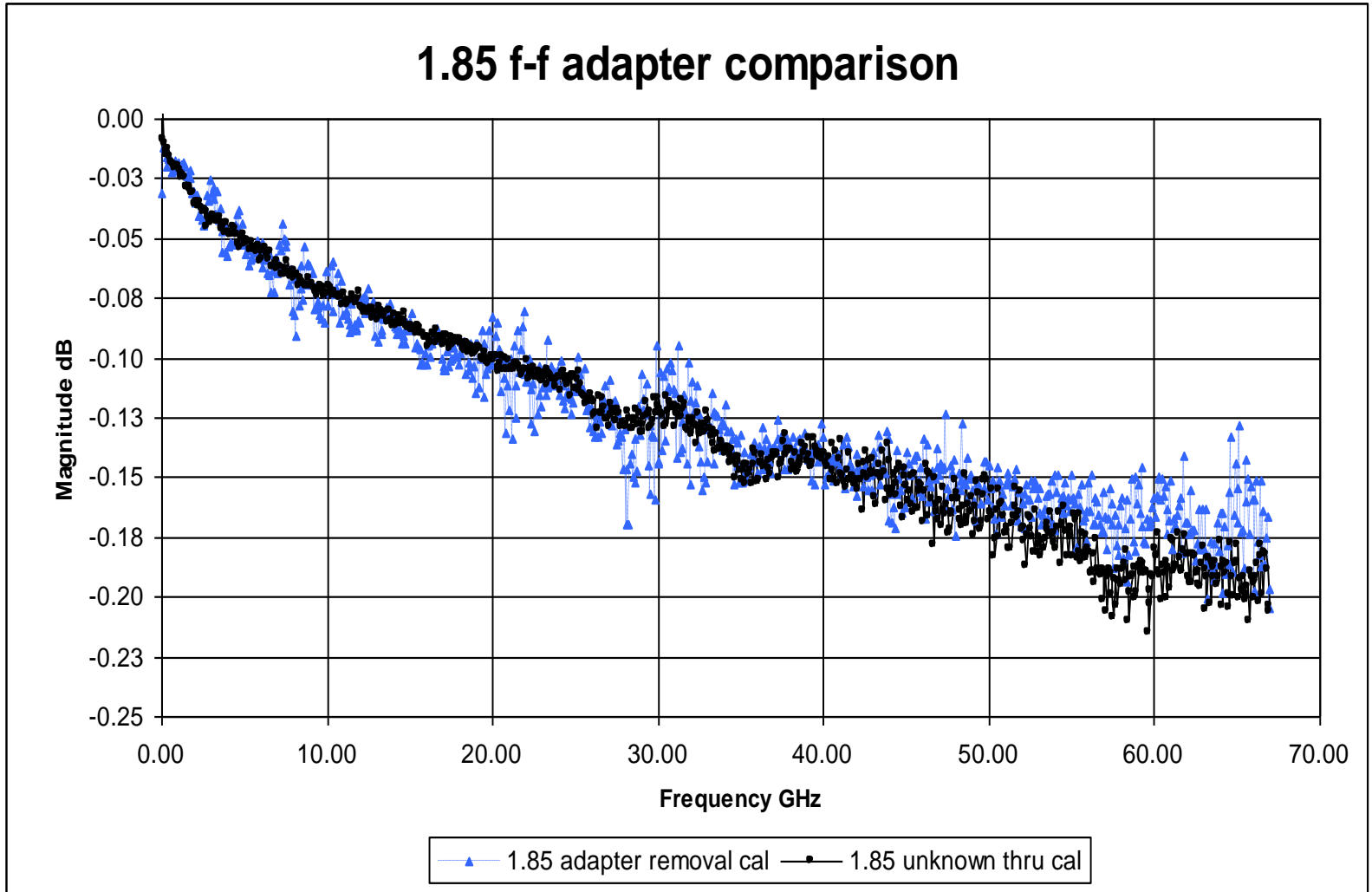
Unknown-Thru Calibration

Cal Methods are listed in order of ascending accuracy (most accurate first):

- ECal with Unknown Thru
- Adapter Removal
- Mechanical with Unknown Thru Cal
- Electronic Calibrator (ECal)
- Uncharacterized Thru Adapter

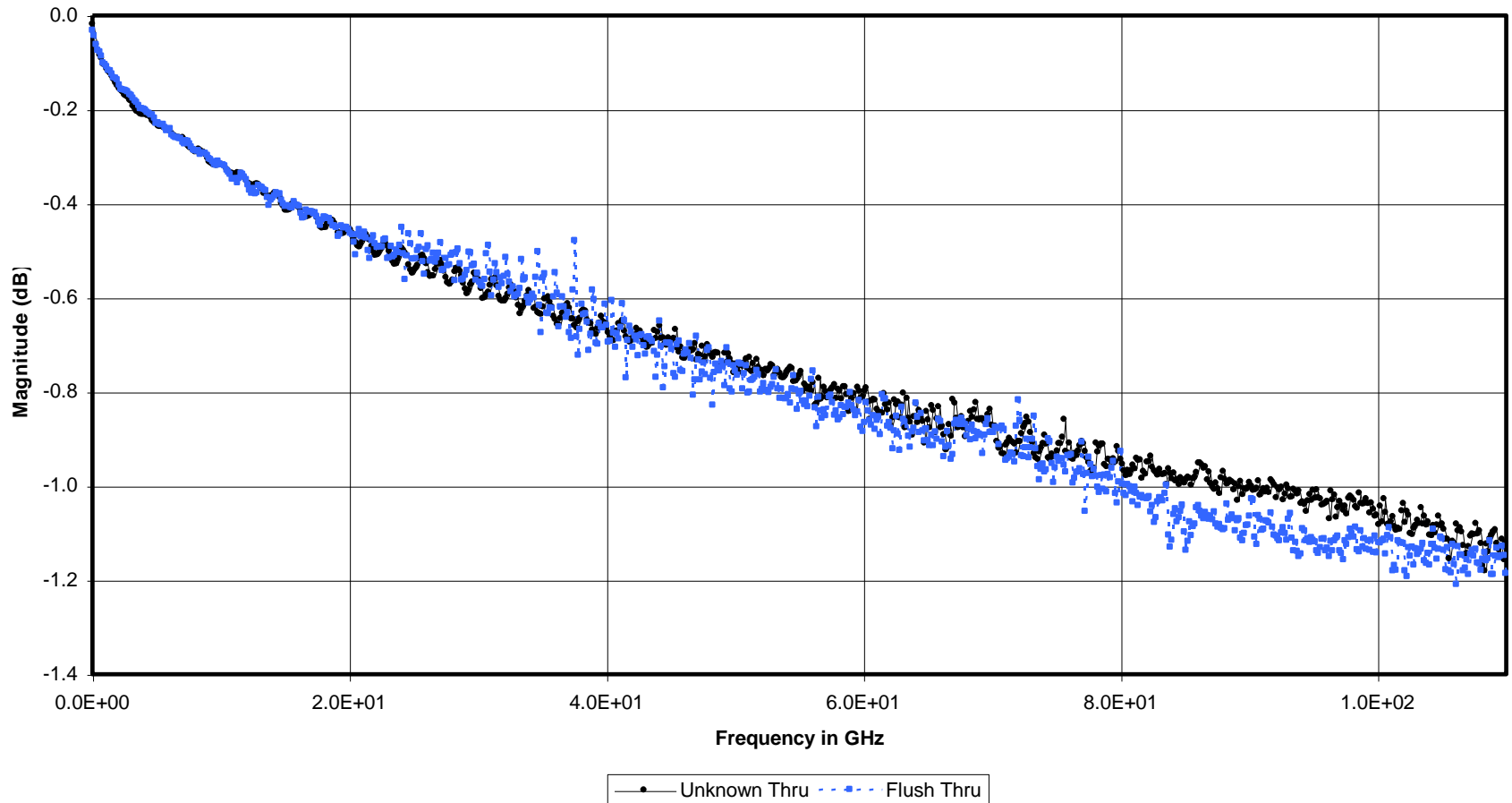


Unknown Thru and Adapter Removal Compared (PNA)



Unknown Thru and Flush Thru Compared (PNA)

Long (Aspect Ratio) Device, 3.5 inch x 1 mm cable, Test Comparison

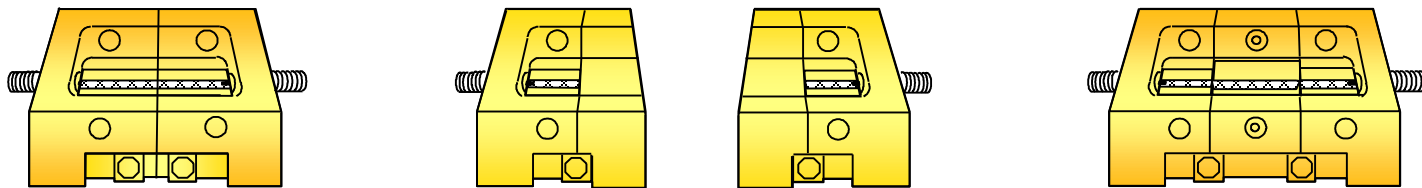


Thru-Reflect-Line (TRL) Calibration

We know about Short-Open-Load-Thru (SOLT) calibration... What is TRL?

- A two-port calibration technique
- Good for non-coaxial environments (waveguide, fixtures, wafer probing)
- Characterizes same 12 systematic errors as the more common SOLT cal
- Uses practical calibration standards that are easily fabricated and characterized
- Other variations: Line-Reflect-Match (LRM), Thru-Reflect-Match (TRM), plus many others

TRL was developed for **non-coaxial microwave** measurements



Agenda

- What measurements do we make?
- Network analyzer hardware
- Error models and calibration
- **Additional measurements**

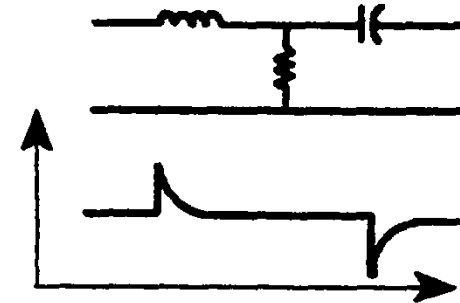
Additional measurements

- Time domain analysis
- Gain compression
- Three and four ports S-parameter measurement
- Mixed-mode S-parameter measurement

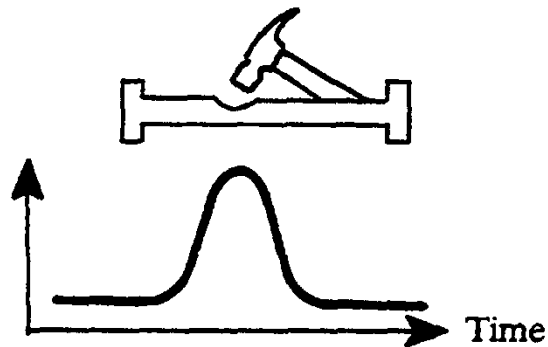
Why the Time Domain?

With the time domain information we can:

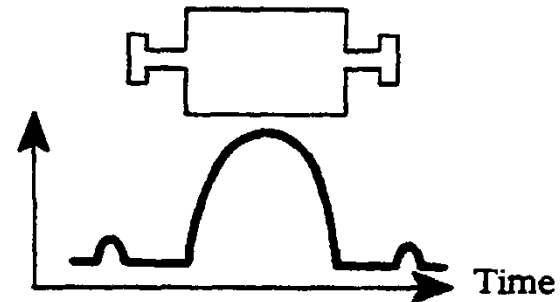
Identify Circuit Elements



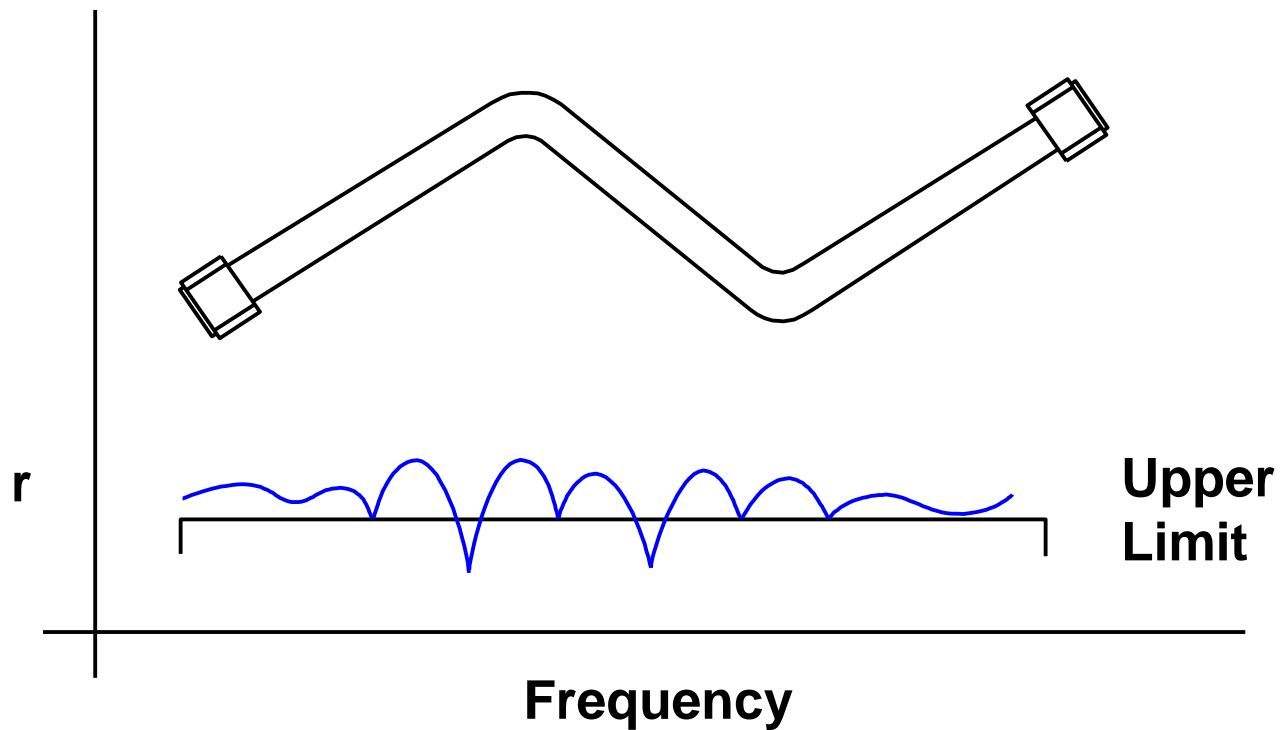
Locate Faults



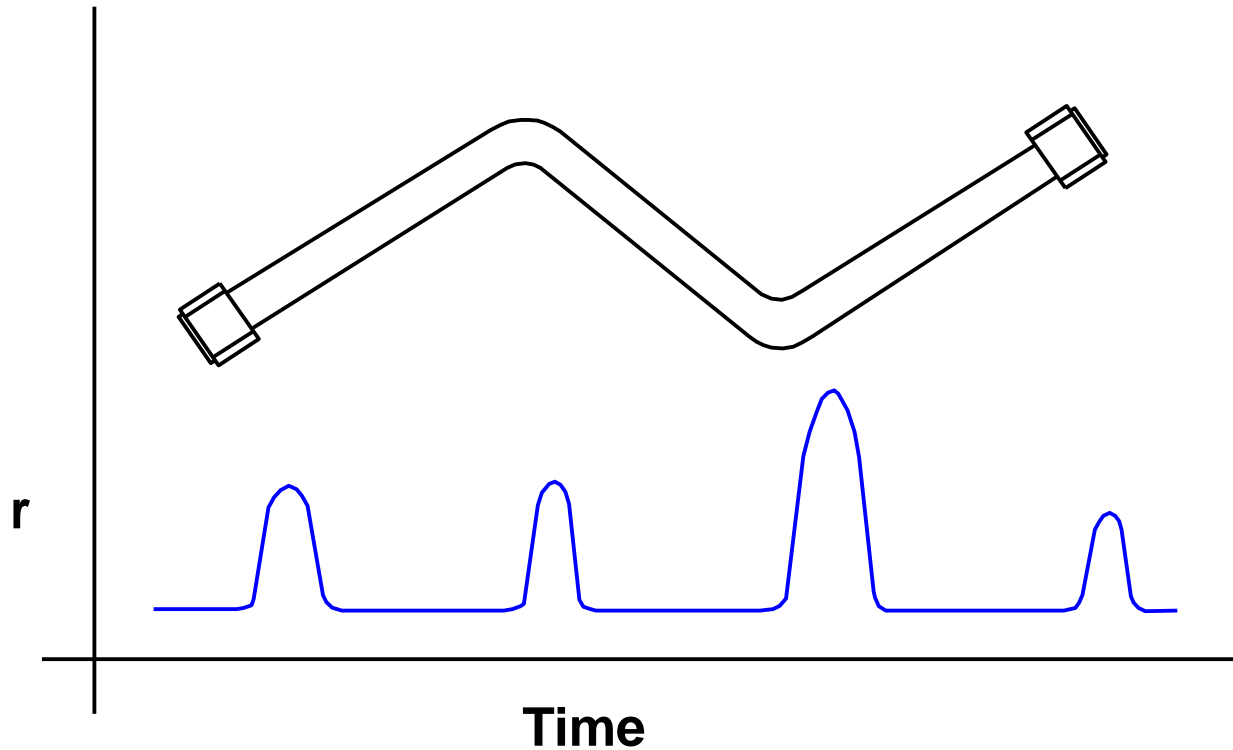
Identify and Remove Unwanted Responses



Frequency Domain S_{11} Response of Semi-rigid Coax Cable



Time Domain S_{11} Response of Semi-rigid Coax Cable



To Increase Alias Free Range

- Increase the number of points
- Decrease frequency span

$$\bullet \text{ AFR} = (\text{Number Points} - 1) / \text{Span}$$

Range Resolution

- The ability to locate a single response in time

$$\bullet \text{ Range Resolution} = \frac{\text{Time Span}}{\text{Points} - 1}$$

Range Calculation Example

$$\text{Range (s)} = \frac{1}{\Delta f} = \frac{\text{Points} - 1}{f_{\text{SPAN}}} \quad \Delta f, f_{\text{SPAN}} = \text{Hz}$$

$$= \frac{400}{2.5 \text{ GHz}}$$

$$= 160 \text{ ns}$$

$$\text{Range (m)} = \frac{\text{Points} - 1}{f_{\text{SPAN}}} * 2.9979 \times 10^8 \text{ m}$$

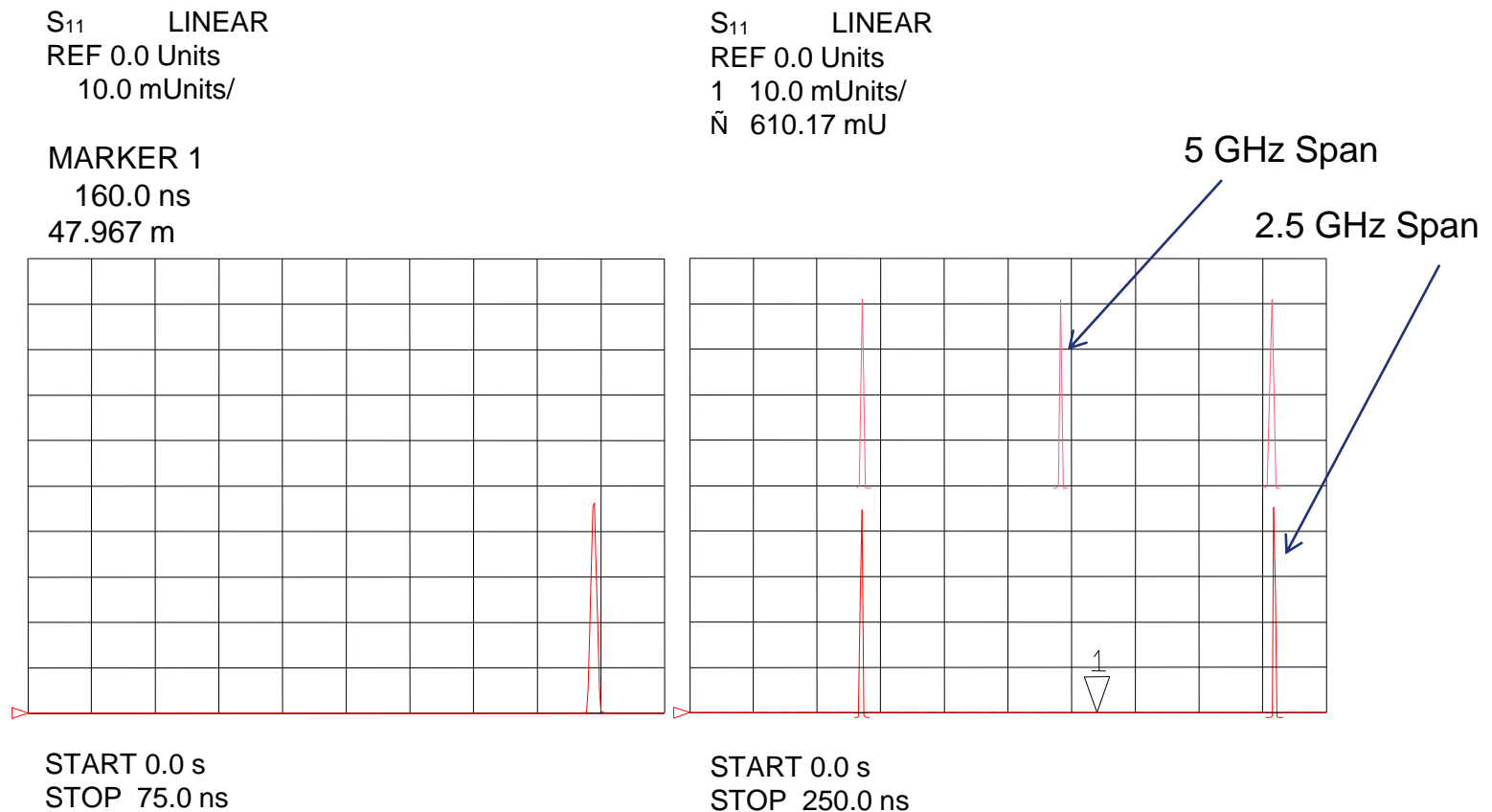
$$= \frac{400}{2.5 \text{ GHz}} * 2.9979 \times 10^8$$

$$= 48 \text{ m}$$

Fault Location Range Example: 10m cable

Effects of Changing Frequency Span

Band Pass Mode, 401 Points, Span changed from 5.0 GHz to 2.5 GHz
GHz Range = 160 ns (48 m)

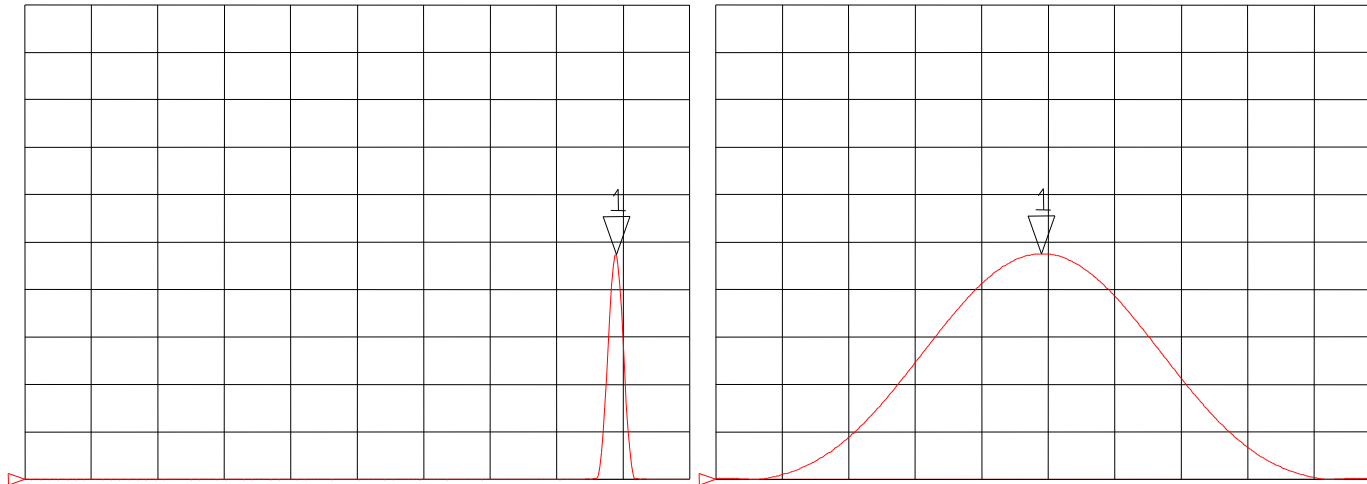


Range Resolution Example - narrow time span

S₁₁ LINEAR
REF 0.0 Units
D 10.0 mUnits/
1 47.571 mU

S₁₁ LINEAR
REF 47.62 Units
1 5.0 mUnits/
Ñ 47.621 mU

MARKER 1
13.3425 ns
4.0 m



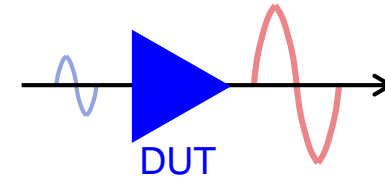
START 0.0 s
STOP 15.0 ns

CENTER 13.3425 ns
SPAN 384.0 ps

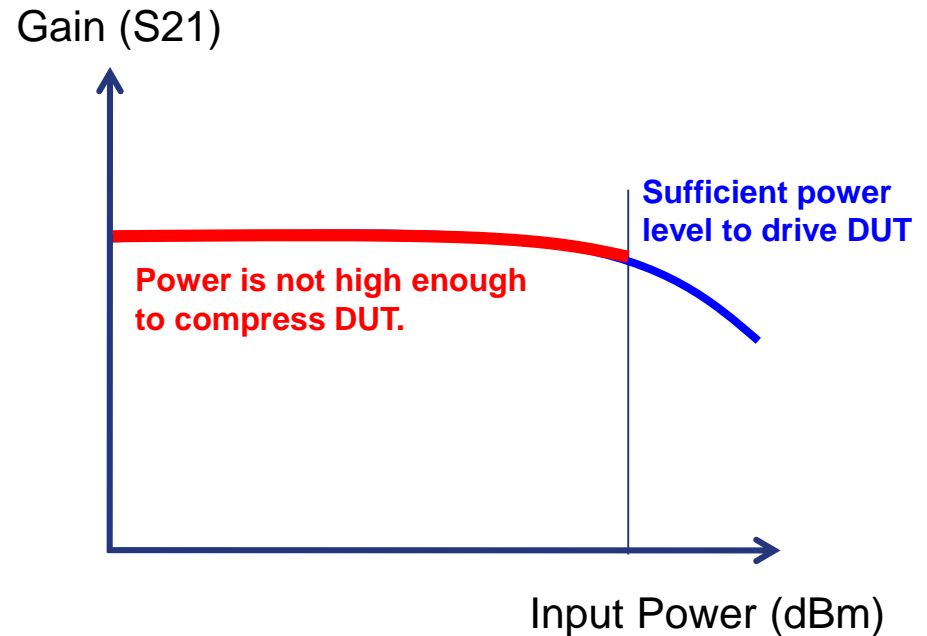
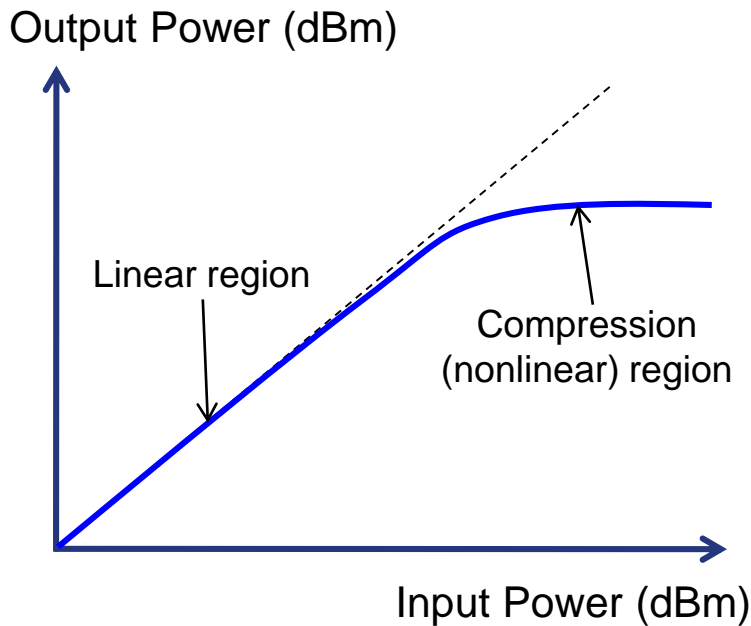
Additional measurements

- Time domain analysis
- Gain compression
- Three and four ports S-parameter measurement
- Mixed-mode S-parameter measurement

What is gain compression?

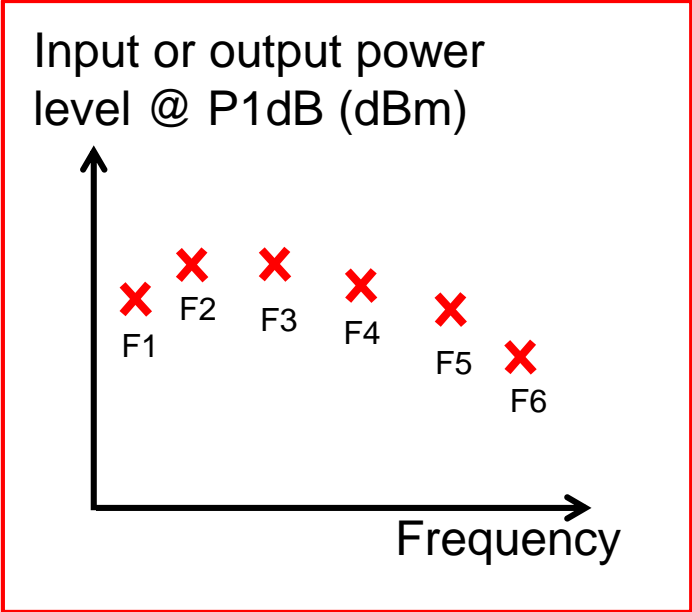
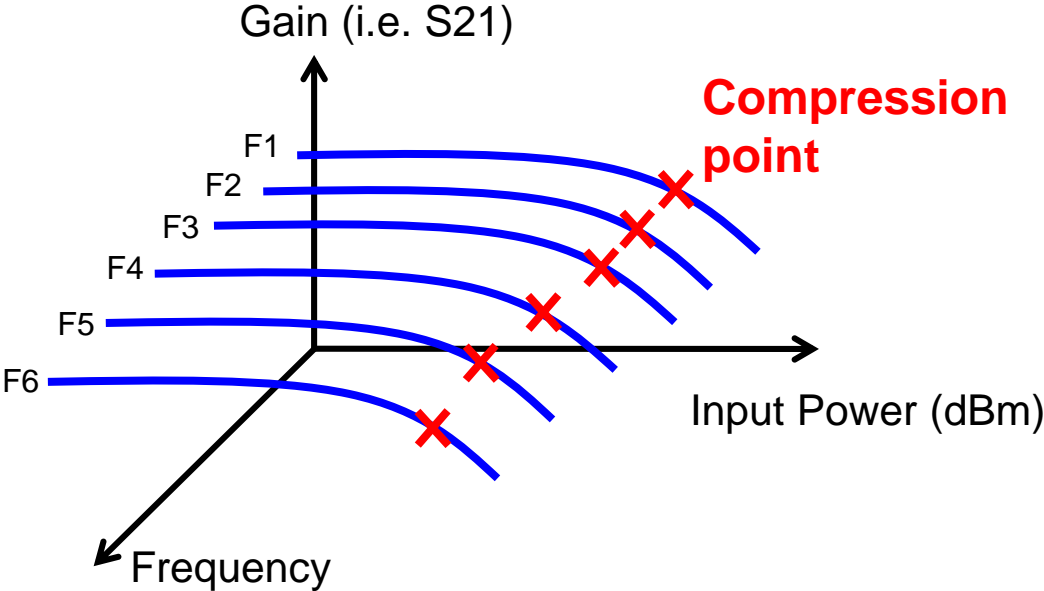


- Parameter to define the transition between the linear and nonlinear region of an active device.
- The compression point is observed as x dB drop in the gain with VNA's power sweep.



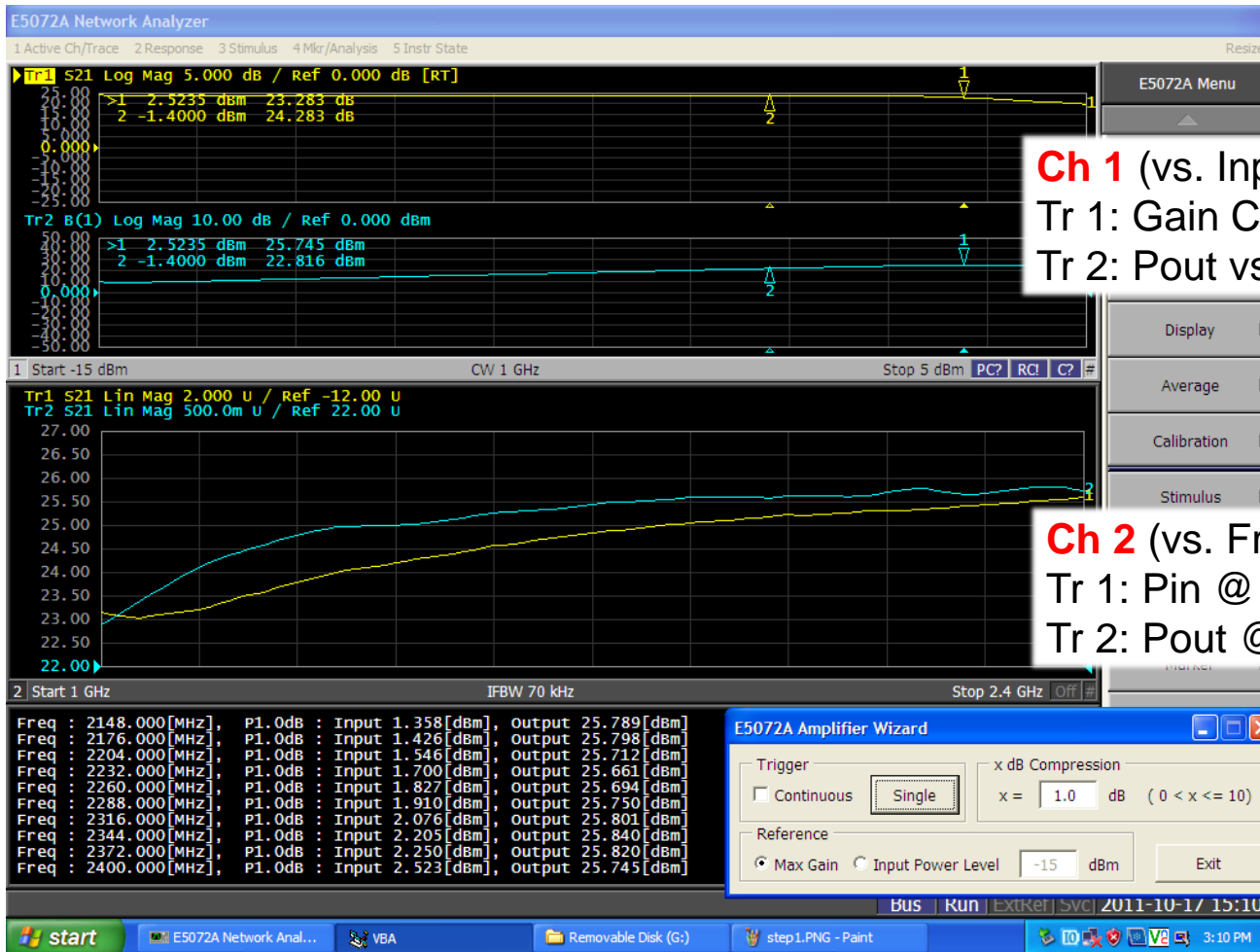
Enough margin of source power capability is needed for analyzers.

Gain compression over frequency



Gain compression over frequency

Gain compression measurement example



Ch 1 (vs. Input power):
 Tr 1: Gain Compression vs. Pin
 Tr 2: Pout vs. Pin

Ch 2 (vs. Frequency):
 Tr 1: Pin @ P1dB vs. Freq
 Tr 2: Pout @ P1dB vs. Freq

RF amplifier test

Stability (K-factor)

Calculates stability (K-factor) from all S-parameters with equation editor

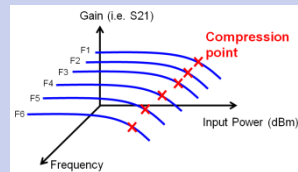
$$K = \frac{1 - |S_{11}|^2 - |S_{22}|^2 + |\Delta|^2}{2|S_{12}S_{21}|}$$

where

$$\Delta = S_{11}S_{22} - S_{12}S_{21}$$

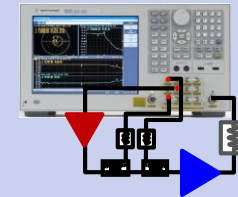
Gain compression

Sweeps both frequency and input power level at P_{1dB}



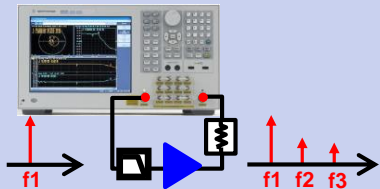
High-power test

Performs accurate tests with high-power input / output of DUT



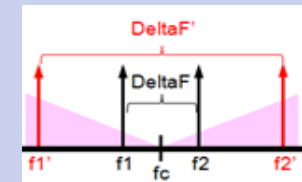
Harmonic Distortion

Performs real-time harmonics test over frequency or input power



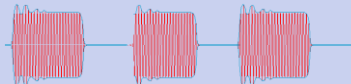
Swept IMD

Performs IMD analysis over an entire range of frequencies



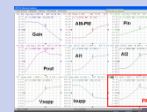
Pulsed-RF

Characterize pulsed performance of devices



Efficiency (PAE)

Calculate power-added efficiency (PAE)



The modern VNA is a more suited solution for many parametric tests of RF amplifiers.

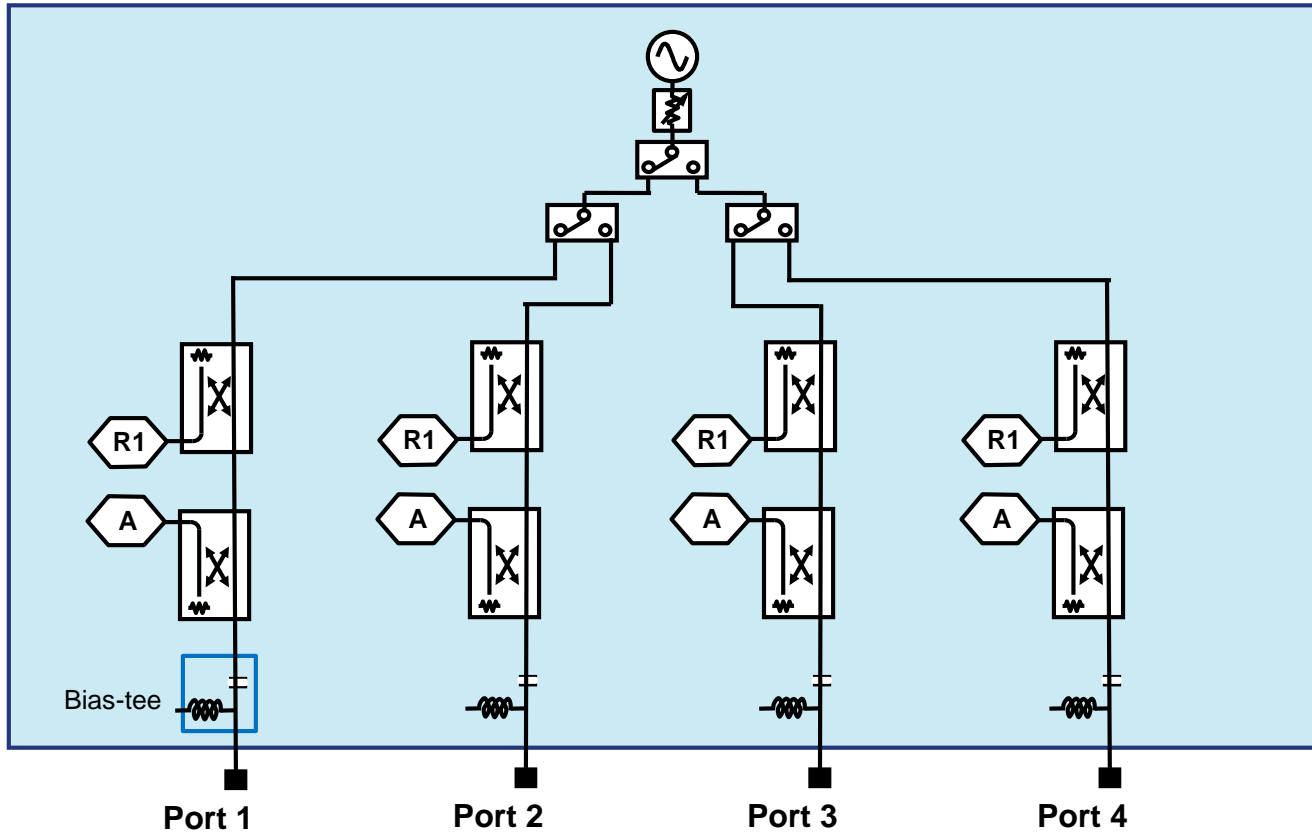
Additional measurements

- Time domain analysis
- Gain compression
- Three and four ports S-parameter measurement
- Mixed-mode S-parameter measurement

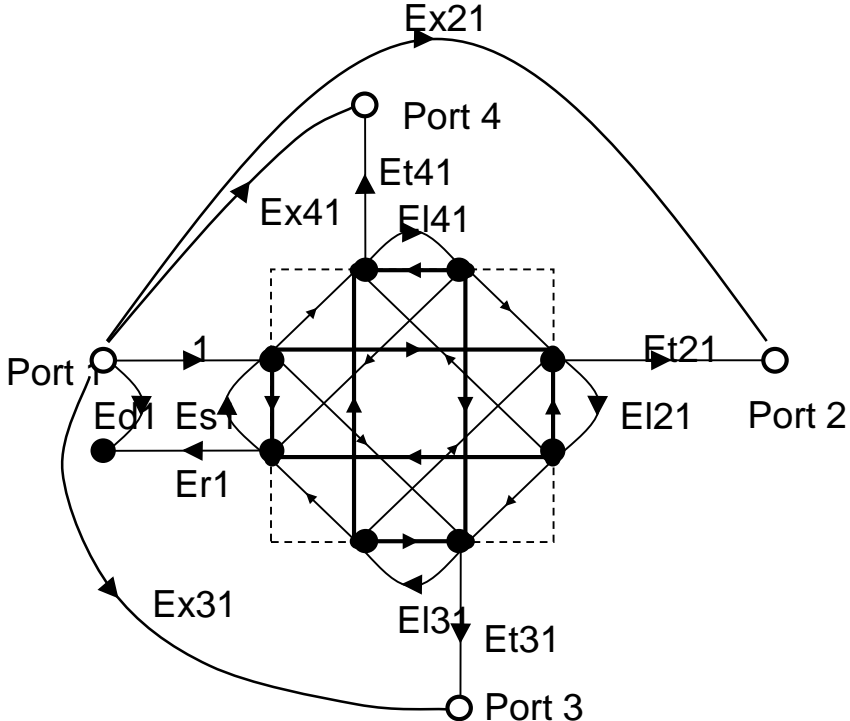
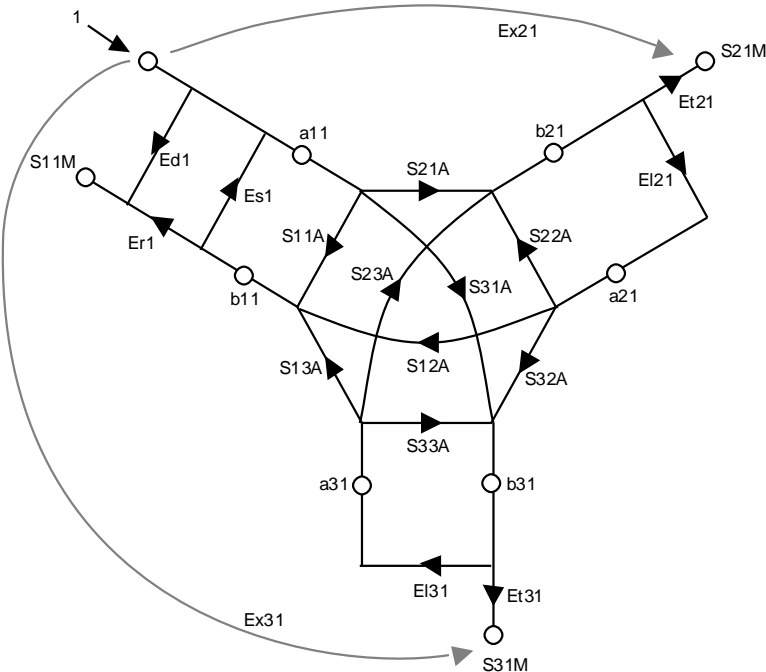
NA
Fundament
al

93

4-port VNA Block Diagram (E5080A)



Full 3 and 4-Port Error Correction



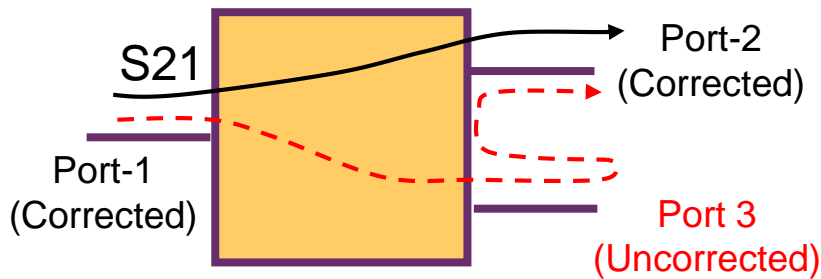
Total number of Error Terms:
 $3N + 3N \cdot (N - 1) = 3N^2$

- 2-port Error Terms : $3 \cdot 2^2 = 12$
- 3-port Error Terms : $3 \cdot 3^2 = 27$
- 4-port Error Terms : $3 \cdot 4^2 = 48$

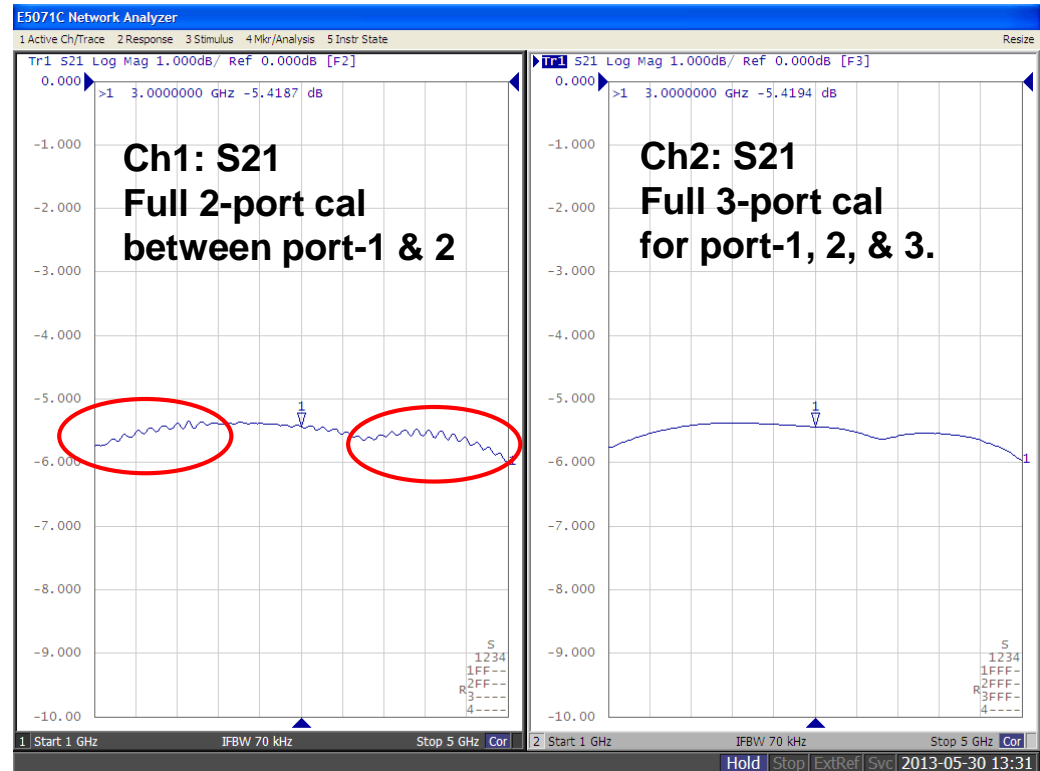
When full 3 and 4-port cal required?

- Reflection from uncorrected test port affects measurement.
- Measure mixed-mode S-parameters

Ex) 2-way power divider (isolation between output ports=13 dB)



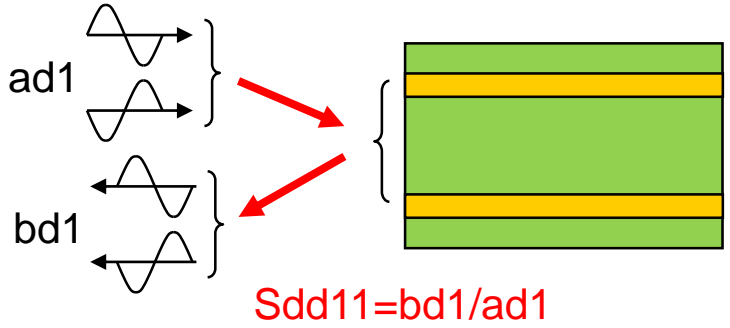
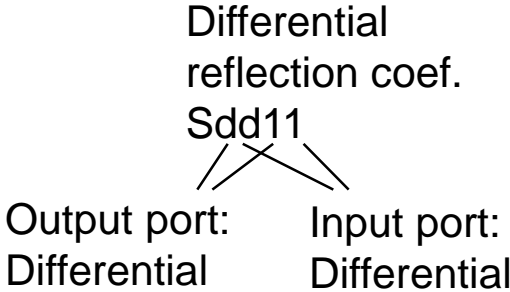
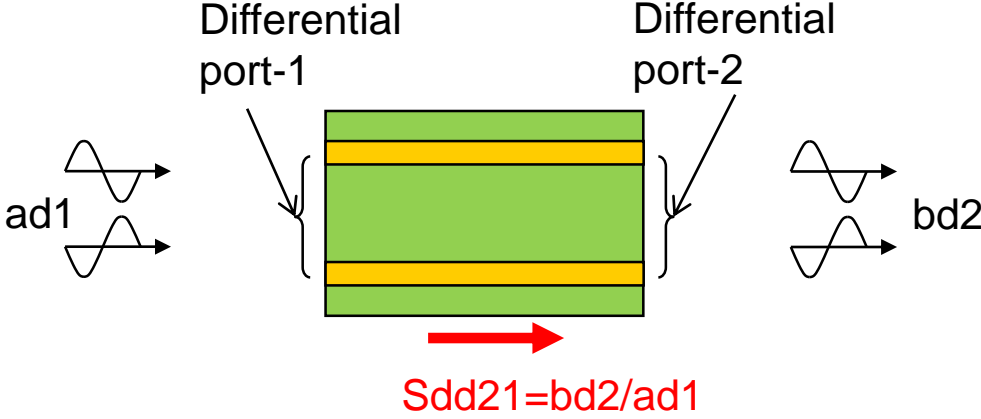
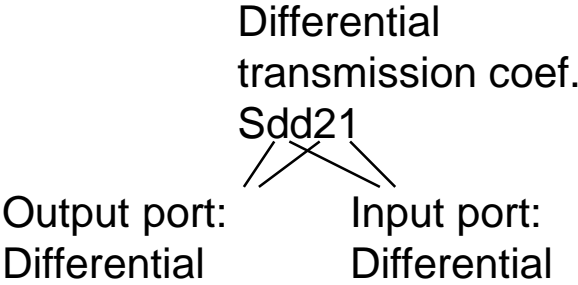
Reflection at uncorrected port-3 affect measurement at port-2.



Additional measurements

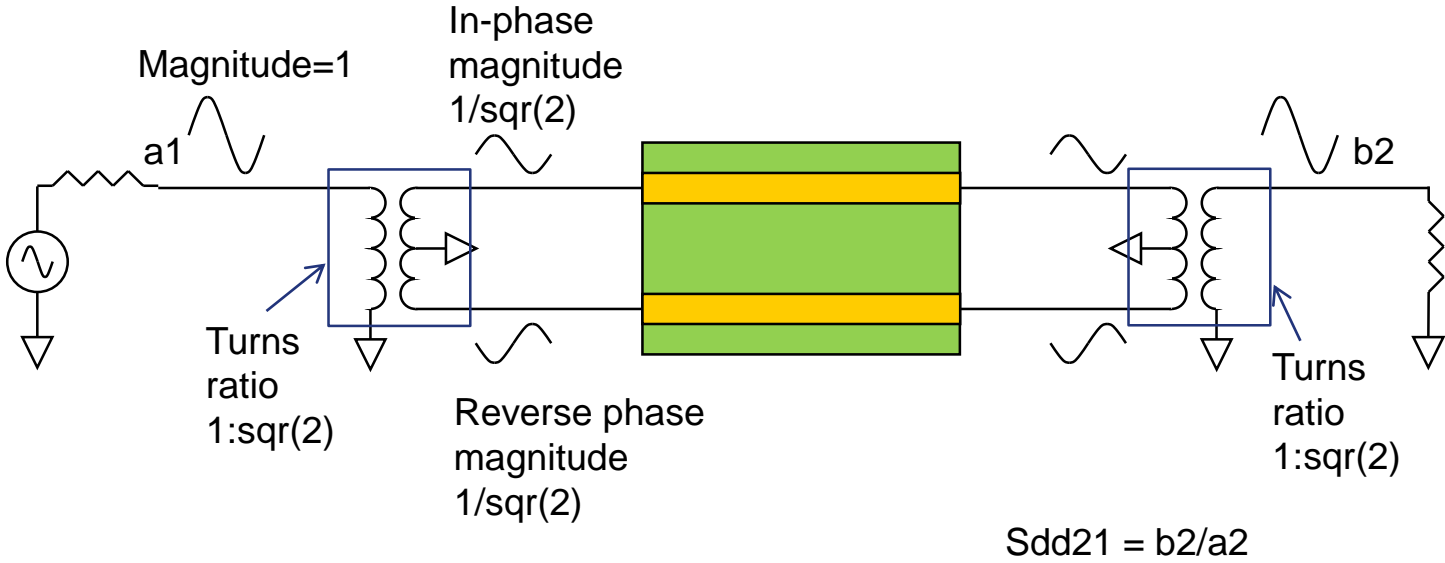
- Time domain analysis
- Gain compression
- Three and four ports S-parameter measurement
- Mixed-mode S-parameter measurement

Differential S-parameter measurement

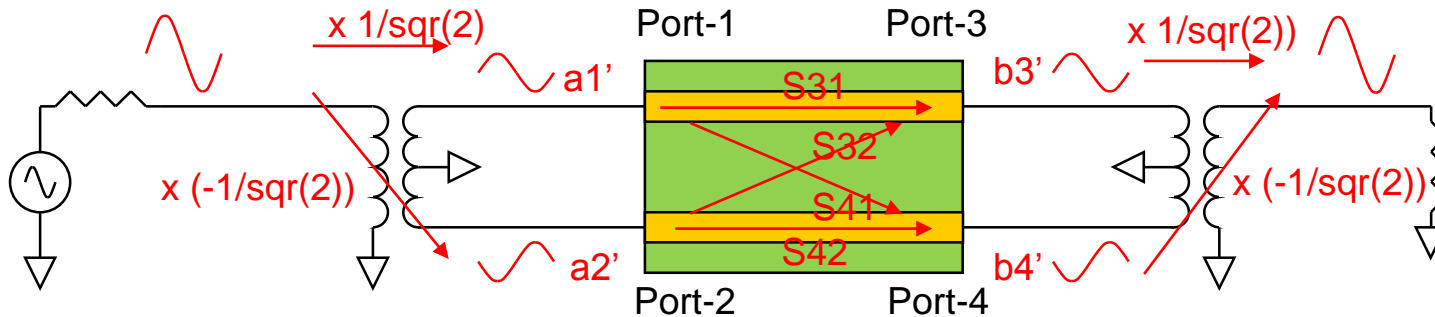


Differential S-parameter measurement

Sdd21 measurement using ideal balun transformers



Differential S-parameter measurement



We consider transmission characteristic of four signal paths;

$$S_{31} \text{ path: } (1/\sqrt{2}) \times S_{31} \times (1/\sqrt{2}) = (1/2) \times S_{31}$$

$$S_{41} \text{ path: } (1/\sqrt{2}) \times S_{41} \times (-1/\sqrt{2}) = (-1/2) \times S_{41}$$

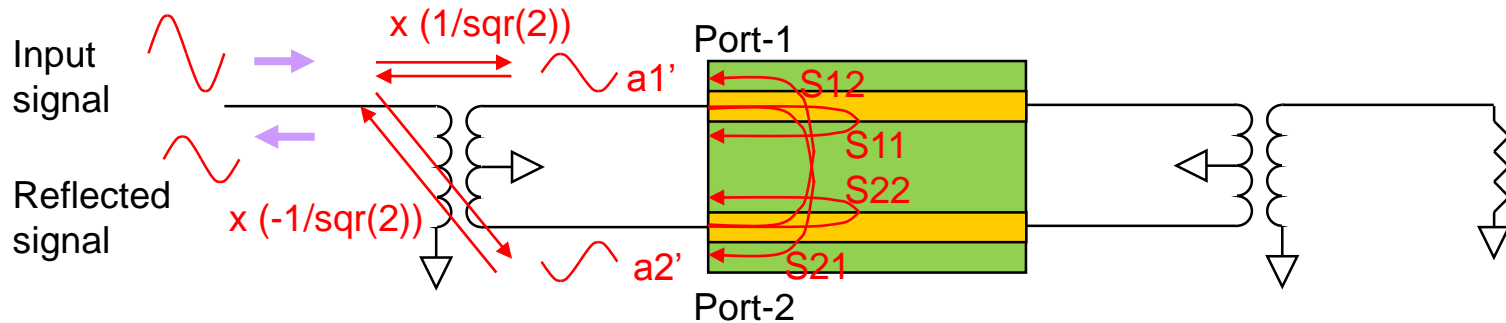
$$S_{32} \text{ path: } (-1/\sqrt{2}) \times S_{32} \times (1/\sqrt{2}) = (-1/2) \times S_{32}$$

$$S_{42} \text{ path: } (-1/\sqrt{2}) \times S_{42} \times (-1/\sqrt{2}) = (1/2) \times S_{42}$$

By superimposing above four equations, we can obtain Sdd21;

$$S_{dd21} = (1/2) \times (S_{31} - S_{32} - S_{41} + S_{42})$$

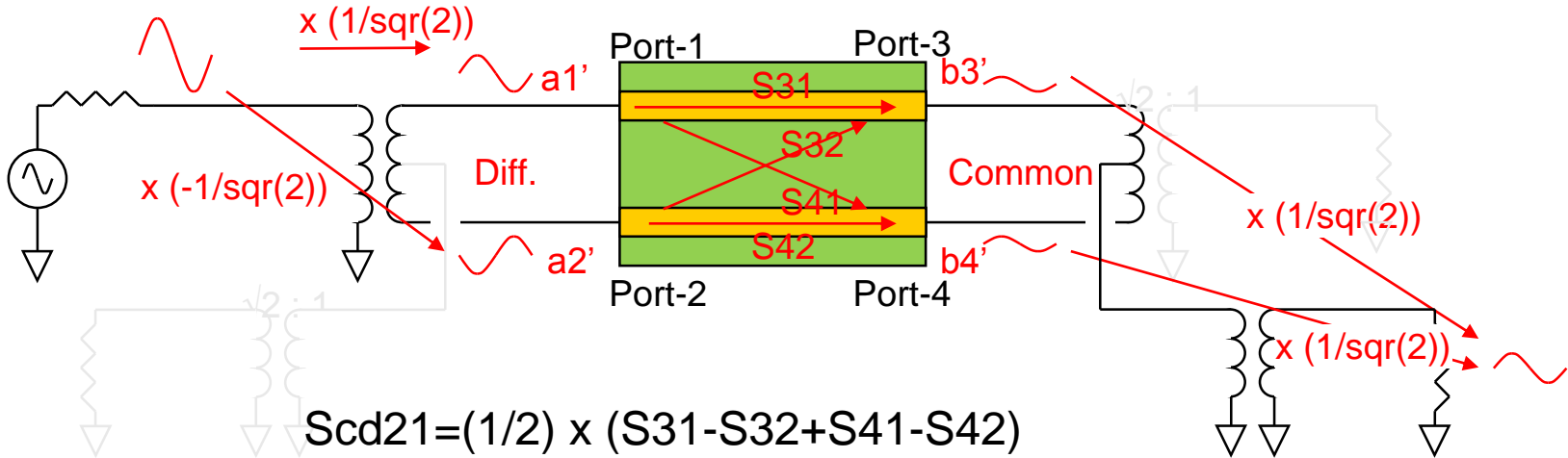
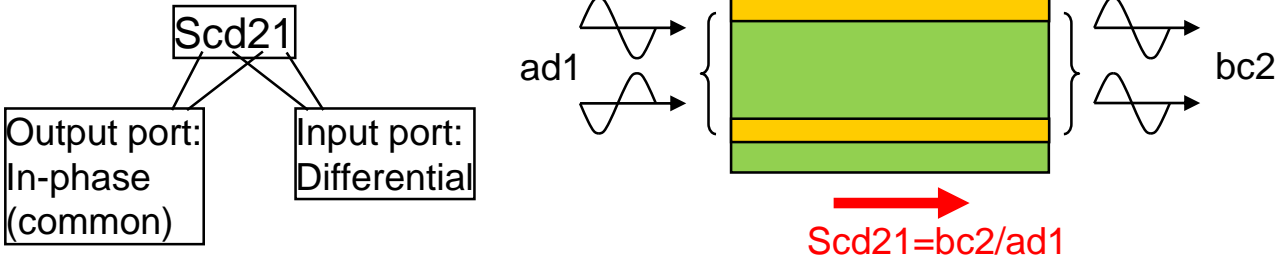
Differential S-parameter measurement



S_{dd11} can be derived by superimposing transmission characteristics of S₁₁, S₁₂, S₂₁, and S₂₂ signal paths;

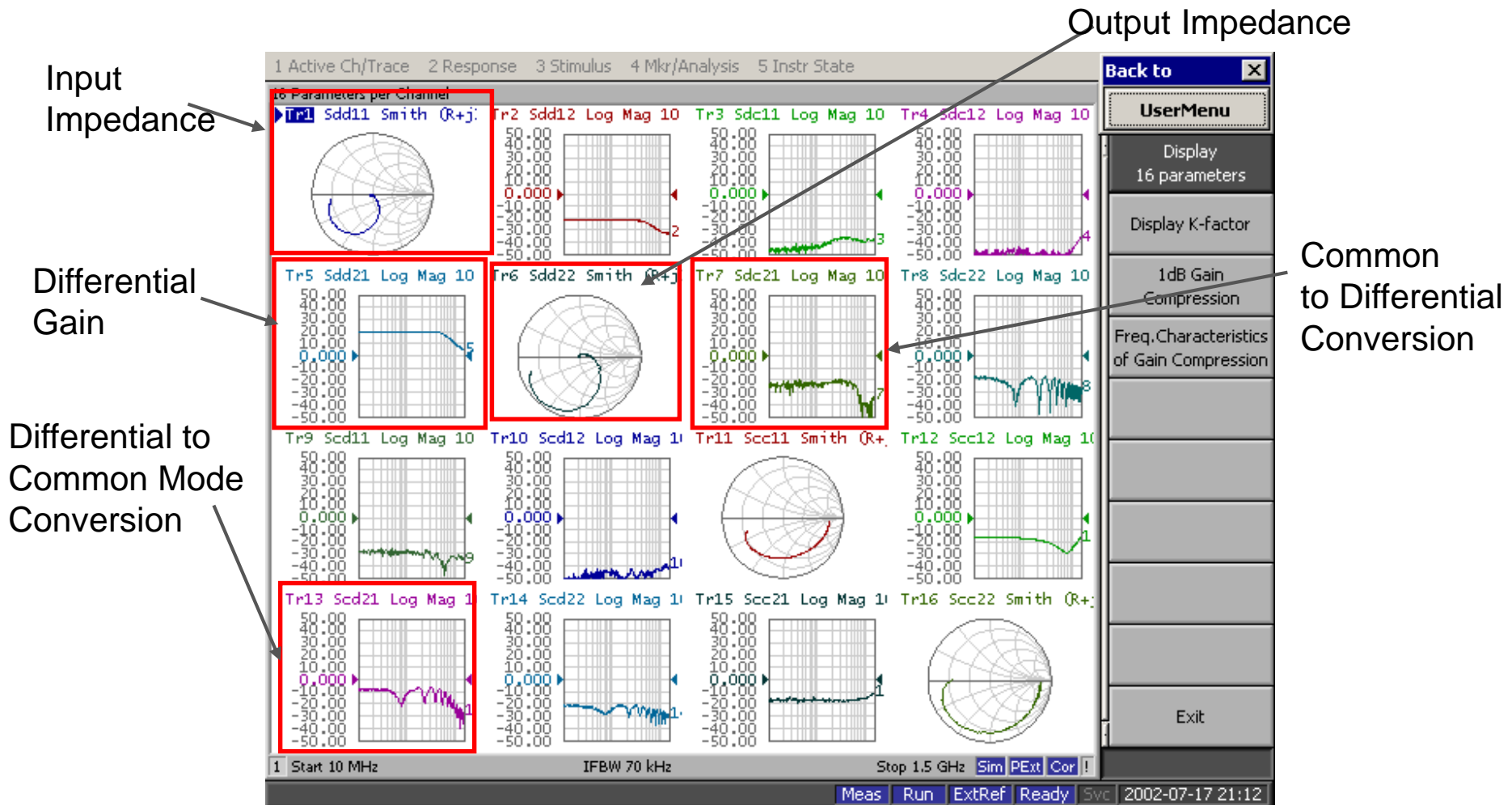
$$S_{dd11} = (1/2) * (S_{11} - S_{21} - S_{12} + S_{22})$$

Differential-Common S-parameter measurement

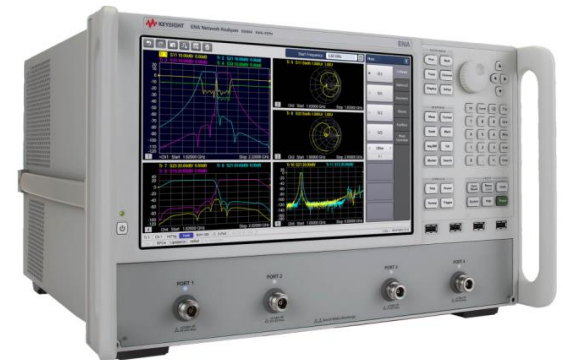
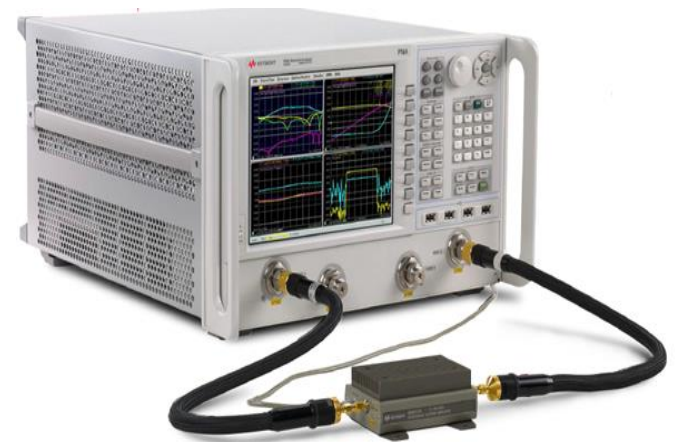


Mixed-mode S-parameter Measurement Example

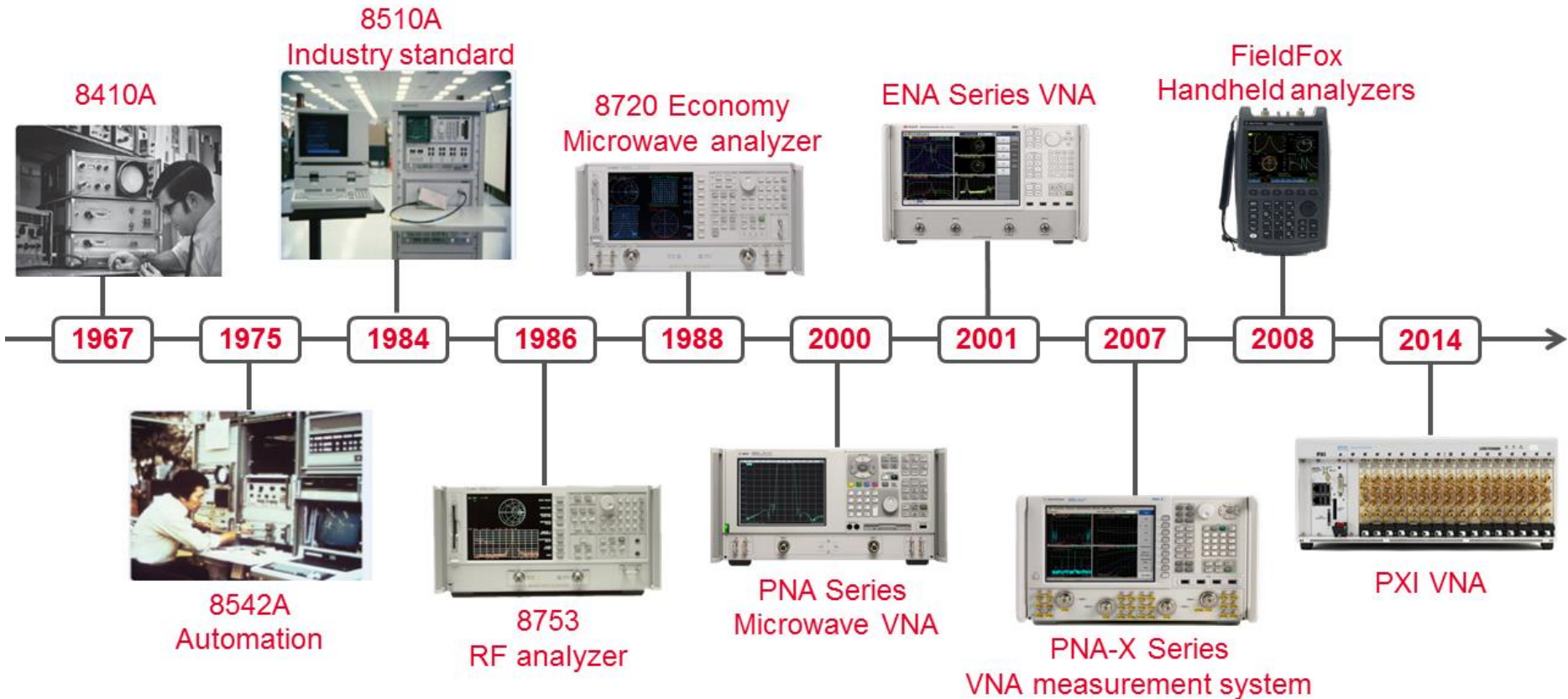
- Differential amplifier



Keysight VNA Portfolio



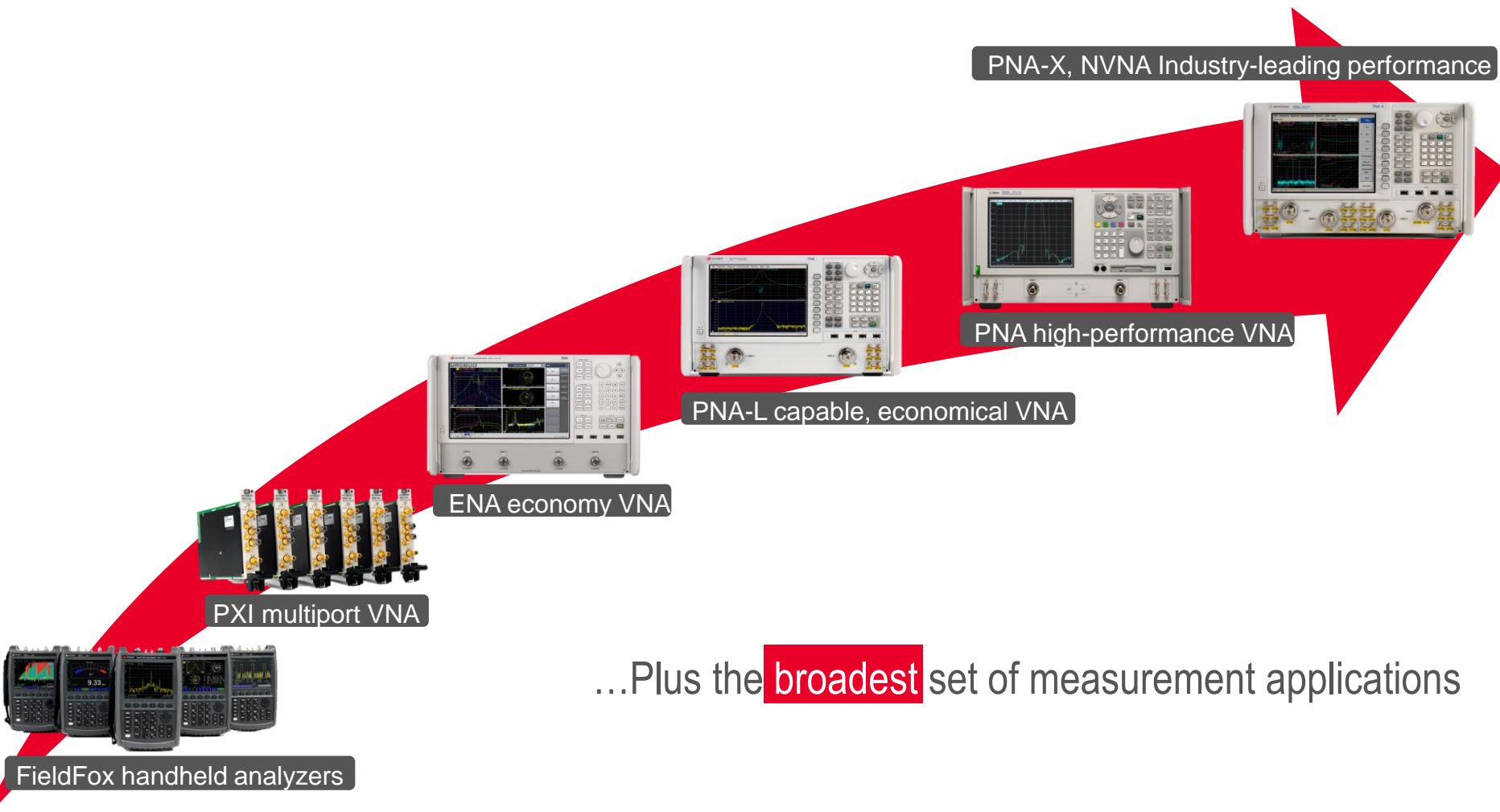
Leader in RF and Microwave Network Analysis



50 Years of Network Analyzer Innovations !

Keysight Vector Network Analyzers

Industry's **broadest** price / performance choices



...Plus the **broadest** set of measurement applications

FieldFox Handheld Analyzers

Carry **precision** with you



FieldFox Handheld Analyzers

Carry **precision** with you



Configurable as:

- ✓ Cable and antenna testers
- ✓ Vector network analyzers
- ✓ Spectrum analyzers
- ✓ All-in-one combination analyzers
- ✓ Frequency ranges from 2 MHz to 50 GHz

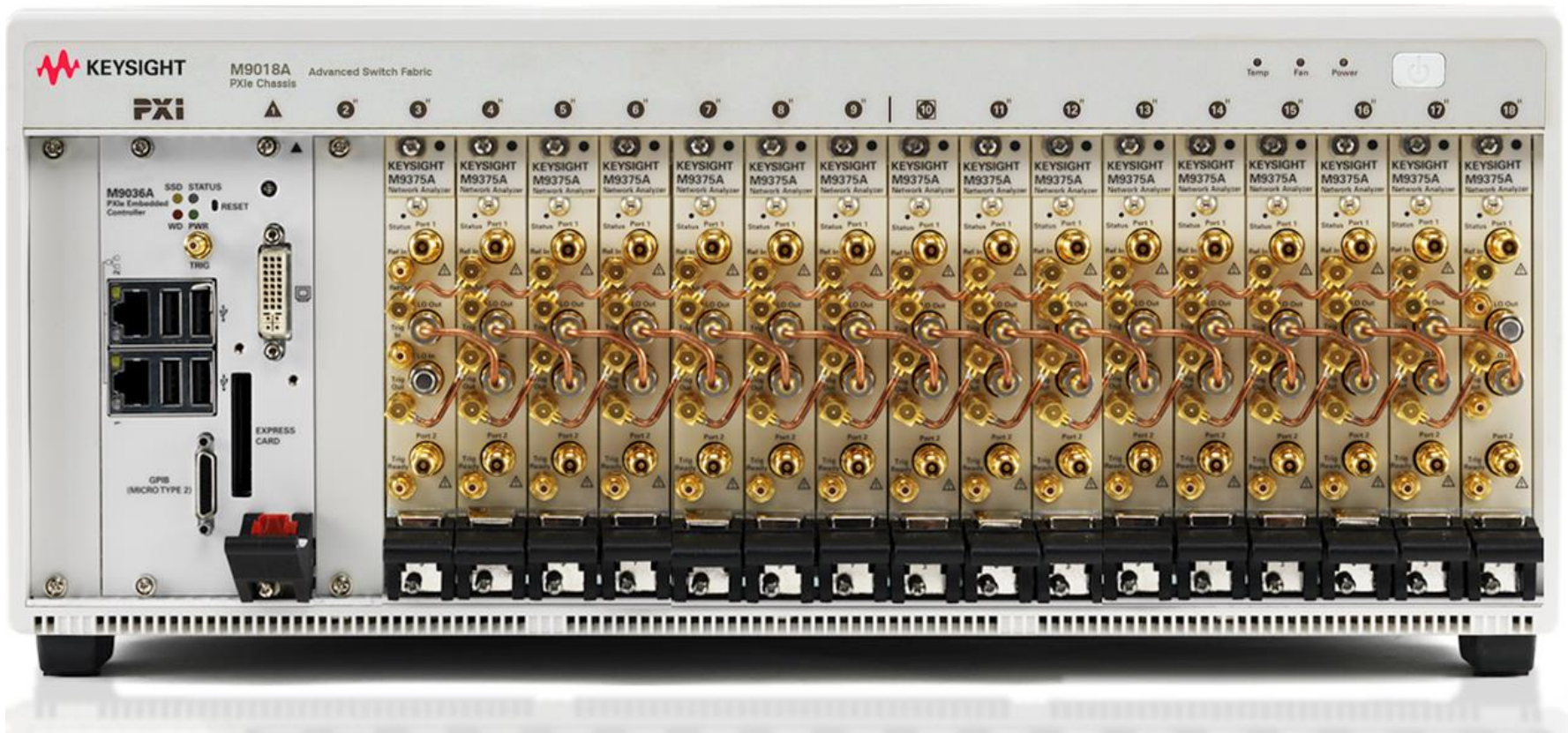
PXI Vector Network Analyzers

- ✓ Full 2 port VNA in a single PXI slot
- ✓ Six Frequency ranges: 300 KHz to 4,6.5,9,14,20 or 26.5 GHz



PXI Vector Network Analyzers

- ✓ True Multiport VNA
- ✓ Up to 32 ports



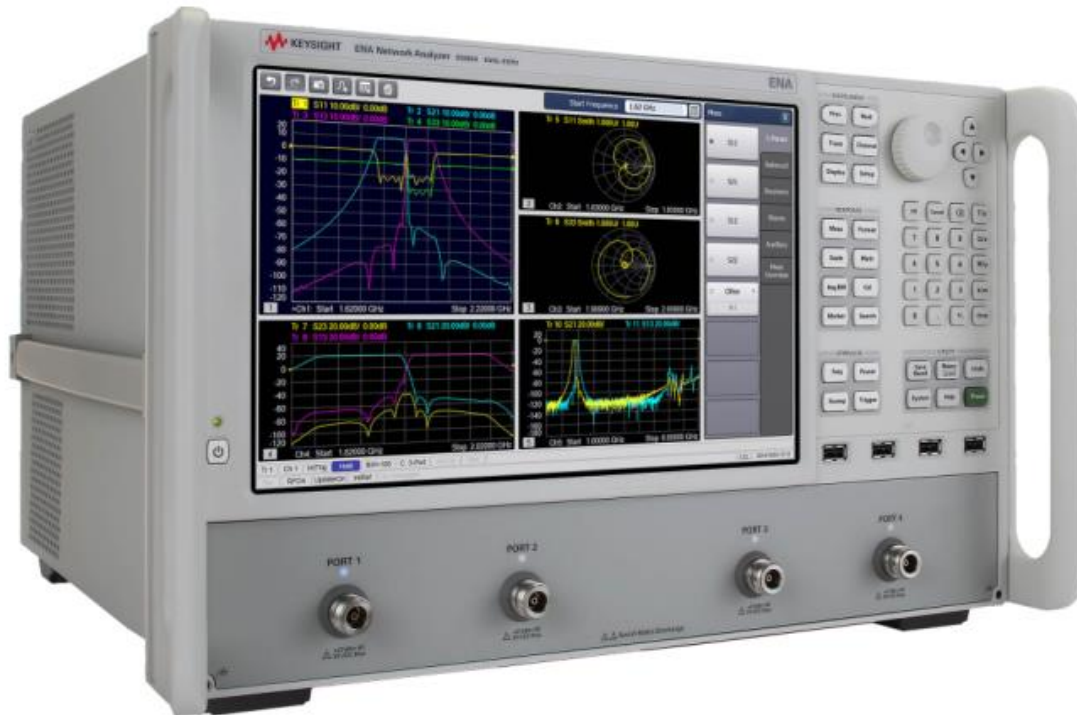
PXI Vector Network Analyzers

- ✓ High Performance Multiport VNA
- ✓ True Modular for customized Applications



ENA Series Vector Network Analyzer

- ✓ Industry standard in RF Network analysis
- ✓ Widely used in Manufacturing test and R&D Application



ENA Series Vector Network Analyzer

- ✓ Industry standard in RF Network analysis
- ✓ Widely used in Manufacturing test and R&D Application



E5080A: The next generation ENA
9 kHz to 4.5/6.5/9 GHz, 2 & 4-port



E5071C: Industry standard RF NA
9/100 k to 4.5/6.5/8.5 GHz
300 k to 14/20 GHz, 2 & 4-port
TDR option



E5072A: ENA with Configurable Test Set
30 kHz to 4.5/8.5 GHz

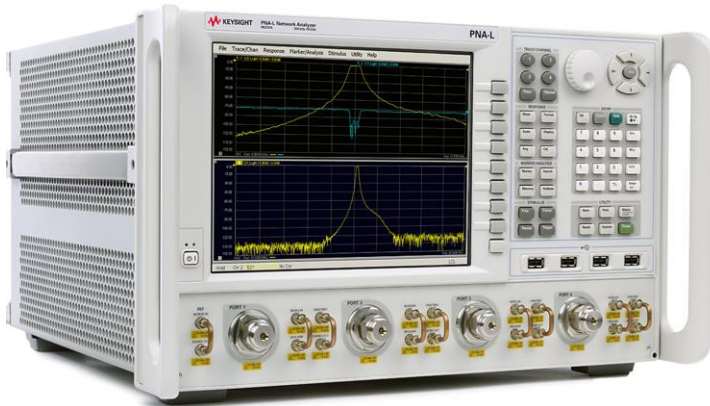


E5061B: LF-RF NA option
5 Hz to 3 GHz
Impedance analysis option
RF NA options
100 kHz to 1.5/3 GHz
50 Ω & 75 Ω

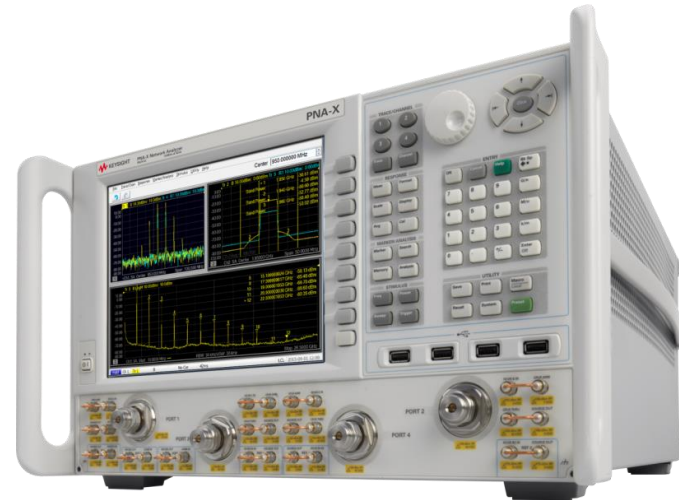


E5063A: Low cost RFNA
100 kHz to 4.5 /8.5/18 GHz

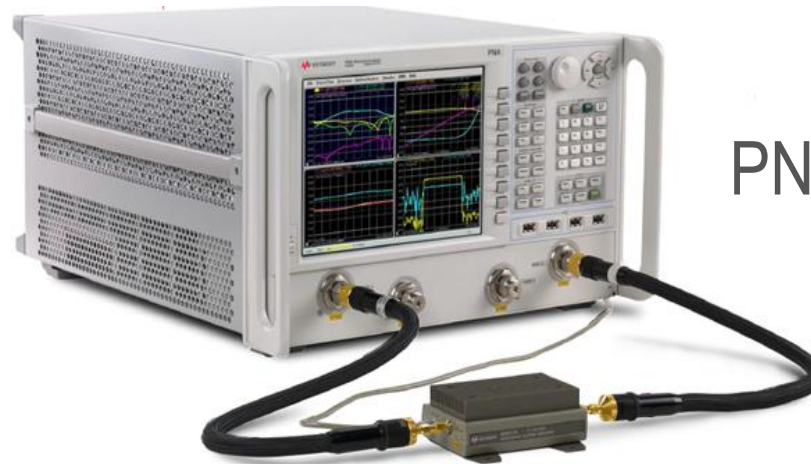
PNA Series Vector Network Analyzer



PNA-L



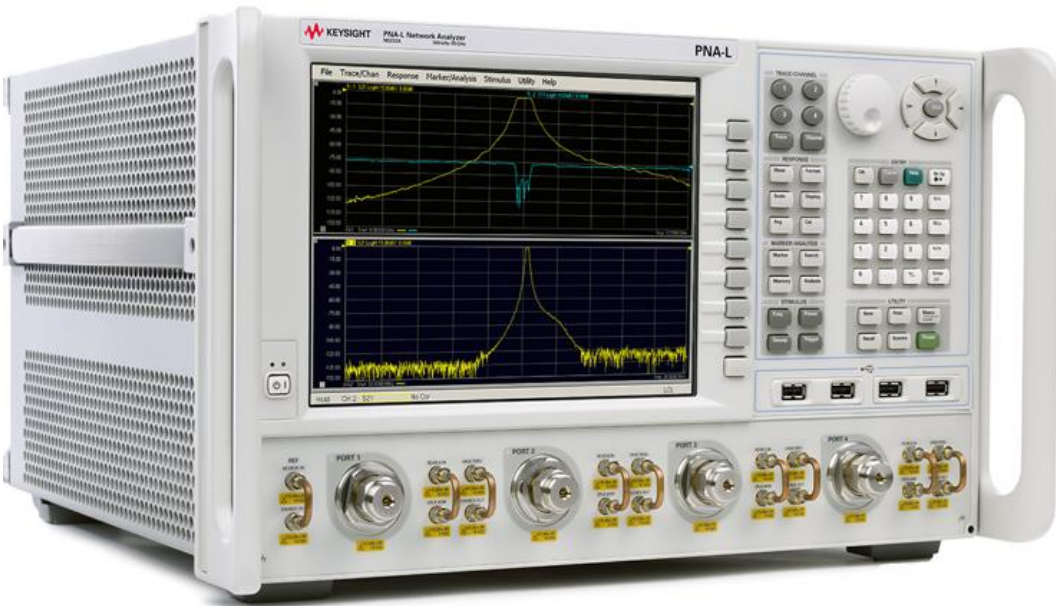
PNA-X



PNA

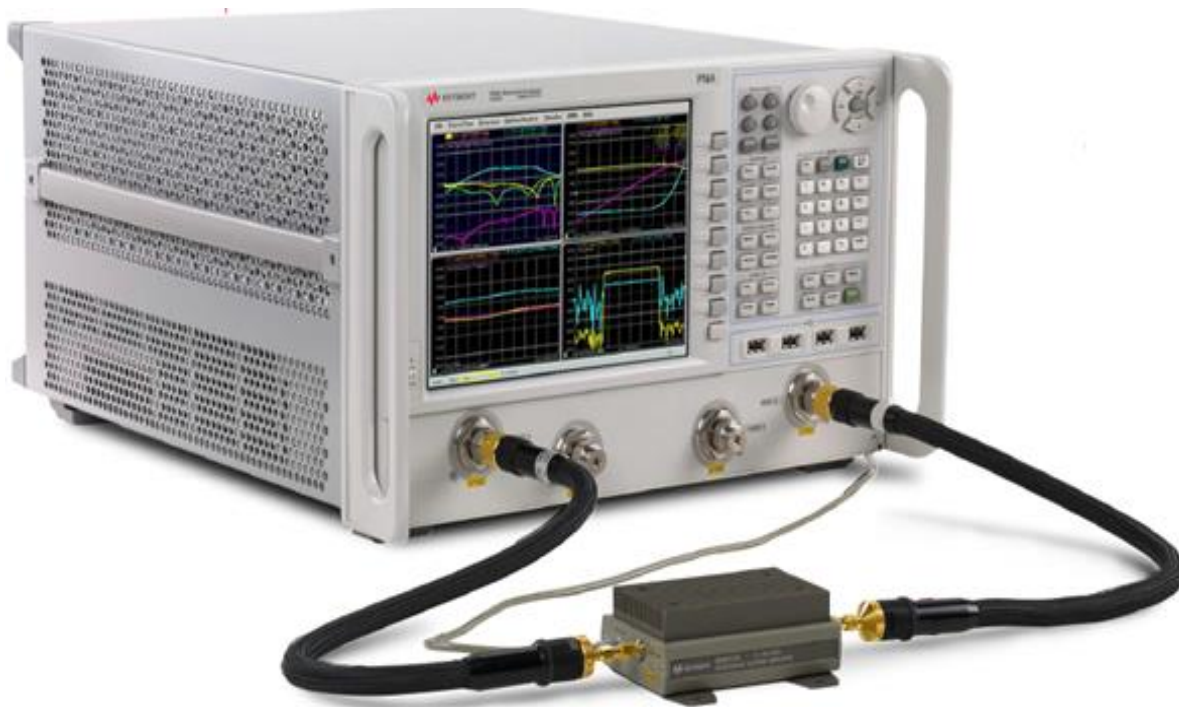
PNA-L Series Vector Network Analyzer

- ✓ Excellent performance at a low price point
- ✓ Frequency ranges from 300 KHz to 8.5,13.5,20,43.5,50 GHz
- ✓ Achieve greater yields and tighter guard bands



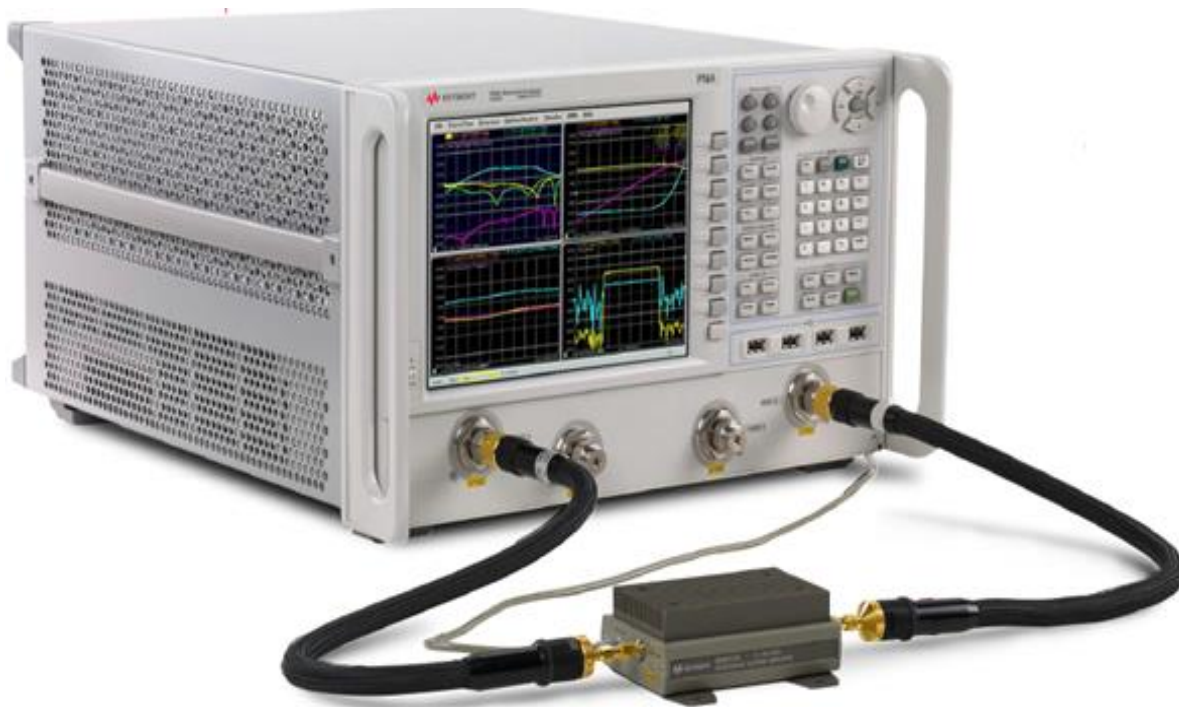
PNA Series Vector Network Analyzer

- ✓ Highest performing network analyzer for passive and active device test
- ✓ Five Frequency ranges up to 67 GHz
- ✓ Customize your PNA with the right performance and application to meet your needs



PNA-X Series Vector Network Analyzer

- ✓ Complete linear and non-linear component characterization
- ✓ Most integrated and flexible microwave network analyzer
- ✓ Unrivaled flexibility and configurability



Rich Set of Measurement Applications and Software Solutions

Optional Capabilities:

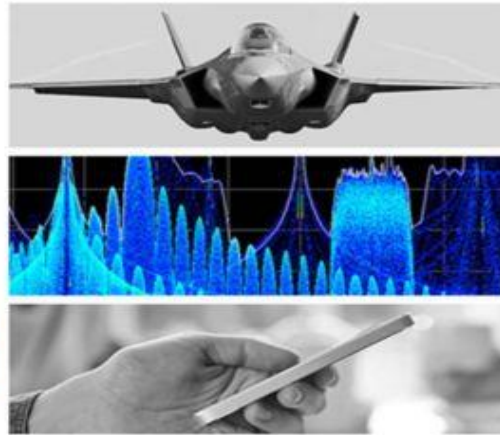
007 Automatic fixture removal
008 Pulsed RF measurements
010 Time domain
015 Dynamic uncertainty for S-parameters
021 Pulse modulators and pulse generators
028 Standard receiver NF measurements
029 Fully corrected noise figure measurements
080 Frequency offset measurements
082 Scalar calibrated converter measurements
083 Vector and scalar calibrated converter
084 Embedded LO measurements
086 Gain compression measurements
087 Intermodulation distortion measurements
088 Source phase control
089 Differential & I/Q device application
090 Spectrum analyzer capability
118 Fast CW mode
510 Nonlinear component characterization
514 Nonlinear X-parameters
518 Nonlinear pulse envelope domain
520 Arbitrary load impedance X-parameters
551 N-port calibrated measurements

Applications:

Material measurements
Load-pull noise parameters
T/R module test
Satellite payload test
Antenna test
Lightwave component analysis
Mixer test
High power devices & components
Millimeter & Terahertz research
Amplifier test
Nonlinear modeling
Metrology
Signal integrity
Atomic force scanning microscope

Keysight Training Services

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- Keysight Instant Buy¹
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- Start-Up Assistance
- Test process analysis consulting

Asset Management: Stay ahead of required maintenance and regulatory audits with automated notifications

Technology Refresh Service: Extend, upgrade or migrate your existing test systems

¹Available in US, Canada, Germany, UK & France

Thank you !





Backup

Keysight Vector Network Analyzer Portfolio

Industry Broadest Price/Performance Choices



FieldFox

Carry precision with you
30 k to 26.5 GHz



PXI VNA

Drive down the size of test
300 k to 26.5 GHz



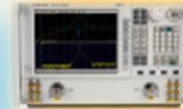
E5061B, E5063A
NA + ZA in one-box
Low cost RF NA



E5071C, E5072A
High-performance RF NA



E5080A
The next-generation ENA



PNA-L (N523XA)
Economy Microwave NA



PNA (N522XA)
High-performance Microwave NA



PNA-X (N524XA), NVNA
Most advanced & flexible
Microwave NA



mm-wave Solution
Up to 1.1 THz



PNA-X Receiver
8530A Antenna
Replacement

Keysight Vector Network Analyzer Portfolio

- Wireless RF components
- Production test
- High-speed digital
- LF-RF components
- CATV / 75-ohm

Price Choices

- Broadest range of applications
- Metrology & cal lab
- Complete linear & nonlinear active device characterization

- Basic S-parameter (wireless components, A/D, etc.)
- High-volume mfg.
- True Multiport Test
- Multi-site Test

Price



E5080A
The next-generation ENA



PNA (N522XA)
High-performance Microwave NA

PNA-L (N523XA)
Economy Microwave NA

PNA Family

Reach for unrivaled excellence

- Broadband device characterization
- Wireless mm-wave
- Research in THz



E5061B, E5063A
NA + ZA in one-box
Low cost RF NA



E5071C, E5072A
High-performance RF NA



mm-wave Solution
Up to 1.1 THz



PXI VNA
Drive down the size of test
300 k to 26.5 GHz

ENA Series
Drive down the cost of test
5 Hz to 20 GHz



PNA-X Receiver
8530A Antenna Replacement

- Antenna test

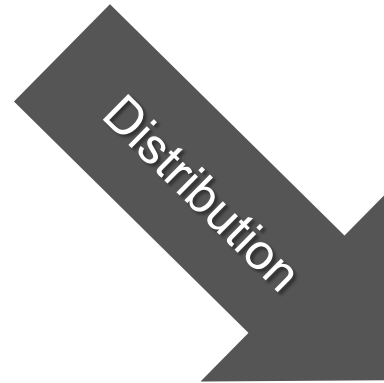
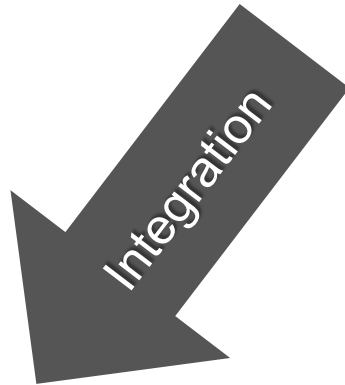
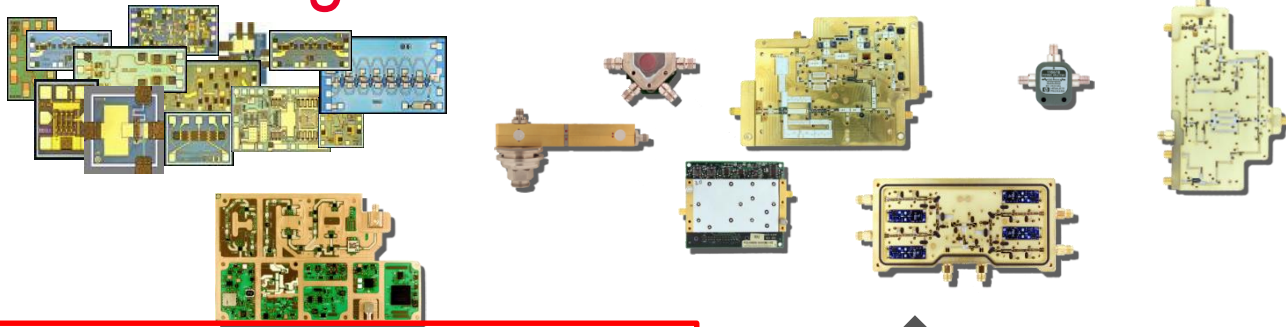


FieldFox

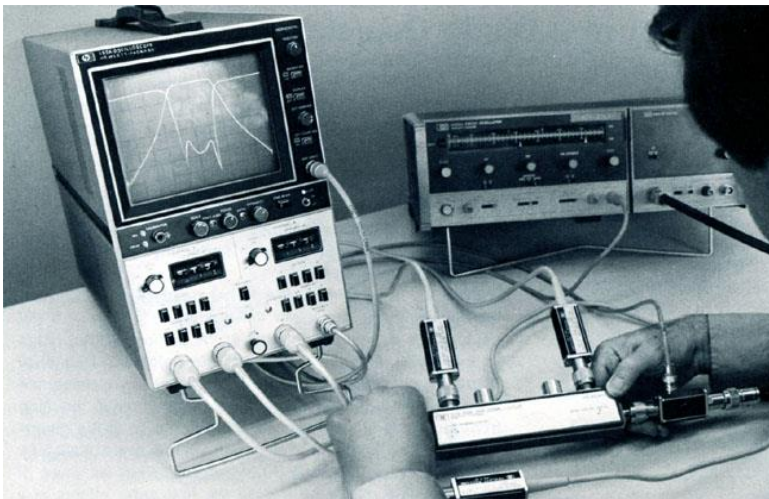
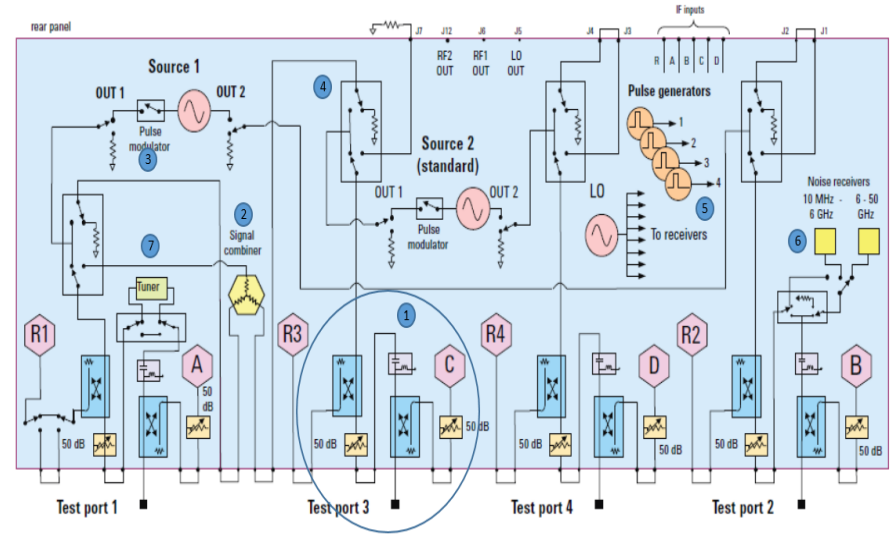
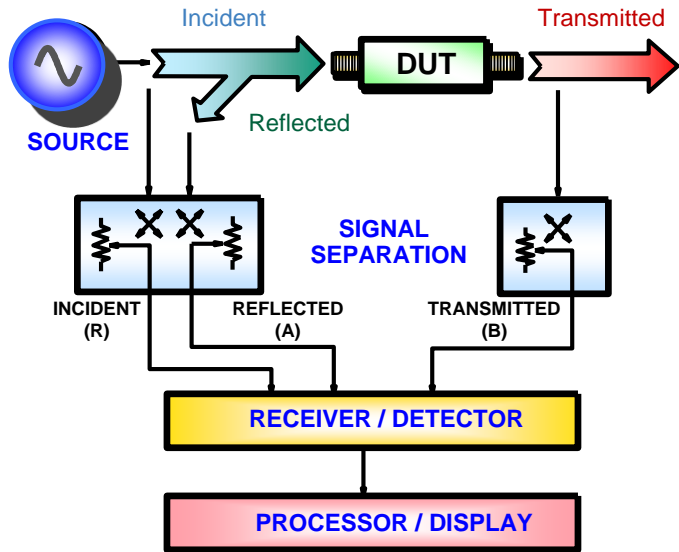
- Installation & Maintenance
- A/D service/maintenance



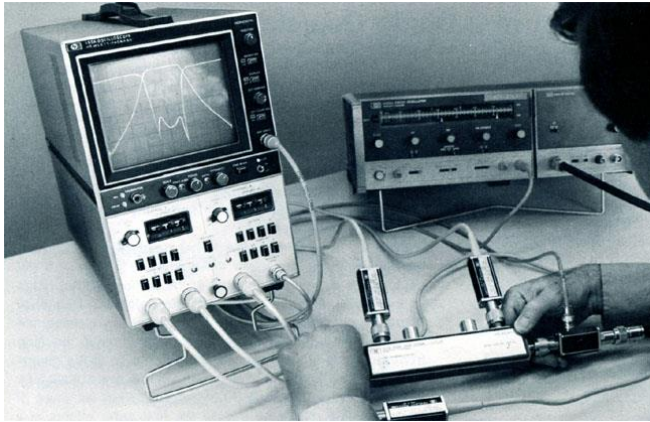
Integration or Distribution?



Network Analyzer Block Diagram: Yesterday and Today

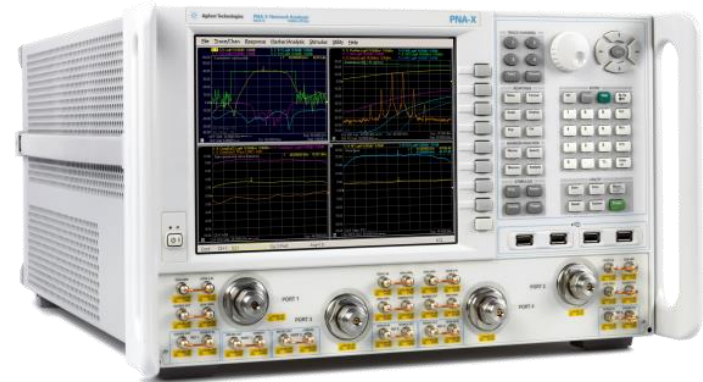
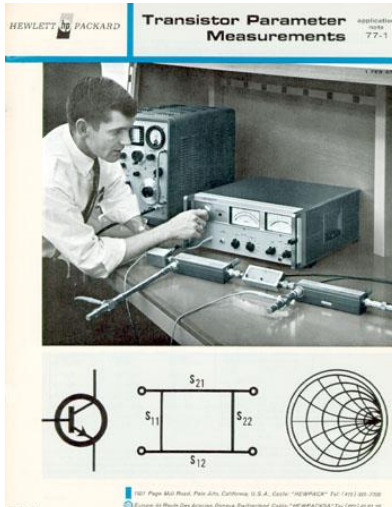


Network Analyzer Block Diagram: Yesterday and Today



Measurements:

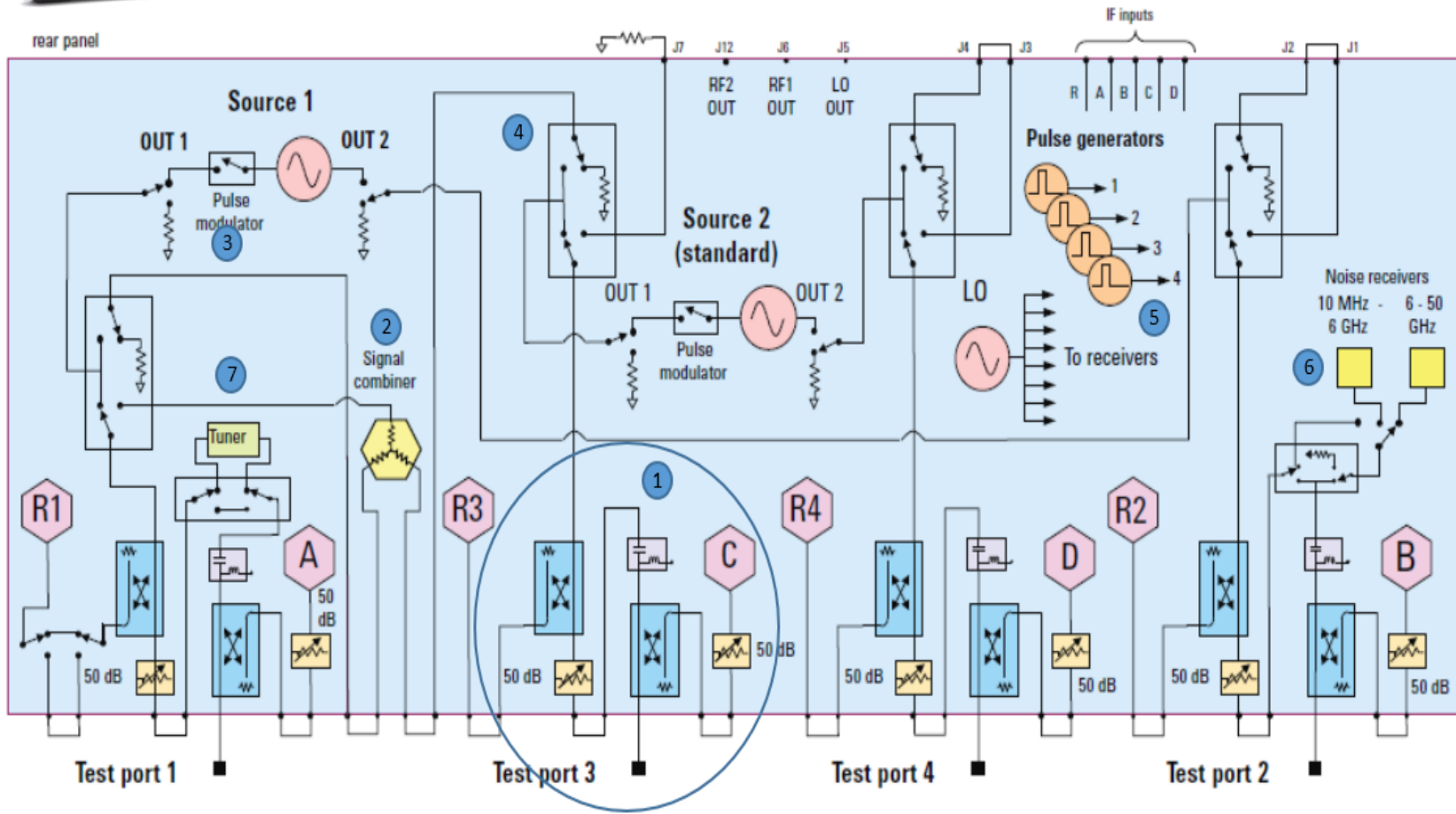
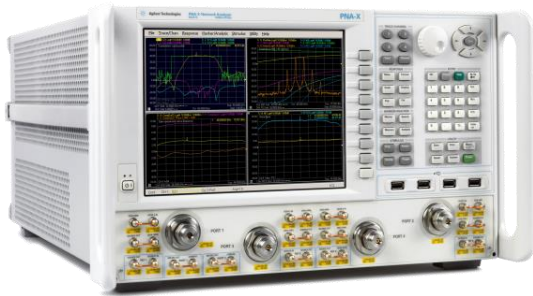
- ✓ CW S-parameters



Measurements:

- ✓ CW S-parameters
- ✓ Pulsed S-parameters
- ✓ Gain compression
- ✓ AM-to-PM conversion
- ✓ Harmonics
- ✓ Intermodulation distortion
- ✓ Noise Figure
- ✓ Hot-S-parameters
- ✓ Phase versus drive
- ✓ True-mode differential stimulus
- ✓ Spectrum Analysis

PNA-X Block Diagram



PNA-X: Single Connection, Multiple Measurements

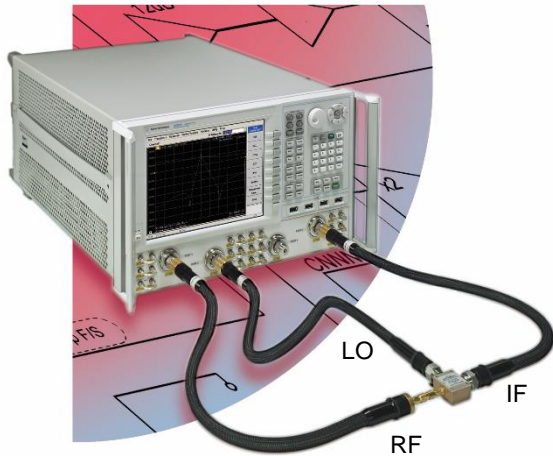
Easily switch between measurements:

- CW S-parameters
- Pulsed S-parameters
- Gain compression
- AM-to-PM conversion
- Harmonics
- Intermodulation distortion
- Hot-S-parameters
- Phase versus drive
- True-mode differential stimulus
- Conversion loss/gain
- Noise Figure
- NVNA



PNA Spectrum Analyzer Option (090)

A multi-channel SA with internal swept-signal generators



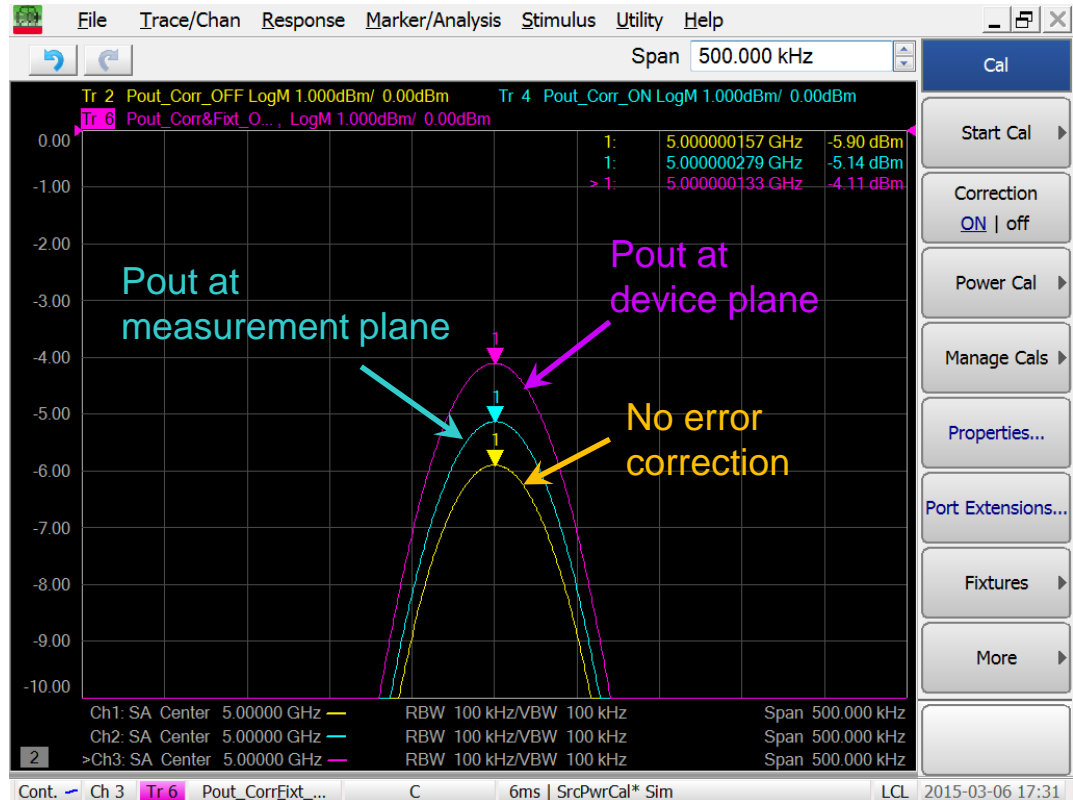
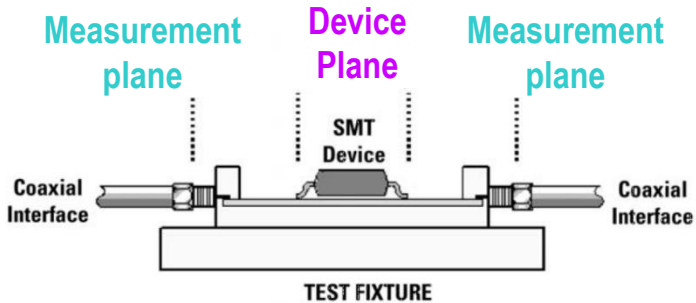
- RF input
- RF reflection
- RF feed-through
- RF harmonics
- LO reflection
- LO feed-through
- LO harmonics
- IF output
- High-/sub-order mixing spurs



With a single set of connections, the spurious content emanating from all ports is readily apparent during operation with fixed or swept stimuli.

PNA Spectrum Analyzer Option (090)

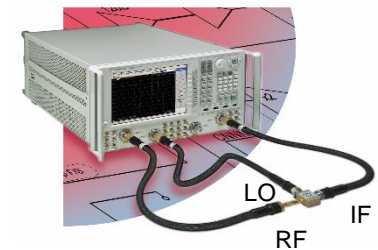
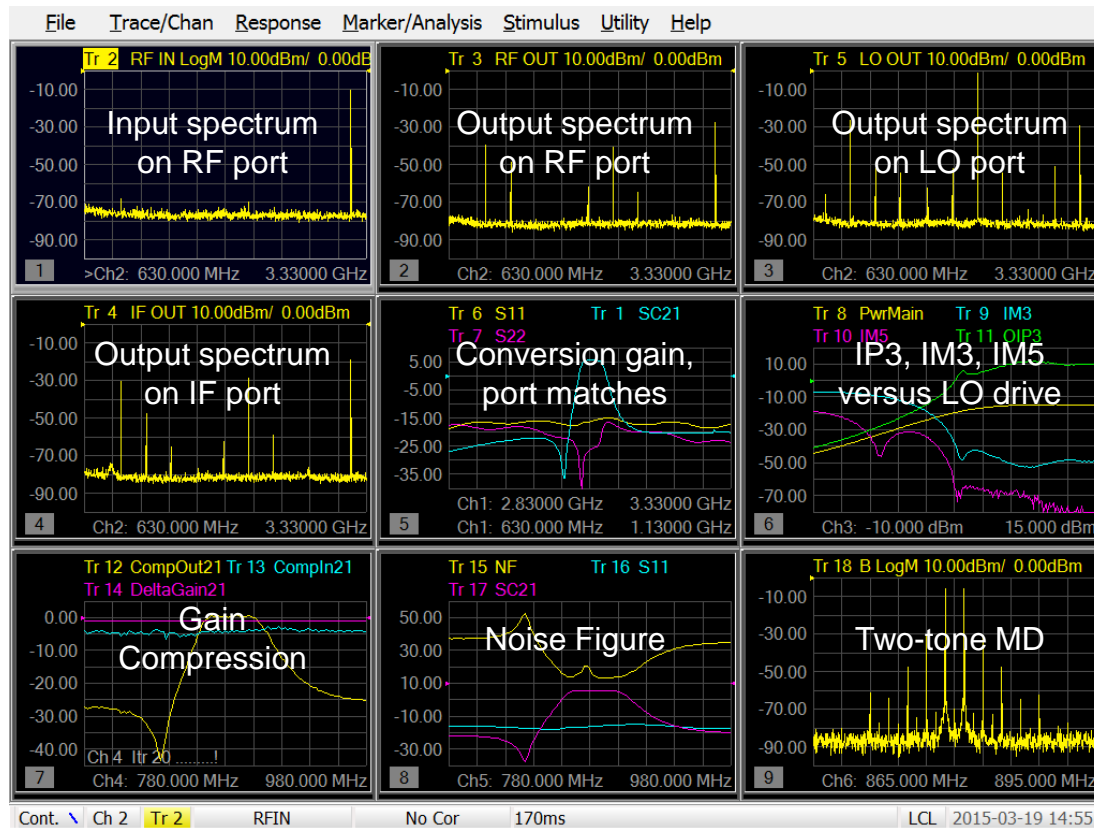
Unlock true performance with in-fixture spectrum analysis



VNA calibration and fixture de-embedding remove cable and fixture effects and correct receiver response errors, providing calibrated in-fixture spectrum analysis.

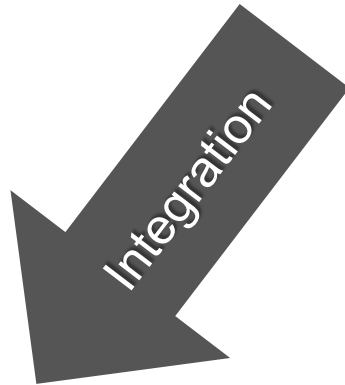
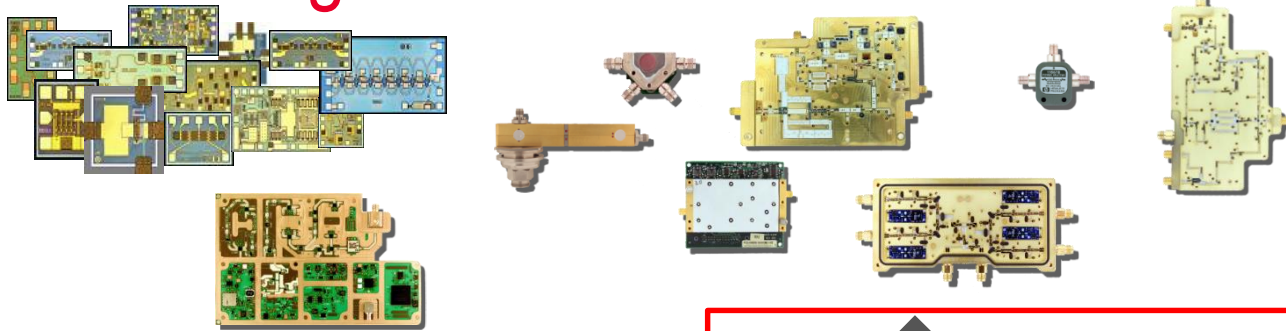
PNA Spectrum Analyzer Option (090)

Spectrum analyzer option adds to suite of PNA apps

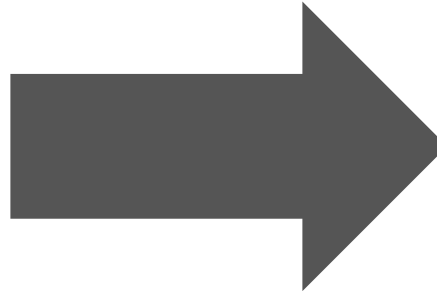


SA option further enriches the PNA capabilities for component tests with a single set of connections.

Integration or Distribution?



Integration or Distribution?



Vector Network Analyzer, 8510X

PXle Vector Network Analyzer, M937XA

Dynamic range (for transmission measurements)

	Frequency range (GHz)			
	0.045–2	2–8	8–20	20–26.5
Maximum power measured at port 2	+2 dBm	+3 dBm	+3 dBm	-1 dBm
Reference power at port 1 (nominal)	-5 dBm	-9 dBm	-14 dBm	-25 dBm
Minimum power measured at port 2	-98 dBm	-98 dBm	-100 dBm	-99 dBm
Receiver dynamic range	100 dB	101 dB	103 dB	98 dB
System dynamic range	93 dB	89 dB	86 dB	74 dB

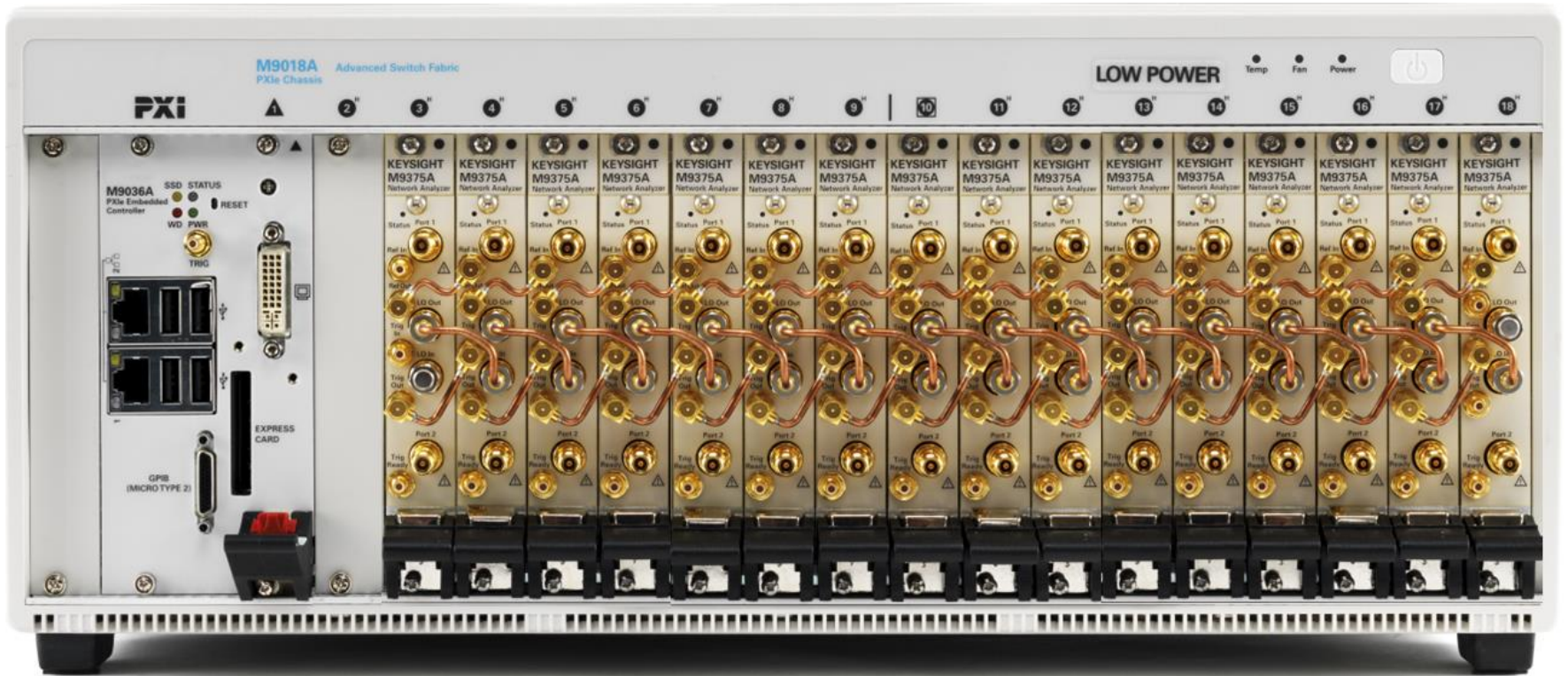
Full two-port network analyzer in just one slot up to 26.5 GHz
Maximum Power : + 10 dBm

Dynamic range: 114 dB (9 GHz), 110 dB (20 GHz)

Trace noise: < 0.003 dB specified, < 0.001 dB typical

Stability: ± 0.005 dB/°C at 4 GHz, ± 0.020 dB/°C at 26.5 GHz

32-port True Crossbar 26.5 GHz VNA in 4U Chassis



Portable - Pick up FieldFox for its Ergonomics

Vertical portrait orientation makes FieldFox comfortable to hold, and the keypad layout lets you easily operate it with your thumbs

Bright, low-reflective display and backlit keys enable easy viewing in darkness or direct sunlight

Large keys are easy to operate, even when wearing gloves



Weighing just 3.0 kg (6.6 lbs) FieldFox is easier to carry than similar analyzers

One-button measurements simplify complex setups and ensure quick, accurate results

The intuitive user interface is designed for the work you do every day, enabling measurements in just a few key presses

“I really like the packaging, and you’ve done a lot to simplify the controls and menus.”

- DoD technical lead for military contracts

...and Depend on its Durability

Specially designed connector bay protects connectors from damage due to drops or other external impacts



Transfer and archive data through LAN, USB and SD card

Keep going with the easily replaceable Lithium Ion battery

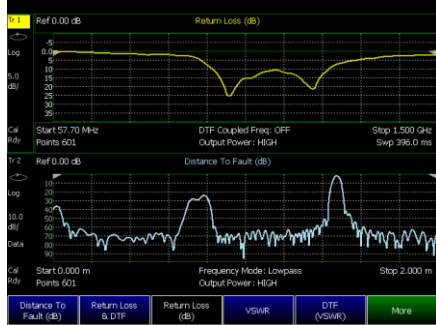


Gasketed doors protect connectors from dust and moisture

Rubber doors protect connectors from dust and moisture



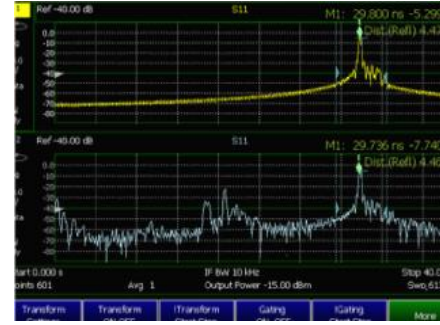
Get a Wide Range of Precise Field Measurements



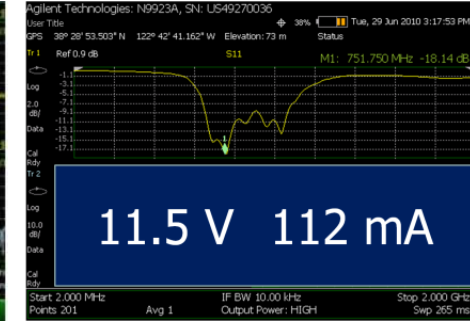
Cable and antenna analysis



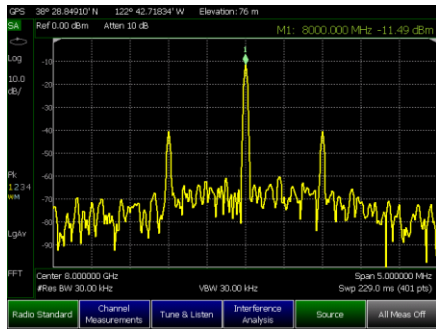
Vector network analysis



Time domain

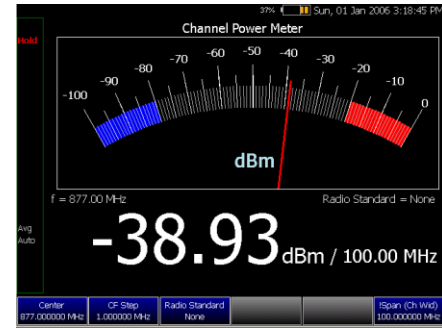


DC source & current monitor

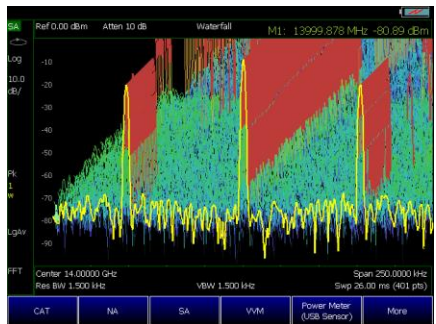


Spectrum analysis

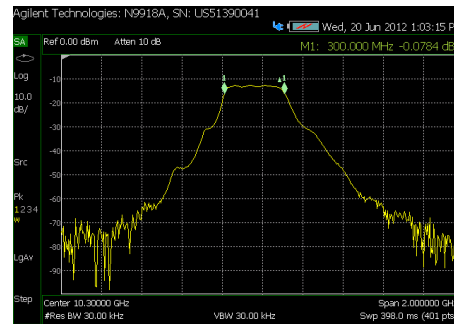
Plus:
Built-in GPS
Independent source
Full-band preamplifier
SA frequency counter



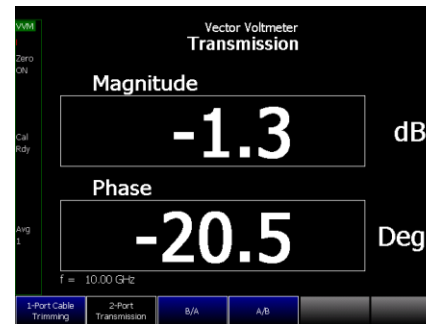
Built-in power meter



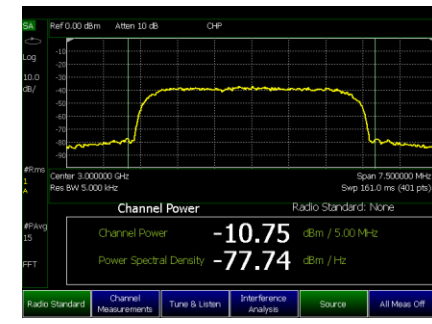
Interference analysis



Full-band tracking generator



Vector voltmeter



Channel power measurement

Find the FieldFox that Meets Your Needs

	Frequency									
	4 GHz	6/6.5 GHz	9 GHz	14 GHz	18 GHz	26.5 GHz	32 GHz	44 GHz	50 GHz	
FieldFox combination analyzer (combo analyzer)	N9952A									
	N9951A									
	N9950A									
	N9918A									
	N9917A									
	N9916A									
	N9915A									
	N9914A									
	N9913A									
	N9912A									
FieldFox vector network analyzer (VNA)	N9928A									
	N9927A									
	N9926A									
	N9925A									
	N9923A									
FieldFox spectrum analyzer (SA)	N9962A									
	N9961A									
	N9960A									
	N9938A									
	N9937A									
	N9936A									
N9935A										